



國家同步輻射研究中心
National Synchrotron Radiation Research Center

X-ray Nano Probes for Nano Materials at TPS

Tseng, Shao-Chin

2016/3/4 NTHU-Physics

NSRRC



Outline

- Synchrotron Light Source
- Application of Synchrotron Light
- X-ray nano probe at TPS

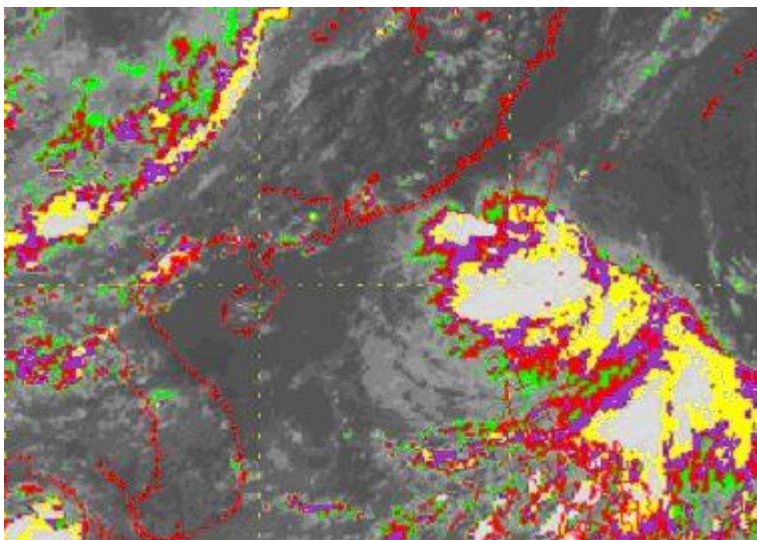


“Light” is indispensable to man’s exploration of nature.

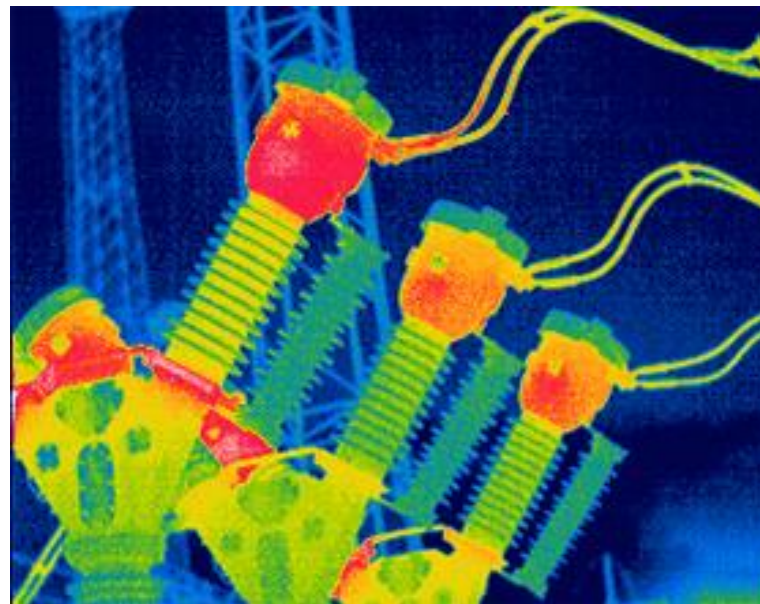


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Invisible light: IR and X-ray...



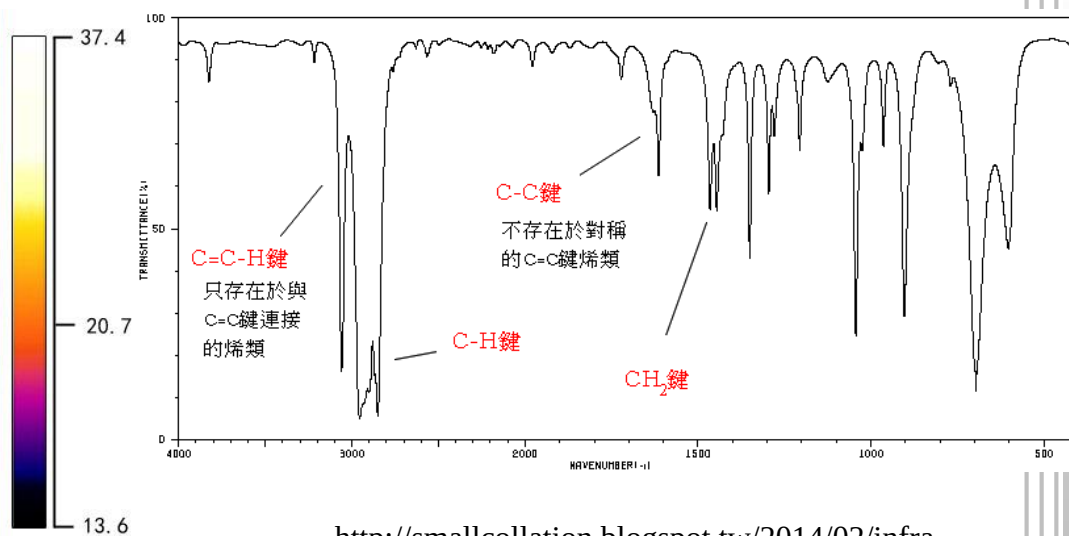
http://www.hko.gov.hk/prtver/html/docs/education/edu02rga/radiation/radiation_02-c.shtml



<http://www.yingfukeji.com/appl/grid.html>

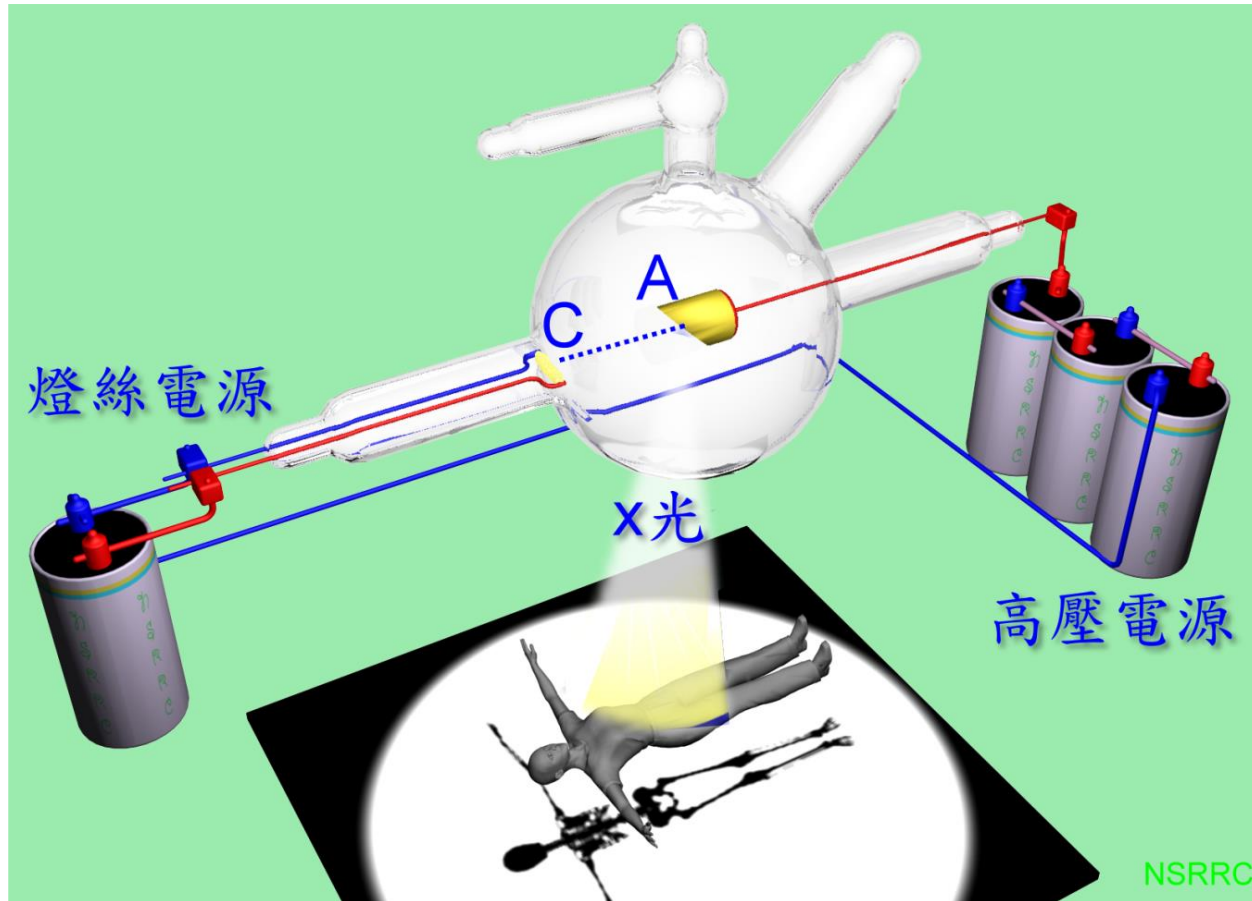


<http://www.uv-teck.com/Ttwjy>



<http://smallcollation.blogspot.tw/2014/02/infrared-spectroscopy-of-alkanes.html#gsc.tab=0>

Rontgen used a simple accelerator to discover X-rays



1895



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Hand mit Ringen (Hand with Rings): Wilhelm Röntgen's first "medical" X-ray, of his wife's hand, taken on 22 December 1895 and presented to Ludwig Zehender of the Physik Institut, University of Freiburg, on 1 January 1896.

<http://en.wikipedia.org/wiki/X-ray>



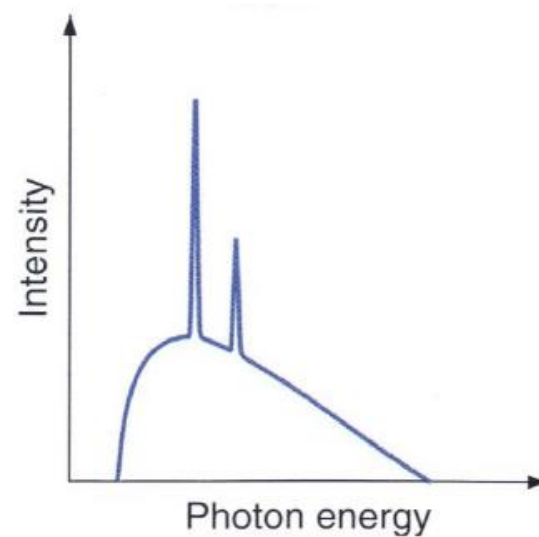
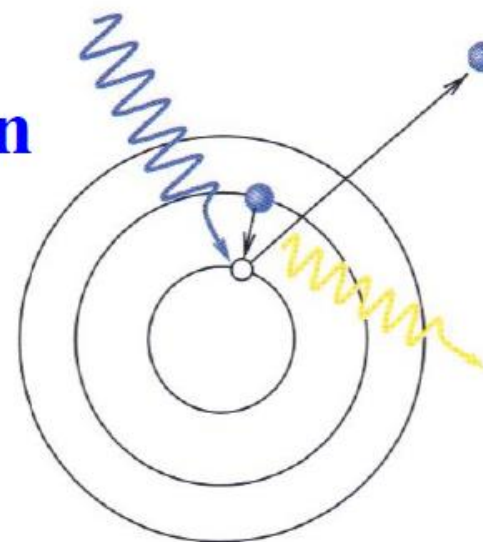
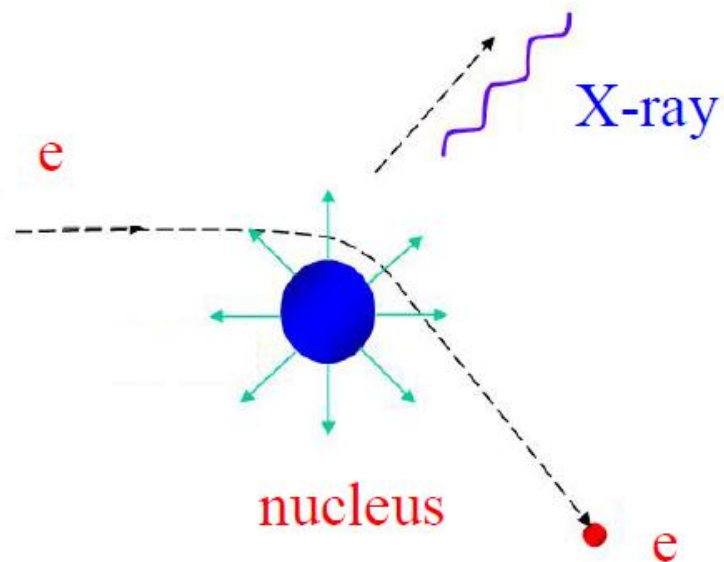


http://snallabolaget.com/?page_id=666

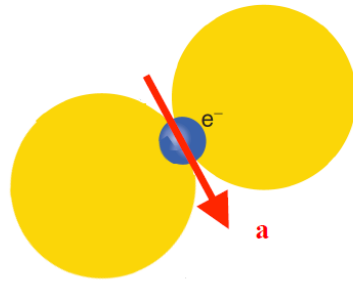


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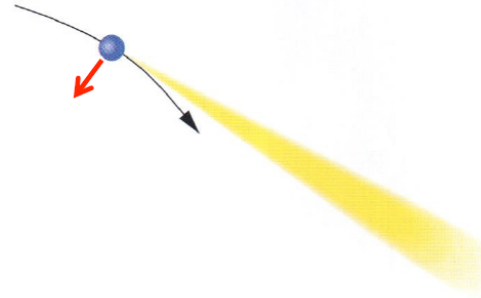
Characteristic X-ray emission



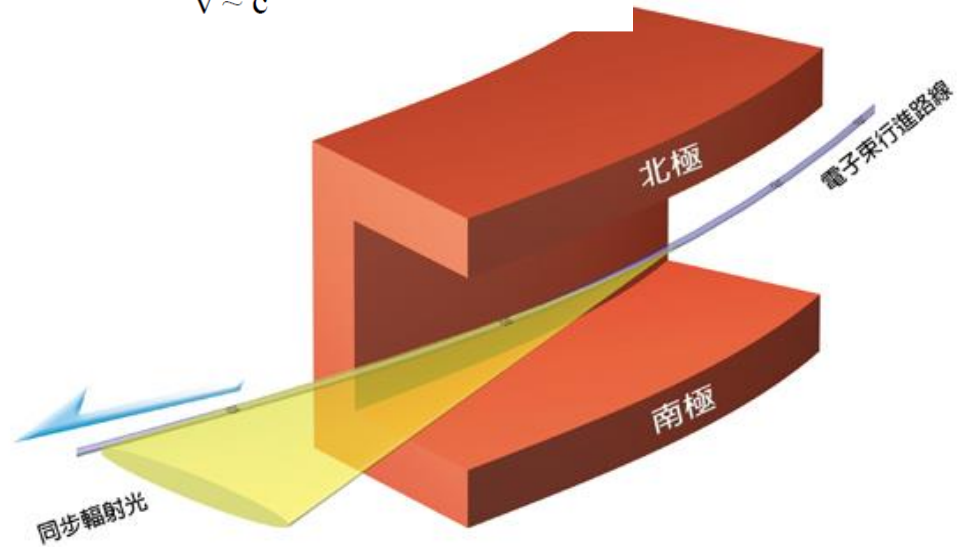
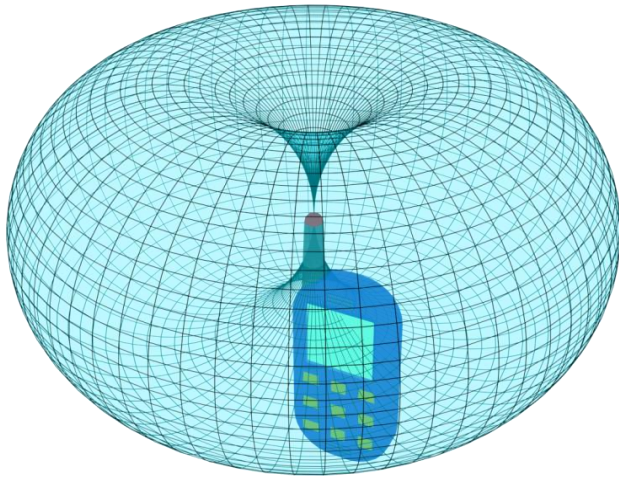
Electromagnetic wave from a moving charge



$v \ll c$



$v \sim c$

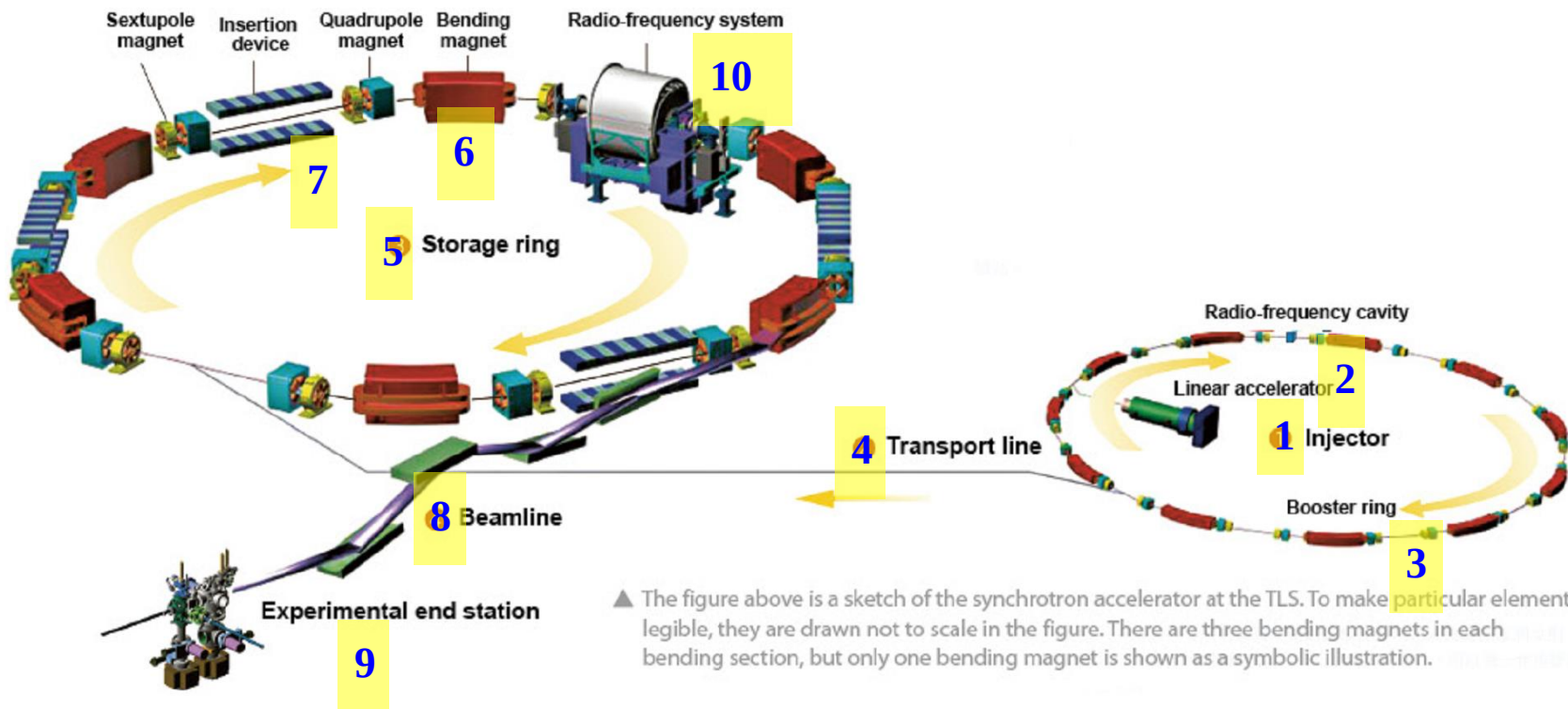


二極偏轉磁鐵



同步加速器光源的原理

- 電子在電子槍(1)內產生，經過直線加速器(2)加速至能量為5,000萬電子伏特。
- 電子束進入增能環(3)後，繼續增加能量至15億電子伏特(1.5GeV)，速度非常接近光速(0.99999995倍)。
- 電子束經由傳輸線(4)進入儲存環(5)。
- 當儲存環累積足夠的電子束後，經由各個磁鐵的導引與聚焦，電子束在偏轉磁鐵(6)及插入磁鐵(7)發出同步加速器光源，經由光束線(8)將光源引導至實驗站(9)進行實驗。
- 電子束在發出同步加速器光源後，要靠高頻腔(10)來補充失去的能量。





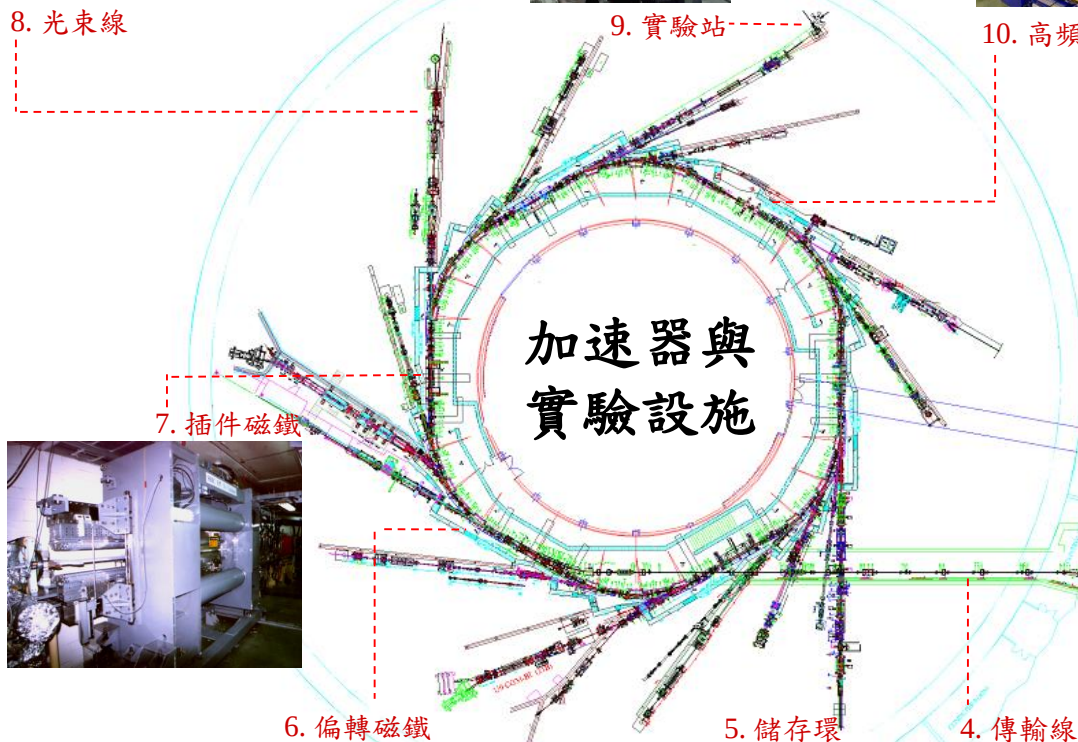
8. 光束線



9. 實驗站



10. 高頻系統



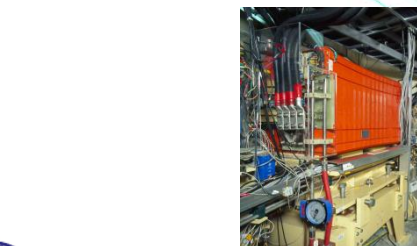
7. 插件磁鐵



1. 電子槍



2. 直線加速器



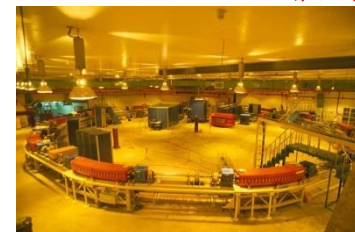
6. 偏轉磁鐵



5. 儲存環



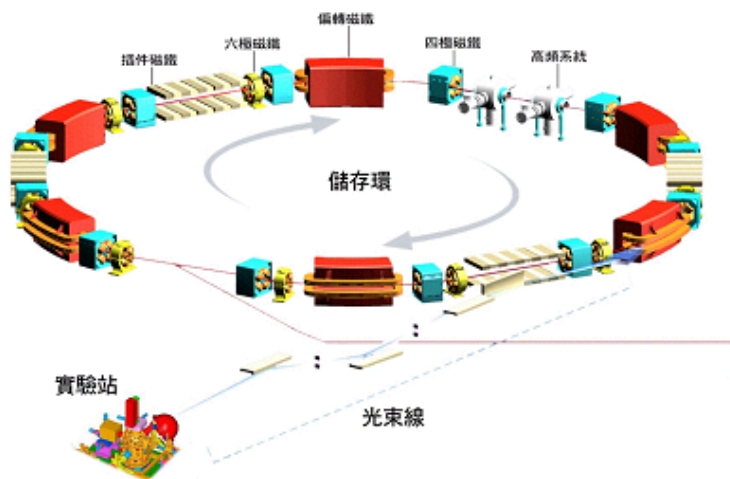
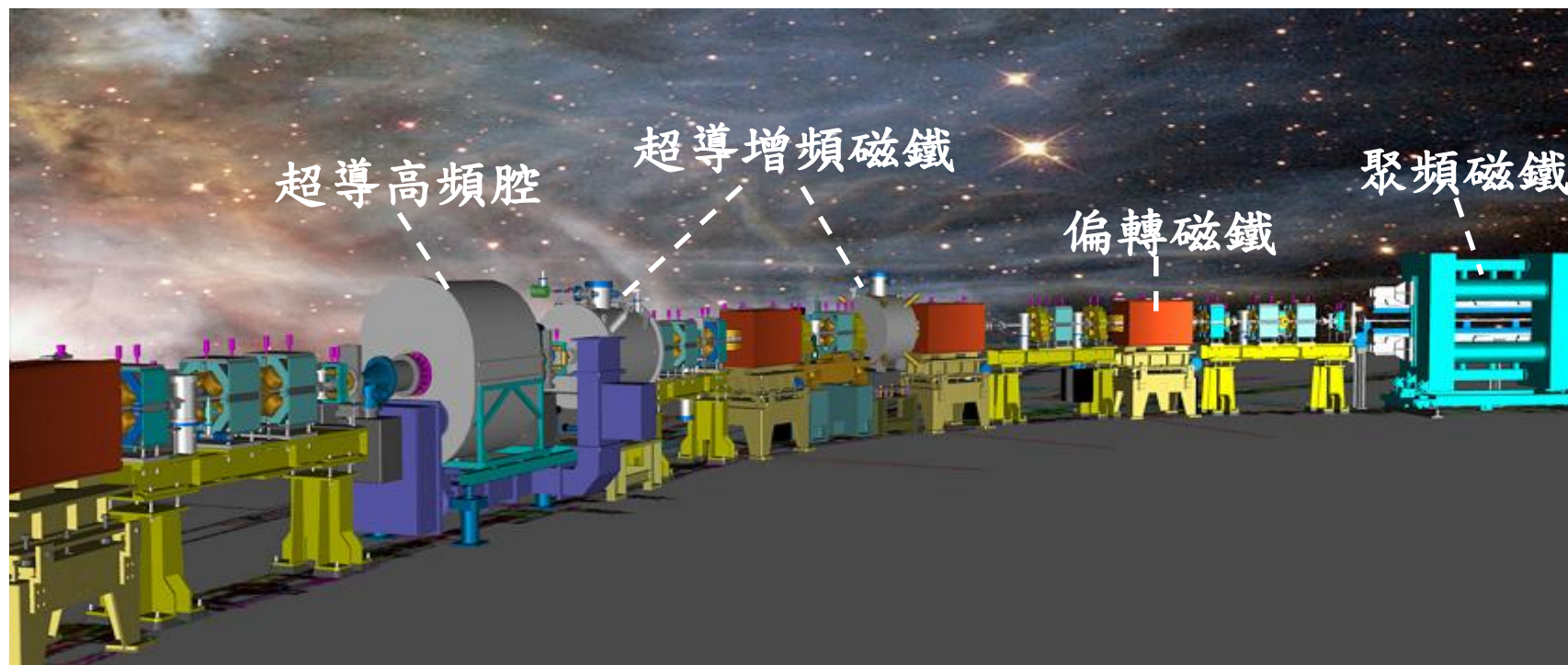
4. 傳輸線



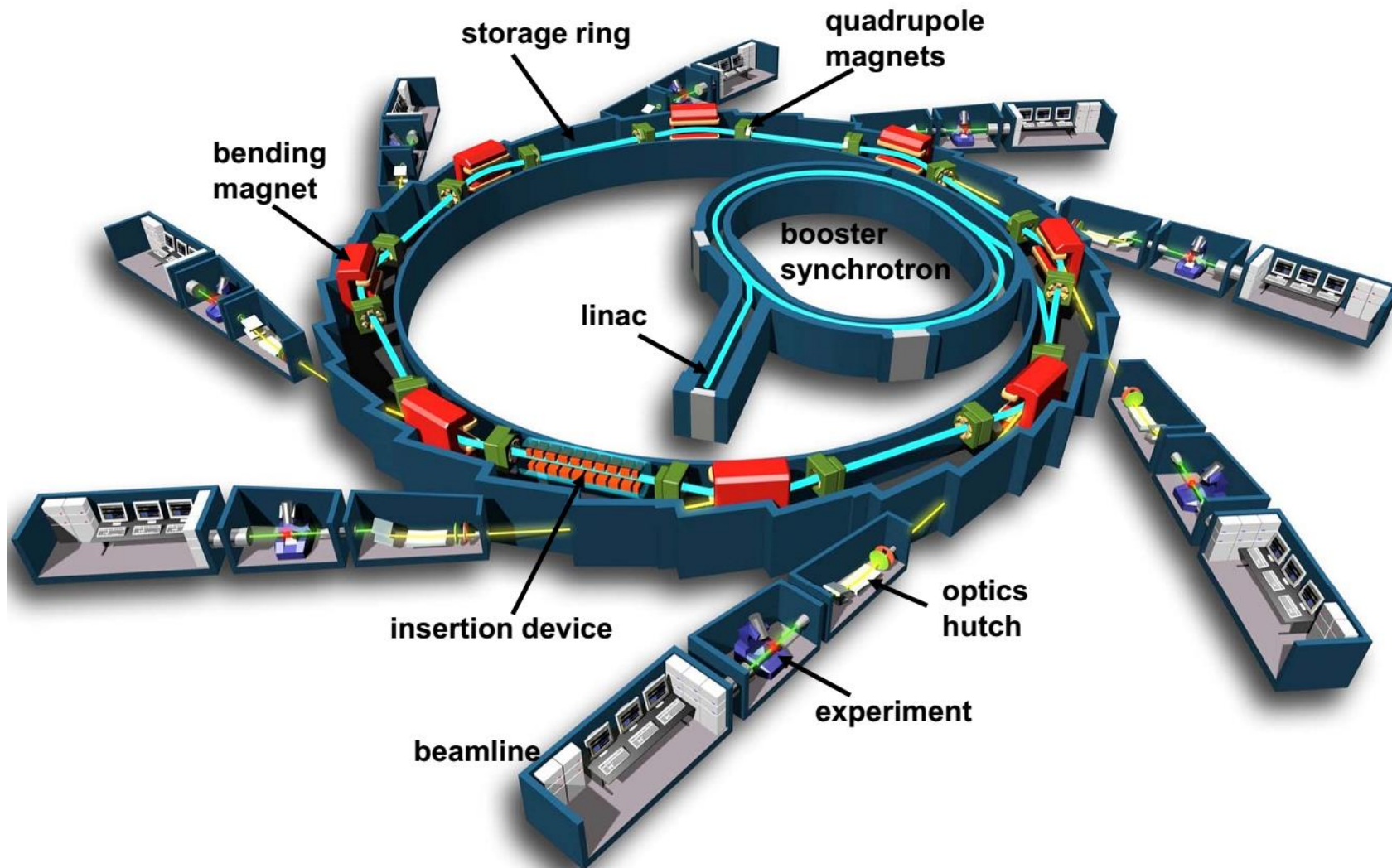
3. 增能環



儲存環 3D 圖

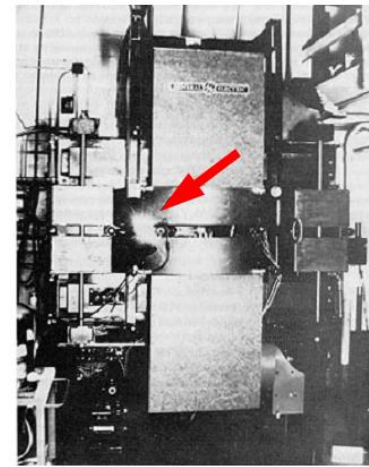


A Synchrotron Step by Step



A brief history

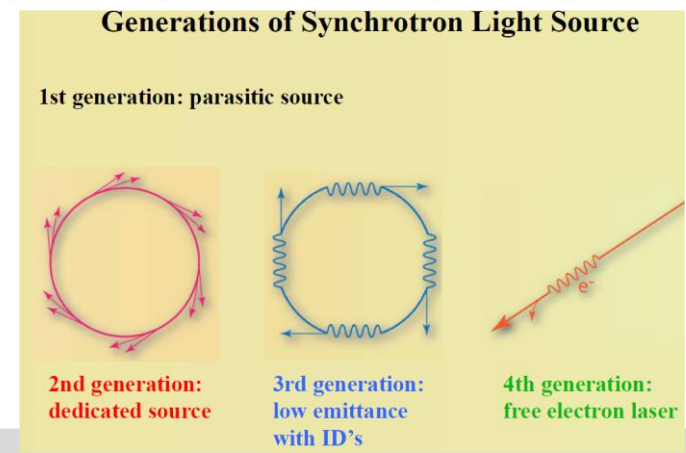
- First observed:
1947, General Electric, 70 MeV synchrotron
- First user experiments:
1956, Cornell, 320 MeV synchrotron
- First insertion Device:
1979, 7 pole wiggler, SSRL
- 1st generation light sources: high energy physics synchrotrons and storage rings used parasitically for synchrotron radiation – eg DESY (Germany), INS-SOR (Tokyo), SPEAR (USA), (1960's, 1970's)
- 2nd generation light sources: purpose built synchrotron light sources, eg Photon Factory, NSLS, Daresbury (1980s onwards)
- 3rd generation light sources: optimised for high brilliance with low emittance and Insertion Devices; SPRing-8, ESRF, APS, Diamond, ... (1990's onwards)
- Free Electron Laser sources: FLASH (Germany), LCLS (USA), SACLA (Japan), FERMI (Italy) ... (2000's)
- Next??



2015 Cheiron School

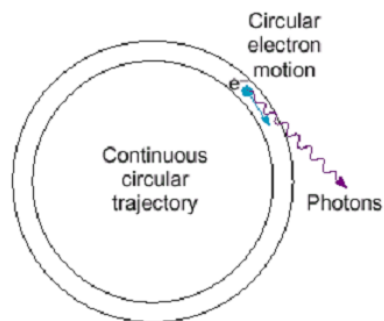


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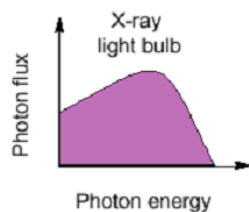


Third Generation Sources: Undulator Insertion Devices

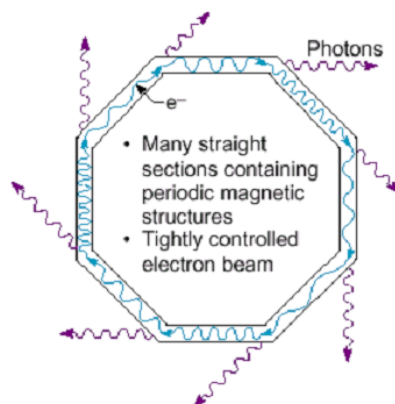
1st, 2nd Generation



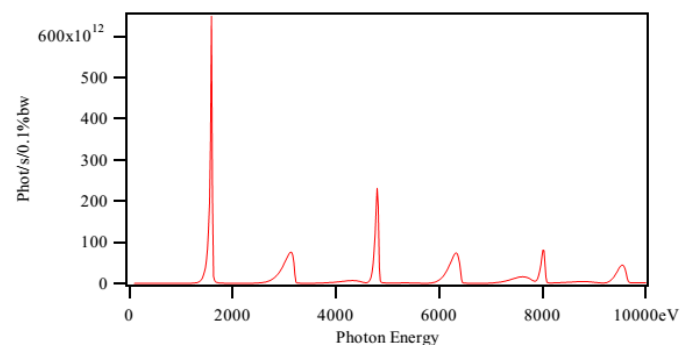
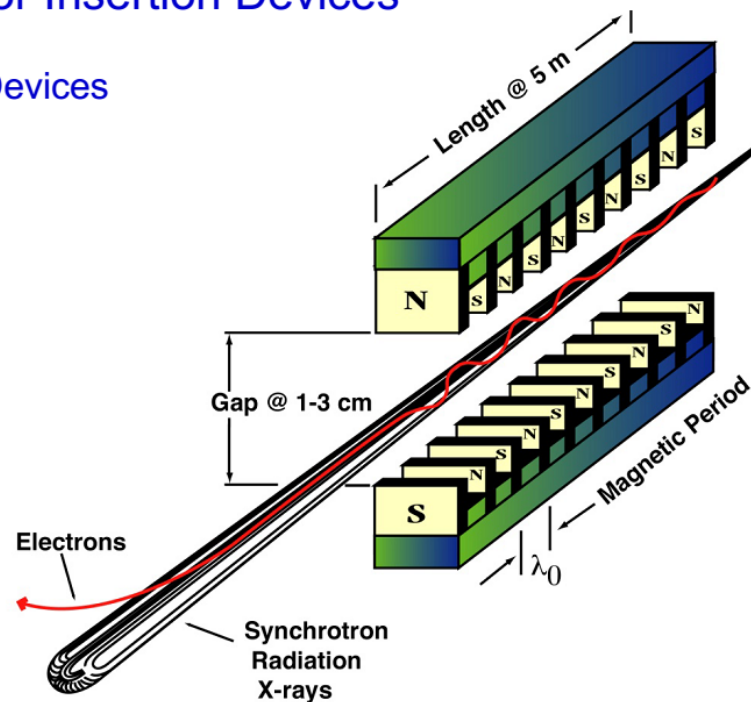
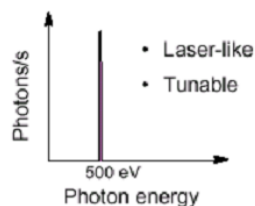
Bend Magnet Radiation



3rd Generation: Insertion Devices

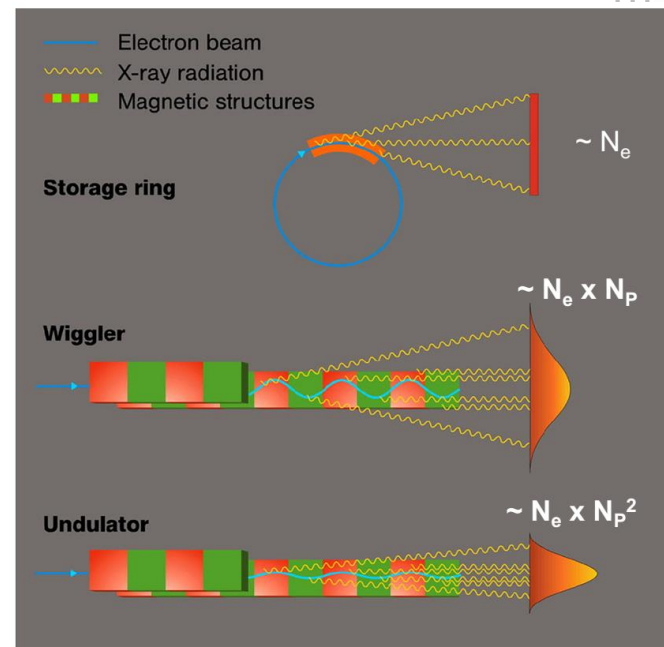
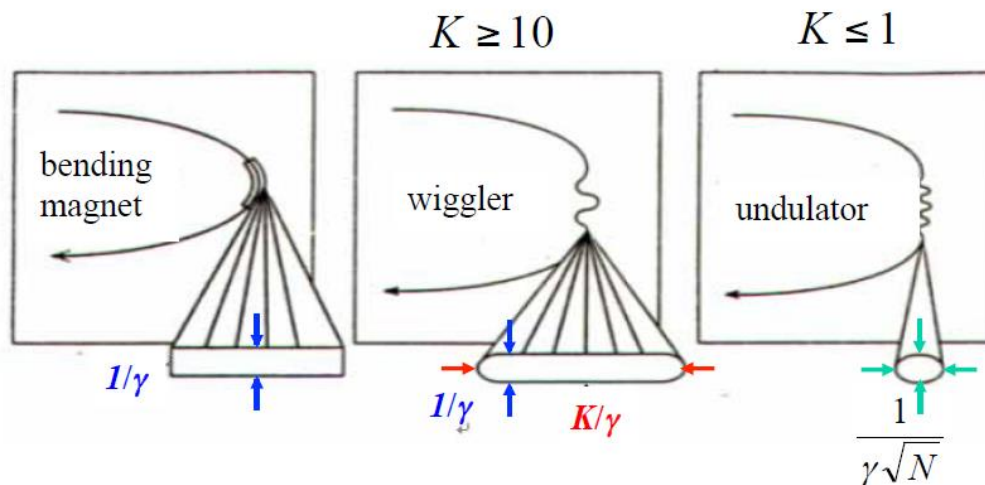
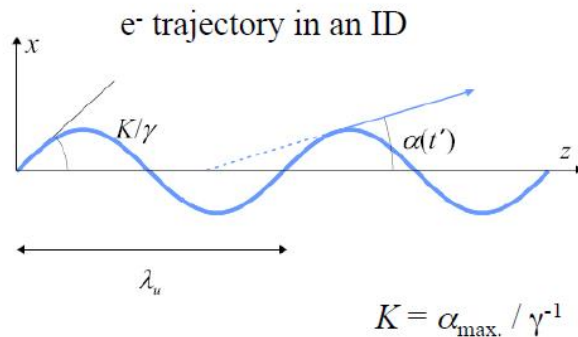
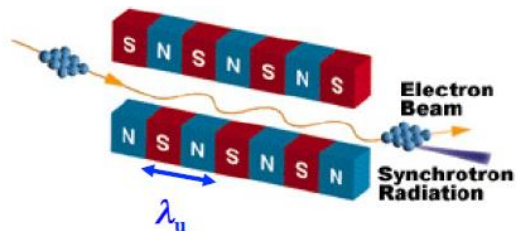


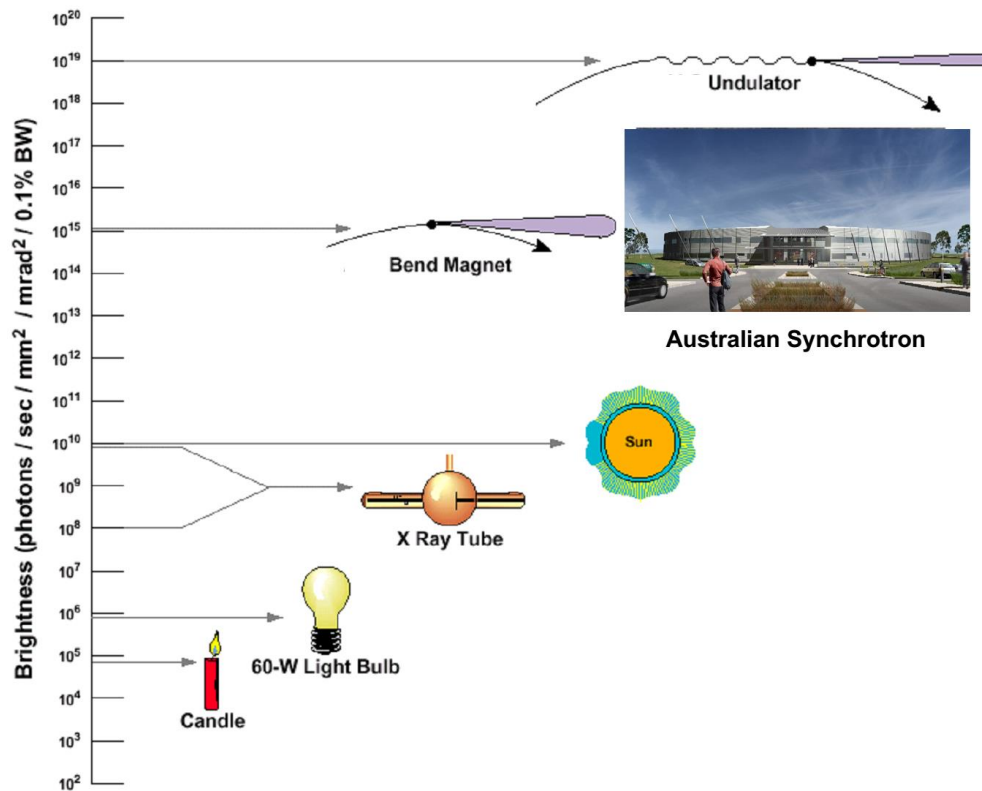
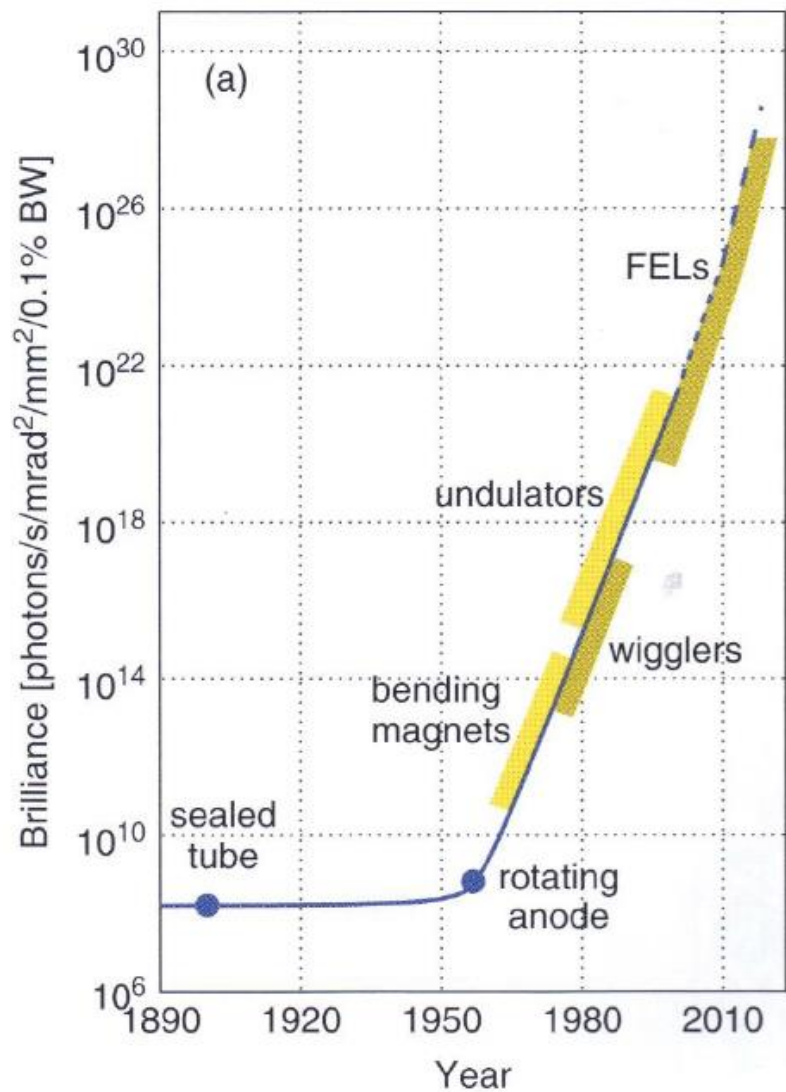
Undulator Radiation



Angular distribution of synchrotron radiation emitted from various magnets

Wiggler or undulator

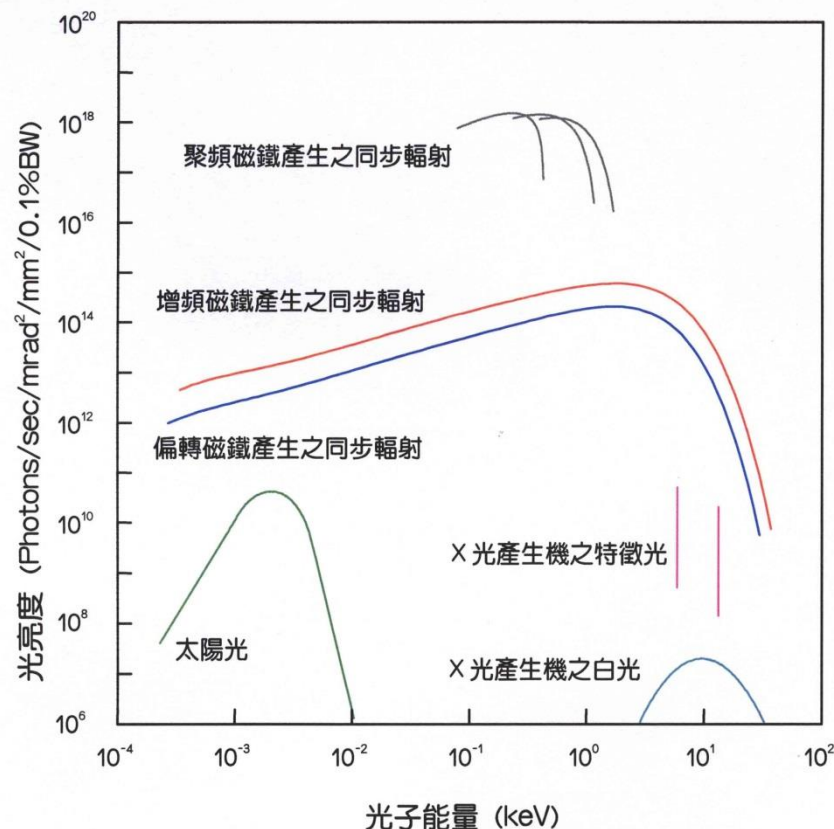




Unique Features of Synchrotron Light Source

- High intensity
- Continuous spectrum
- Excellent collimation
- High polarization
- Pulsed-time structure

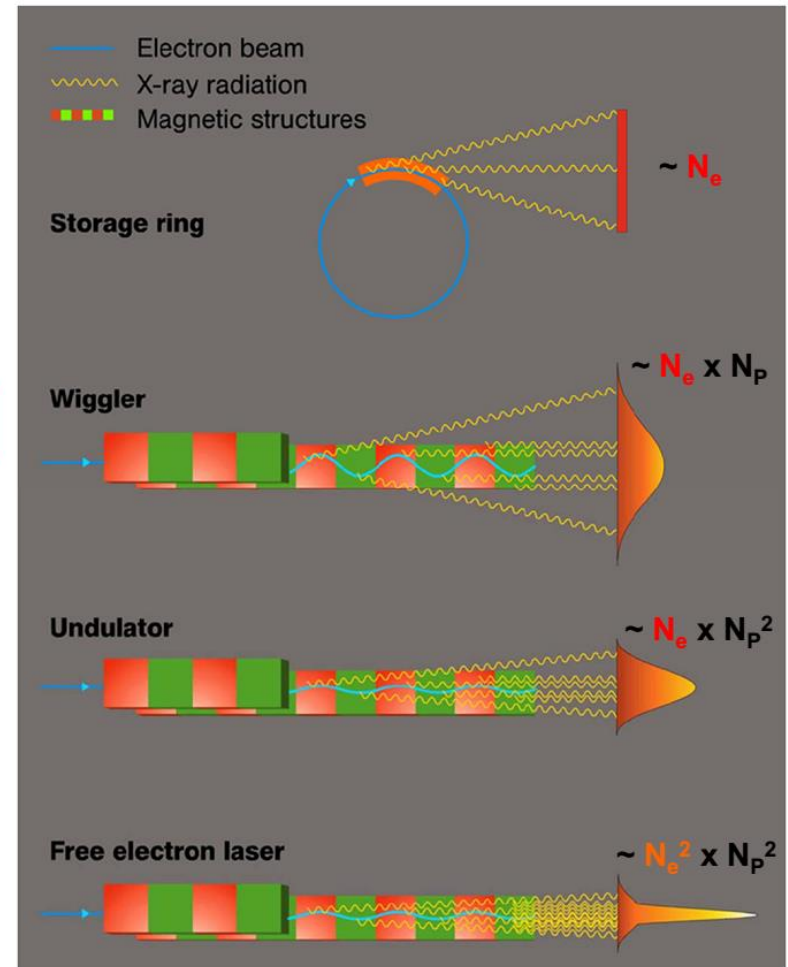
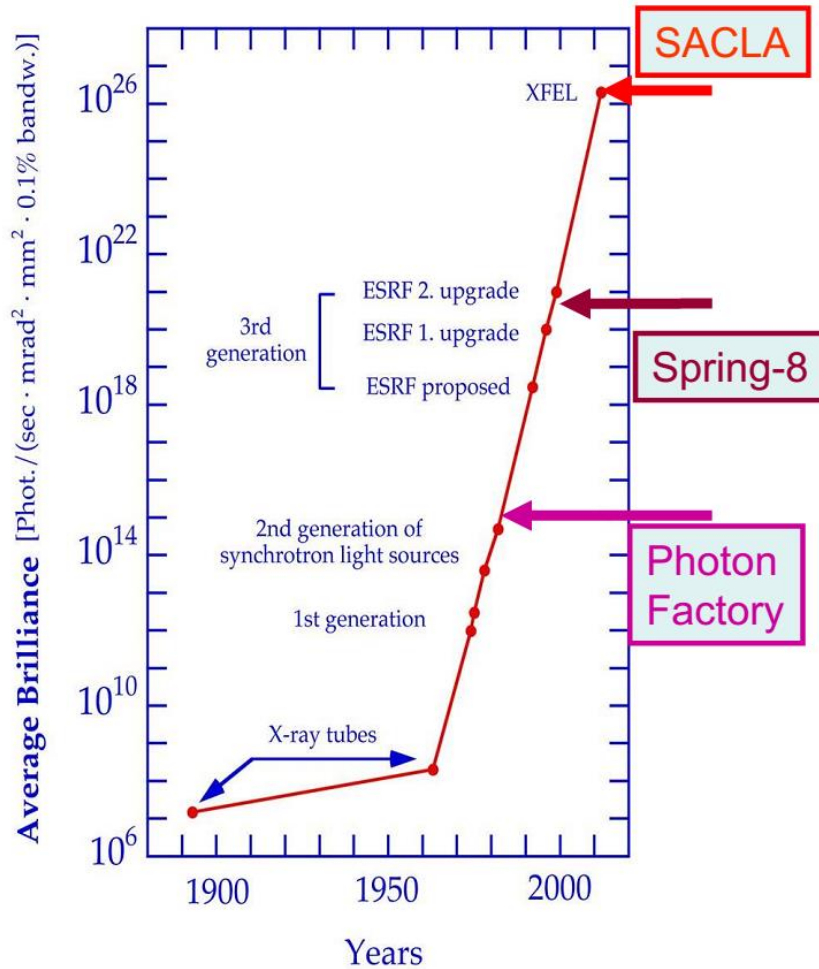
以X光為例，同步加速器光源在這個波段的亮度比傳統X光機還要強百萬倍以上！過去需要幾個月才能完成的實驗，現在只需幾分鐘便能得到結果。以往因實驗光源亮度不夠而無法探測的結構，現在藉由同步加速器光源，都可分析得一清二楚，也因此得以開發新的研究領域。



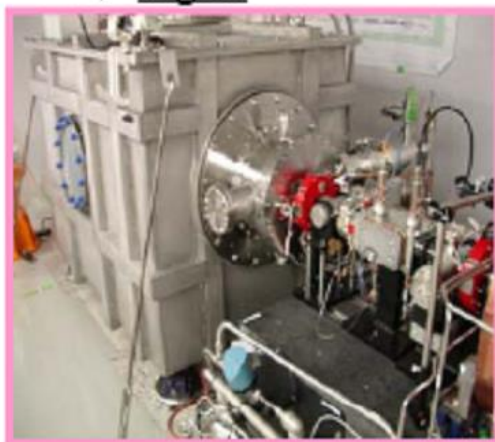
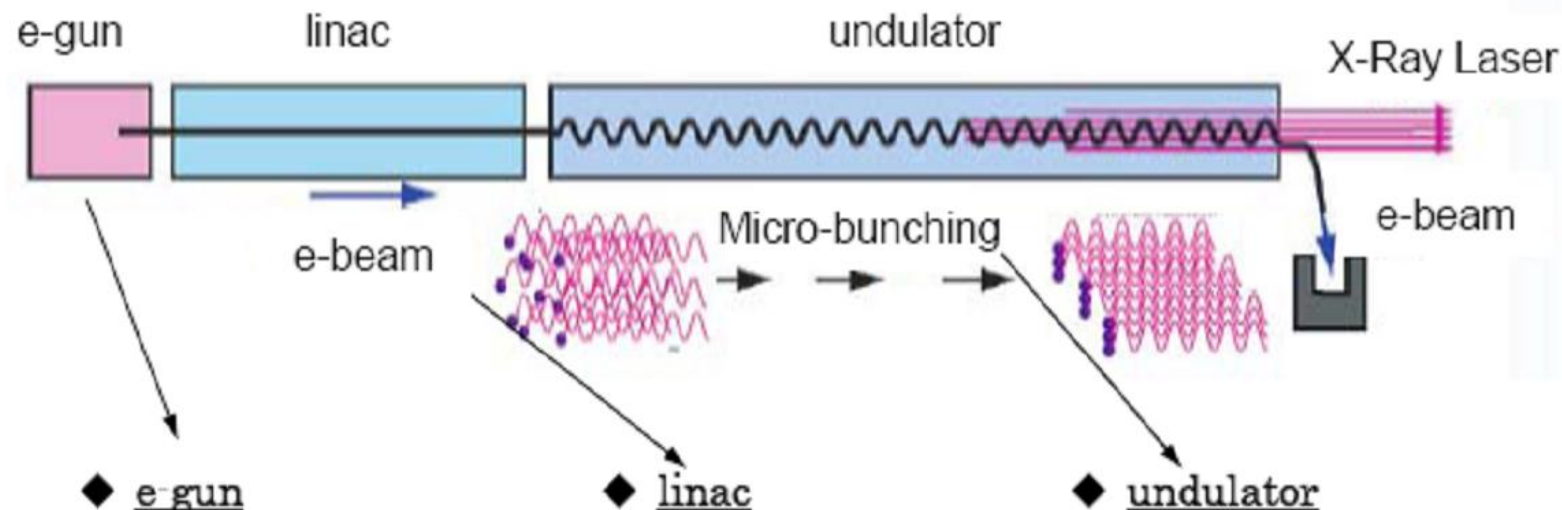
- 光子能量：一般單位為電子伏特(eV)，一電子伏特為電子在真空中通過一伏特電位差所獲得的能量。
- 光亮度：指單位時間內通過單位立體角的單位頻寬光子數。



Next Step - X-ray Lasers? Yes → FELs



Linac-Based Free Electron Laser Self-Amplified Spontaneous Emission (SASE)



SACLA 1st beamline: 90m Undulator



2012 Cheiron School Tour

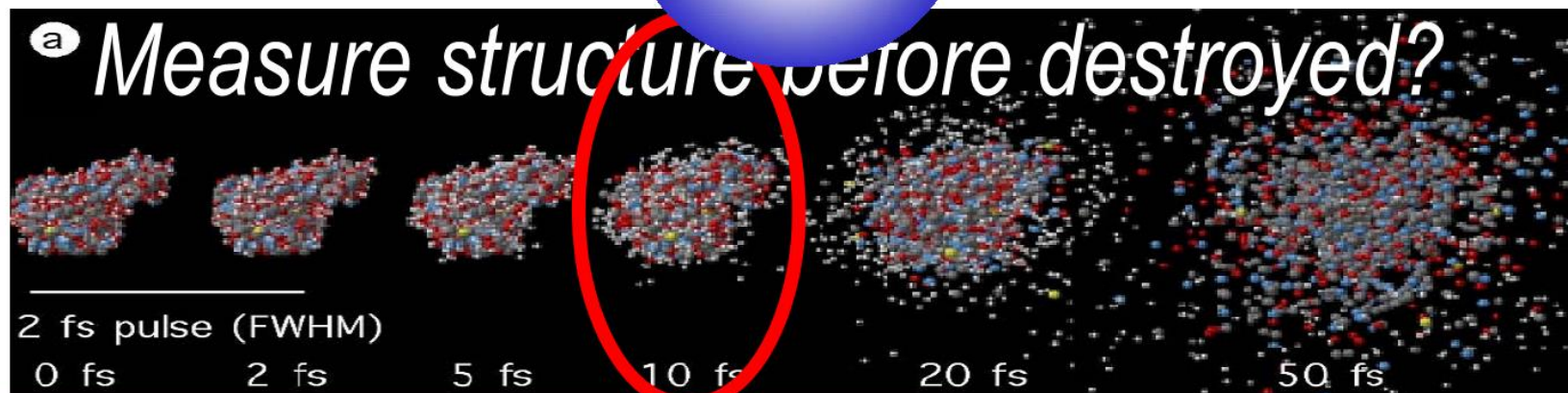
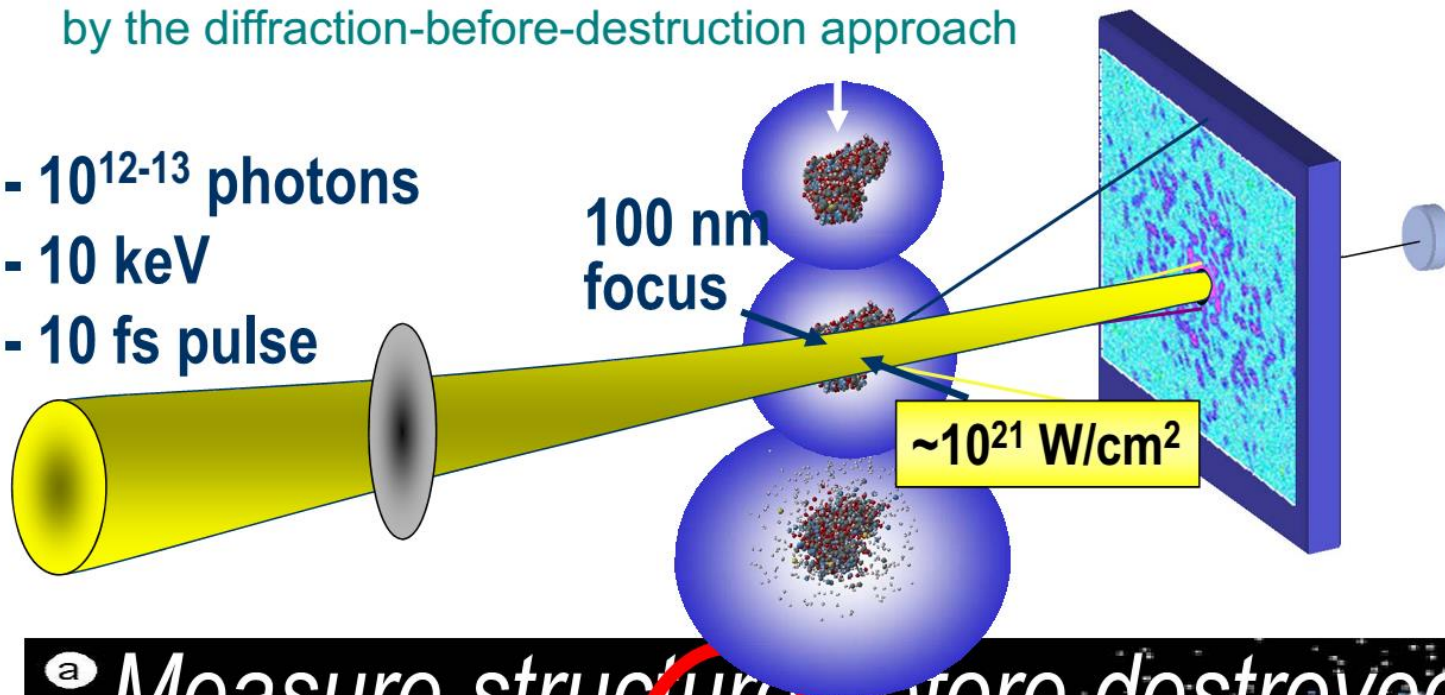


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Coherent diffractive imaging of single particles

by the diffraction-before-destruction approach

- 10^{12-13} photons
- 10 keV
- 10 fs pulse



Calculations. in vacuum Neutze et al., Nature 2000



$$E = h\nu = hc/\lambda,$$

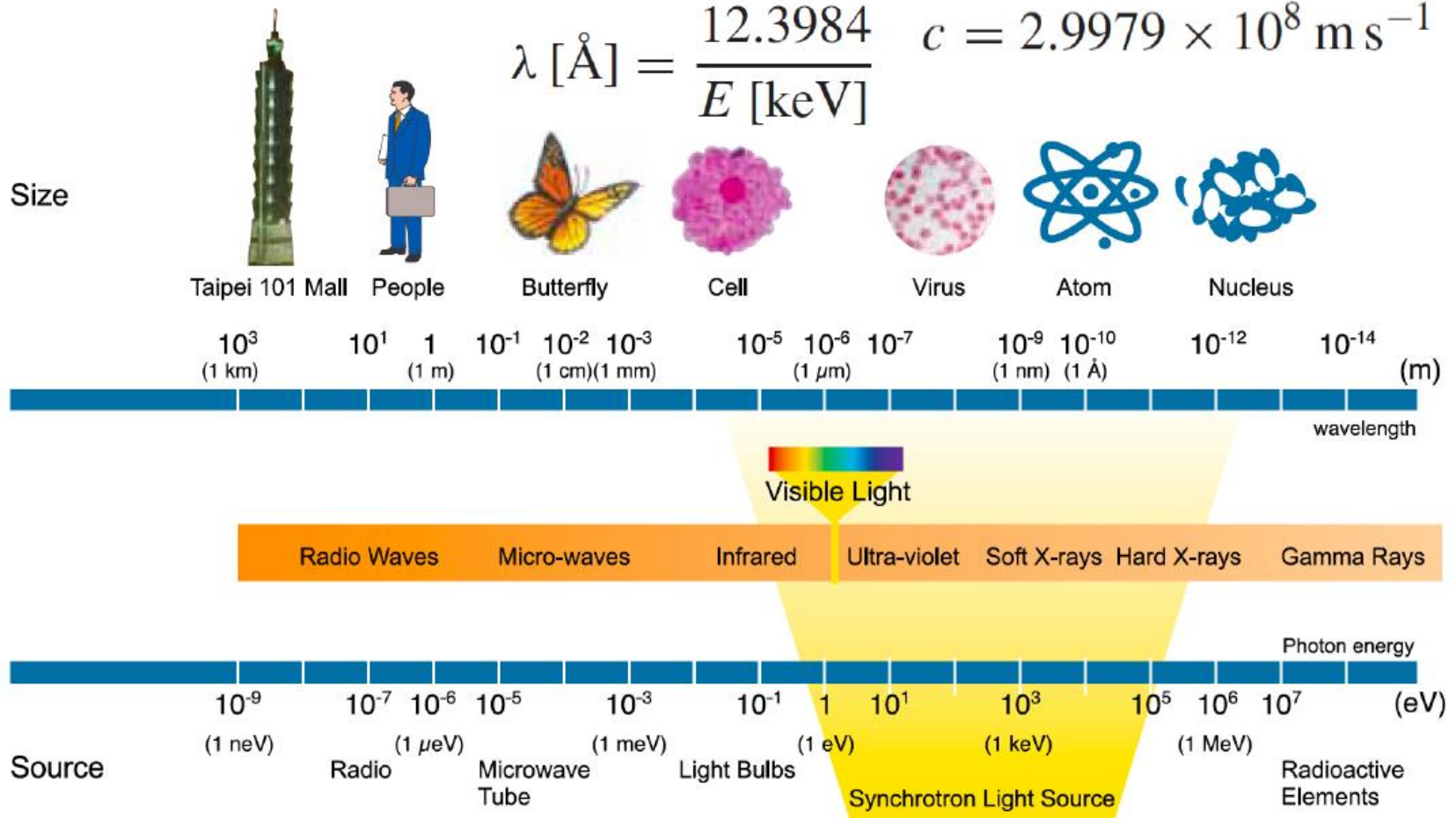
$$h = 6.626 \times 10^{-34} \text{ J s}$$

$$c = 2.9979 \times 10^8 \text{ m s}^{-1}$$

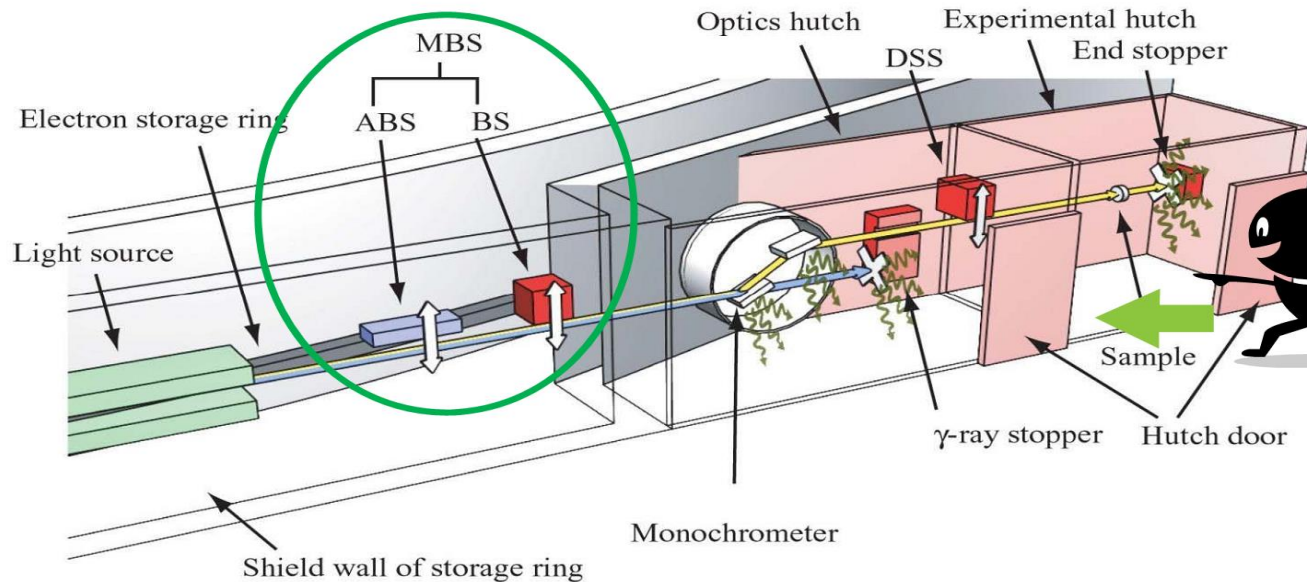
Electromagnetic Spectrum

$$\lambda [\text{\AA}] = \frac{12.3984}{E [\text{keV}]}$$

Size



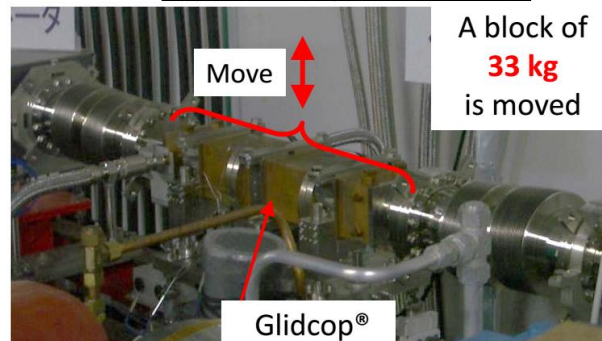
Beamline



When we operate a main beam shutter (MBS), what happens ?

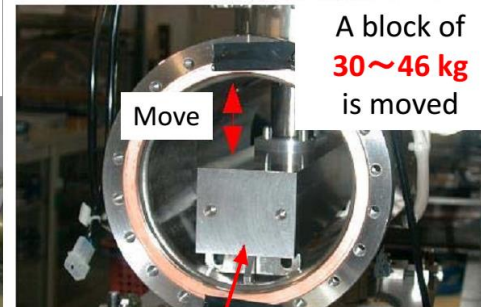
For safety

X-ray → **Absorber (Abs)** → **Beam shutter (BS)**
to protect BS from heat load to shield you against radiation



A block of **33 kg** is moved

(copper that is dispersion-strengthened with ultra-fine particles of aluminum oxide)



A block of **30~46 kg** is moved

Heavy metal (alloy of tungsten)

the thermal conductivity not so high

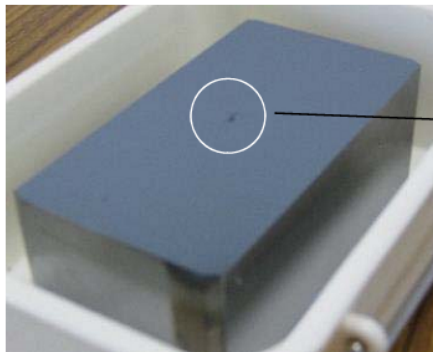


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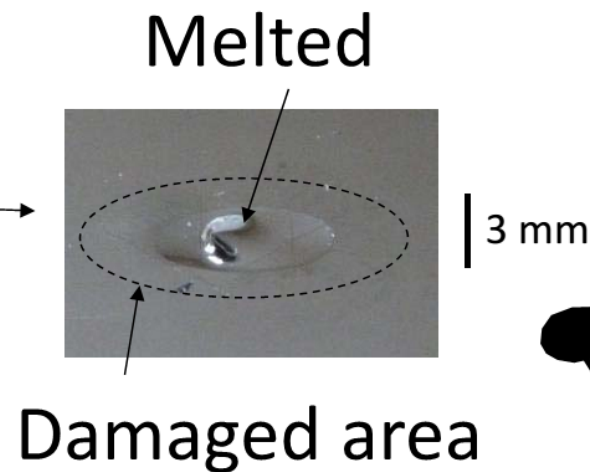
If an optical component is irradiated
by too much power

One user opened FE slit excessively.

2kW



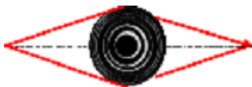
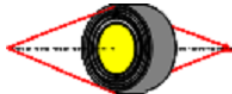
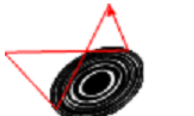
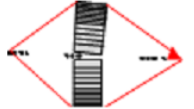
LN2-cooled
Si crystal



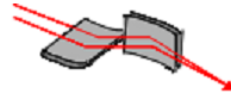
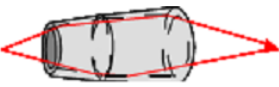
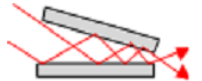
Slit : *"Too much is as bad as too little"*



Overview of x-ray focusing devices

Diffraction	focus size, focal length [energy]	energy range	aberration -coma -chromatic -figure error
 Fresnel Zone Plate	12 nm, $f = 0.16$ mm [0.7 keV], 30 nm, $f = 8$ cm [8 keV]	soft x-ray hard x-ray	-coma small -chromatic exist -figure error small
 Sputter sliced FZP	0.3 μ m, $f = 22$ cm [12.4 keV], 0.5 μ m, $f = 90$ cm [100 keV]	8-100 keV	-coma small -chromatic exist -figure error large $\rightarrow$ small
 Bragg FZP	2.4 μ m, $f = 70$ cm [13.3 keV]	mainly hard x-ray	-coma small -chromatic exist -figure error small
 Multilayer Laue Lens	16 nm(1D), $f = 2.6$ mm [19.5 keV], 25nm $\times$ 40nm, $f = 2.6$ mm, 4.7mm [19.5 keV]	mainly hard x-ray	-coma large -chromatic exist -figure error small

Refraction	focus size, focal length [energy]	energy range	aberration -coma -chromatic -figure error
 Pressed Lens	1.5 μ m, $f = 80$ cm [18.4 keV], 1.6 μ m, $f = 1.3$ m [15 keV]	mainly hard x-ray	-coma small -chromatic exist -figure error large
 Etching Lens	47nm $\times$ 55nm, $f = 1$ cm, 2cm [21 keV]	mainly hard x-ray	-coma small -chromatic exist -figure error small

Reflection	focus size, focal length [energy]	energy range	aberration -coma -chromatic -figure error
 Kirkpatrick-Baez Mirror	7 nm $\times$ 8nm, $f = 7.5$ cm [20 keV]	soft x-ray hard x-ray	-coma large -chromatic not exist -figure error small
 Wolter Mirror	0.7 μ m, $f = 35$ cm [9 keV]	<10 keV	-coma small -chromatic not exist -figure error large
 X-ray Waveguide	95 nm, [10 keV]	soft x-ray hard x-ray	-coma large -chromatic not exist -figure error large



World Map of Synchrotron Facilities



Outline

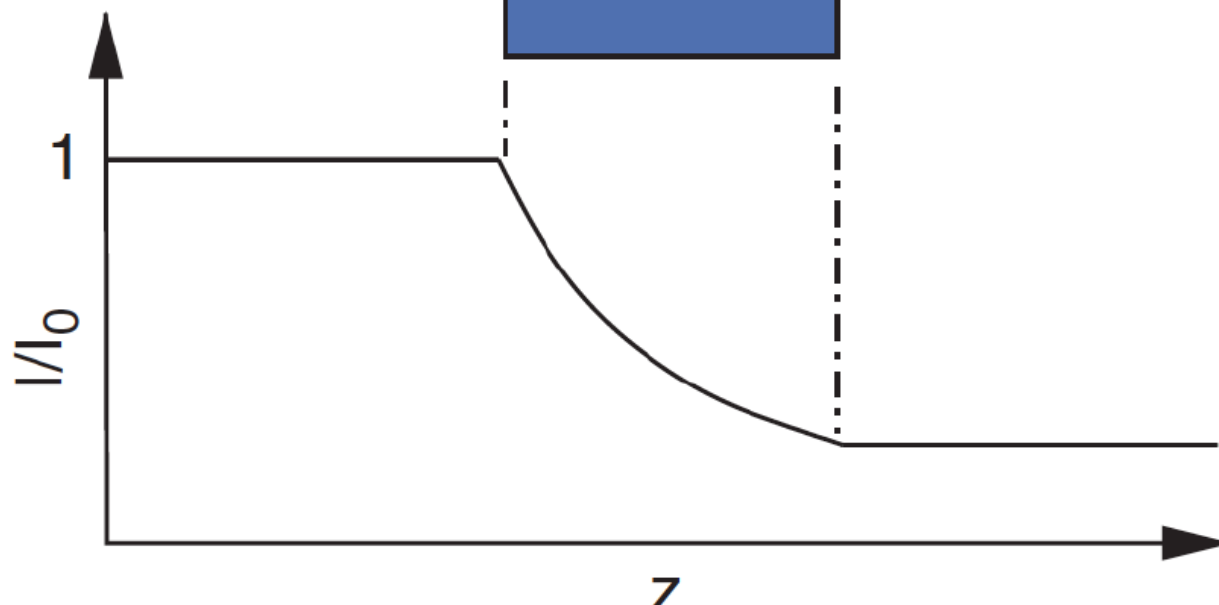
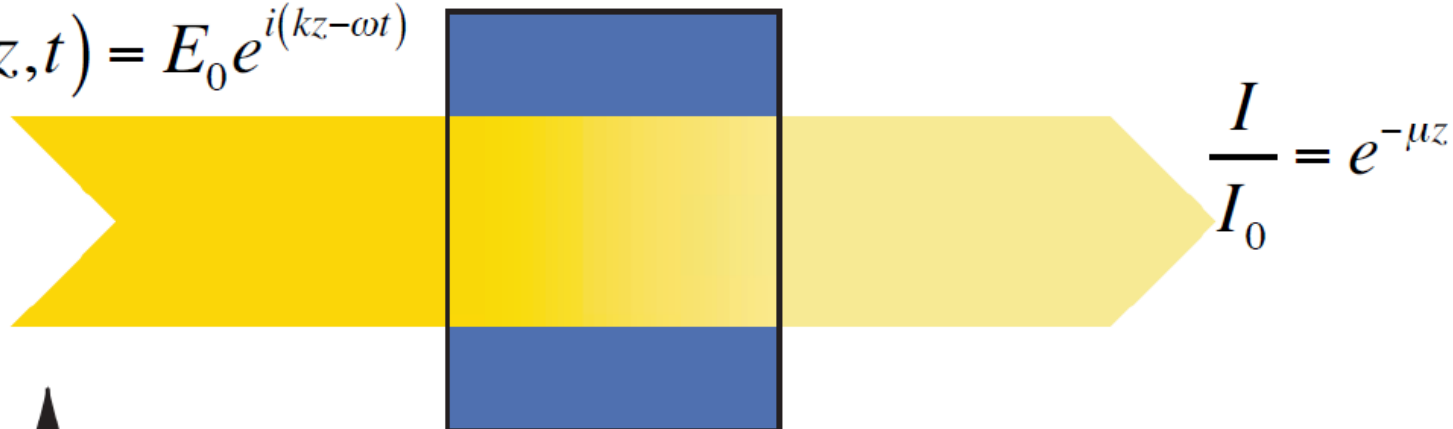
- Synchrotron Light Source
- Application of Synchrotron Light
- X-ray nano probe at TPS



Absorption

$$E(z, t) = E_0 e^{-n_I k z} e^{i(n_R k z - \omega t)}$$

$$E(z, t) = E_0 e^{i(kz - \omega t)}$$



absorption coefficient

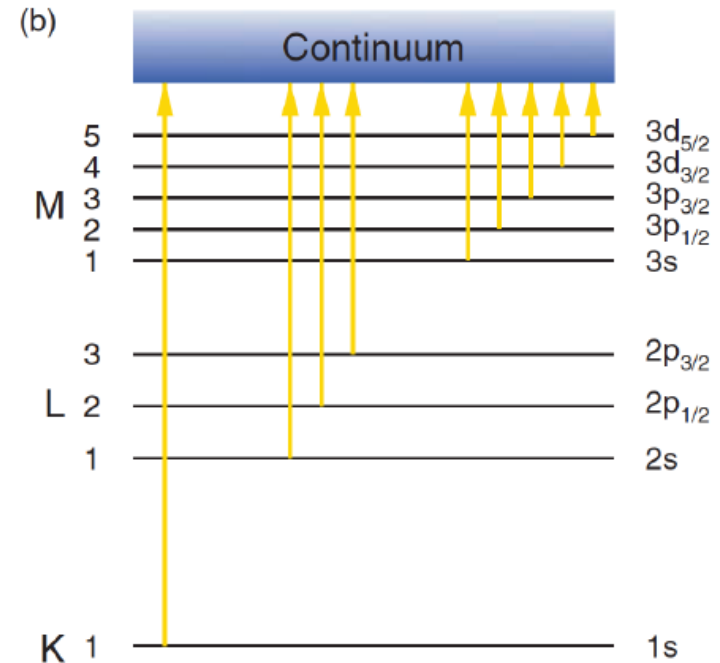
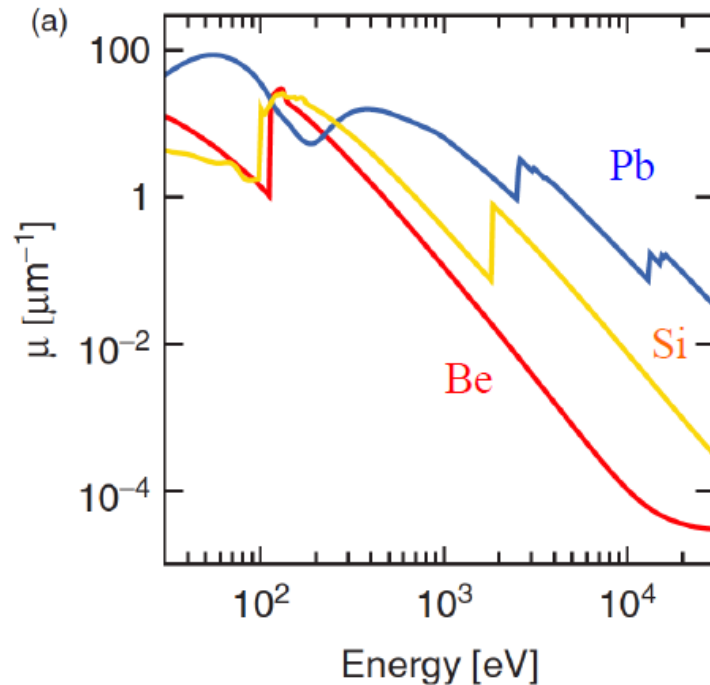
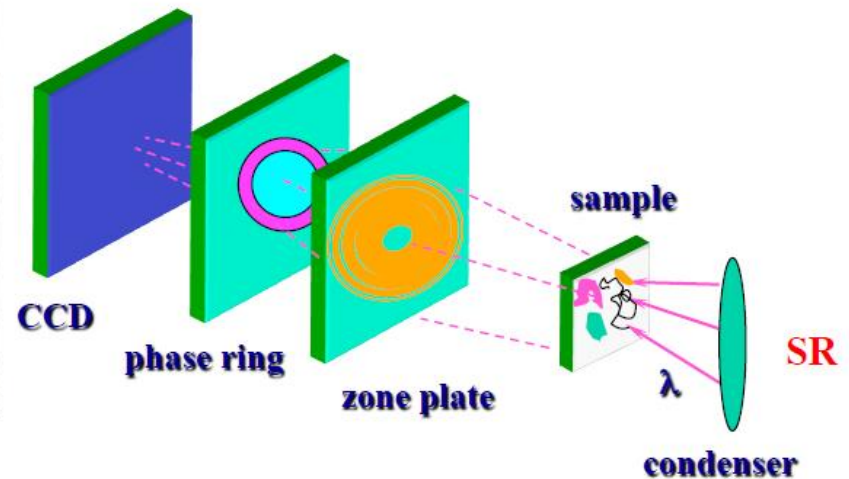


Figure 2.16 (a) The x-ray absorption coefficient μ for beryllium (red curve), silicon (yellow) and lead (blue) as a function of the photon energy. (b) Sharp increases in the absorption occur when the photon energy is just sufficient to eject the electron from the electronic orbital to the continuum. The x-ray absorption (left) and atomic orbital labellings (right) are shown.



Transmission X-ray Microscope (TXM)

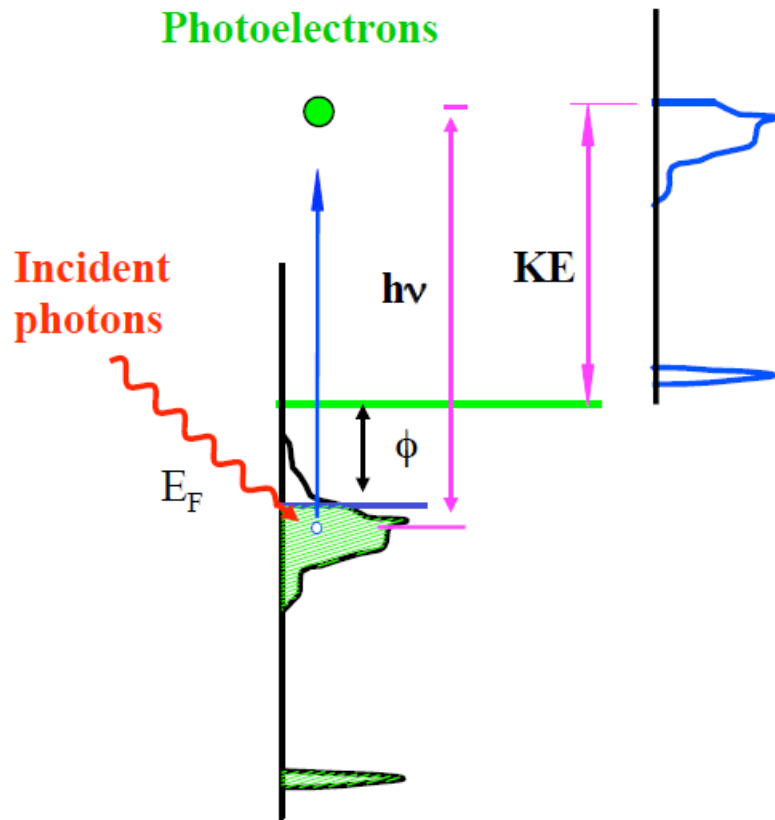


energy: 8 keV
3D tomography
spatial resolution = 60 nm



Photoemission Spectroscopy

Energy Distribution Curve (EDC)



$$KE = h\nu - BE - \phi$$

$$\frac{d\sigma}{d\Omega} \propto \sum \left| \langle \Psi_f | A \cdot P | \Psi_i \rangle \right|^2 \cdot \delta(E_f - E_i - h\nu)$$

Selection rule: $\Delta l = \pm 1$

$\Delta m_l = 0$ (linearly polarized)

$\Delta m_l = +1$ (L. circularly polarized)

$\Delta m_l = -1$ (R. circularly polarized)

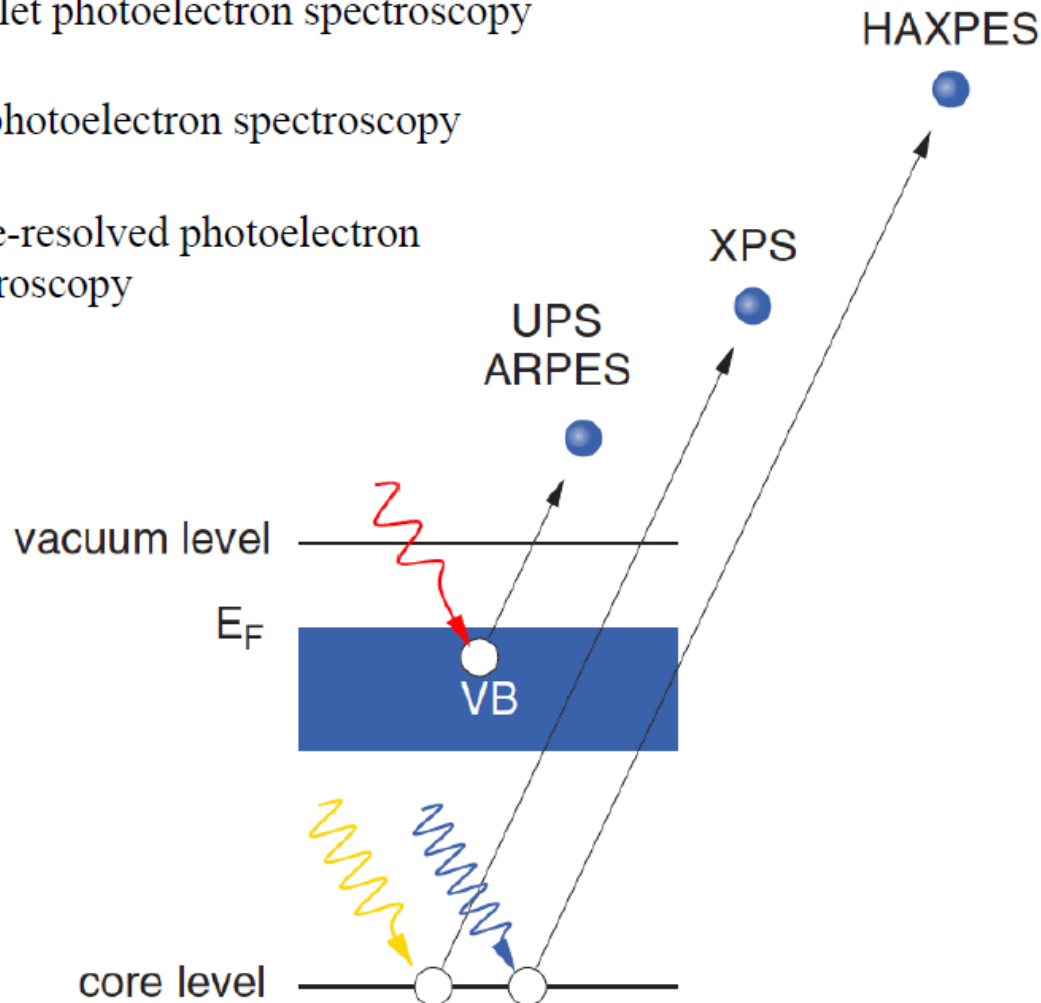


HAXPES = Hard X-ray photoelectron spectroscopy

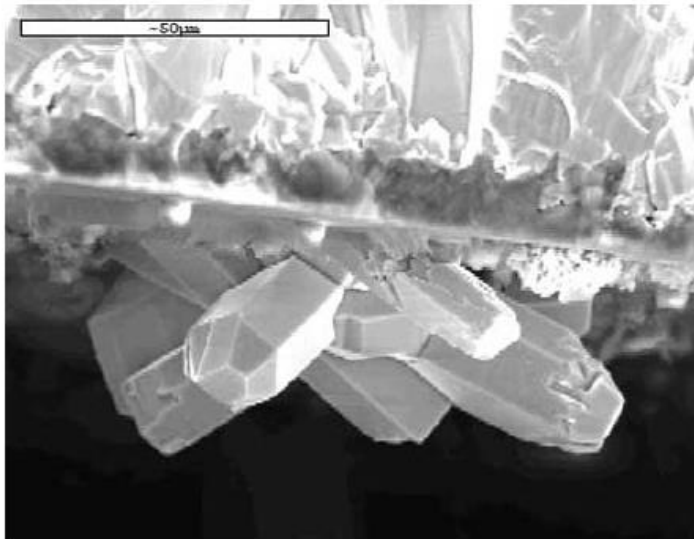
UPS = ultraviolet photoelectron spectroscopy

XPS = X-ray photoelectron spectroscopy

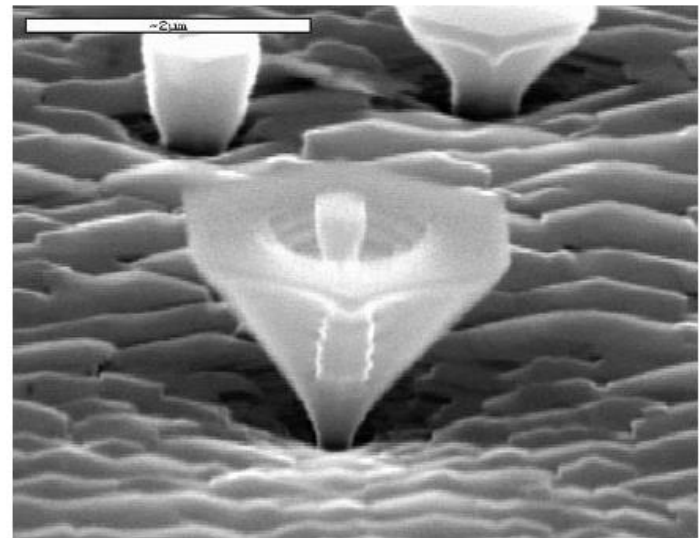
ARPES = angle-resolved photoelectron spectroscopy



“Crystals”

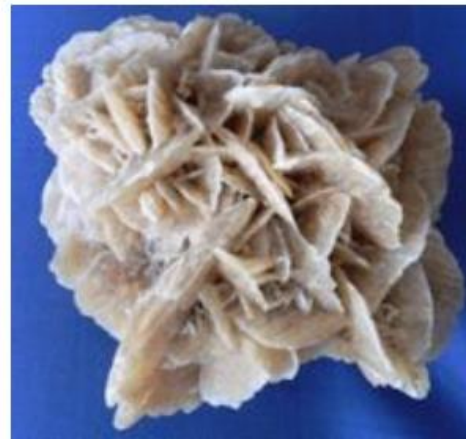


GaN (hexagonal) crystal cluster grown by hydride vapor phase epitaxy



AlN pyramids grown by MBE

Sand Rose of gypsum
(石膏) crystals



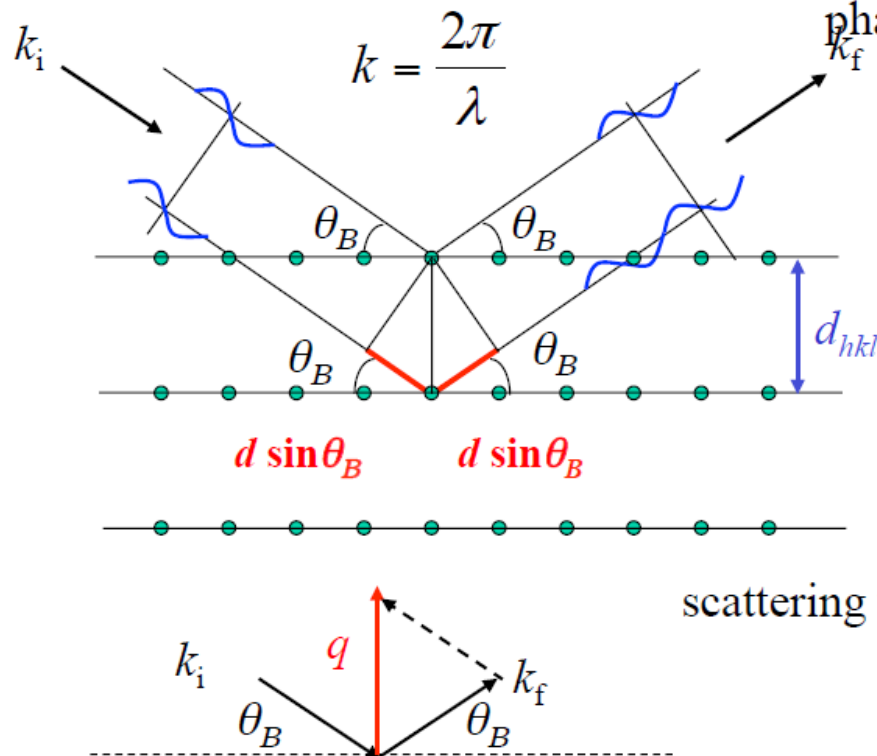
Bragg Law - X-ray reflected by the (hkl) planes

$$\vec{E} = E_0 e^{i(\vec{k} \cdot \vec{r} - \omega t)}$$

Path Difference $L = 2d_{hkl} \sin \theta_B$

Constructive interference: $L = n\lambda$

phase difference $\phi = k L$



Bragg Law: $2d_{hkl} \sin \theta_B = n\lambda$

$$2\pi \frac{2}{\lambda} \sin \theta_B = 2\pi \frac{1}{d_{hkl}} = G_{hkl}$$

scattering vector $\vec{q} = \vec{k}_f - \vec{k}_i$ $q = 2 \frac{2\pi}{\lambda} \sin \theta_B$

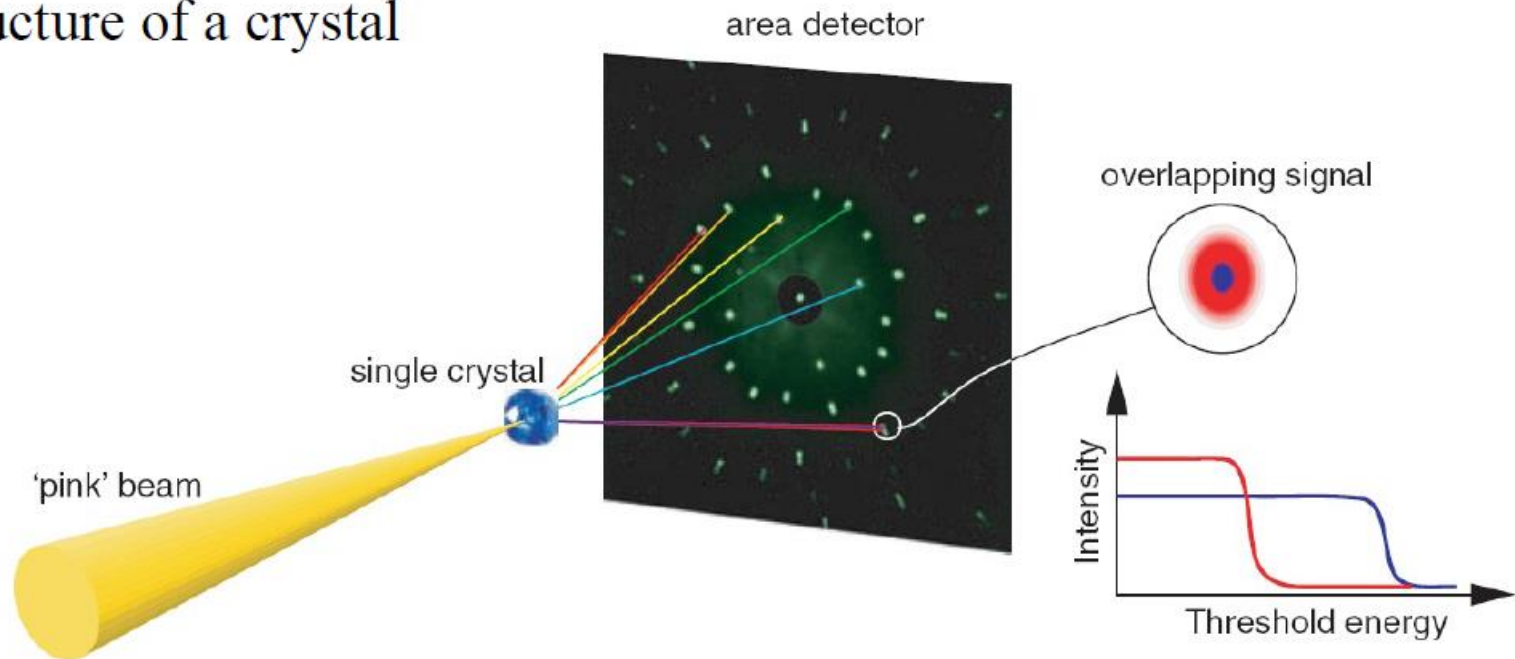
$q = G_{hkl}$

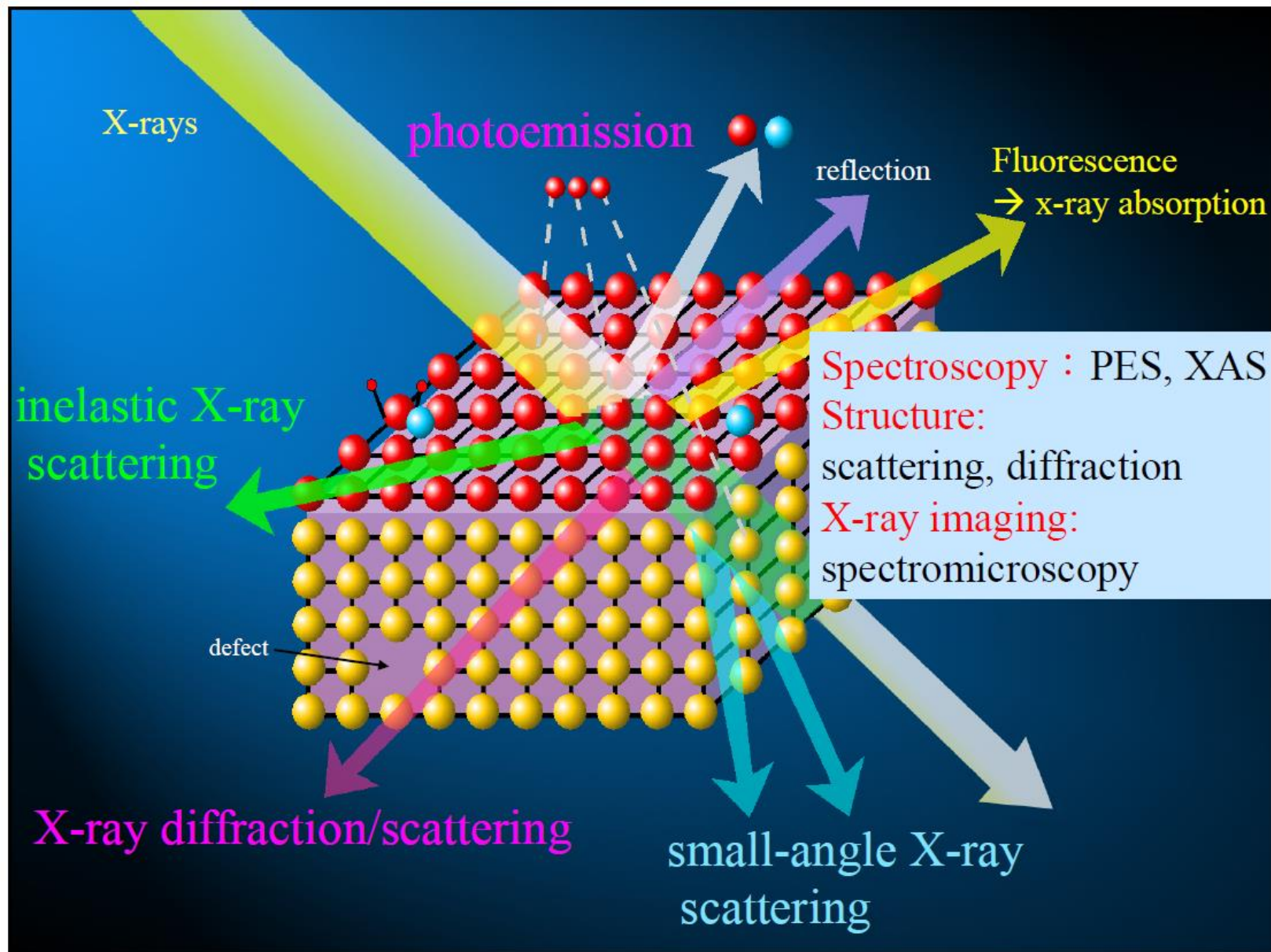
In terms of diffraction, two key characteristics of a set of crystal planes :
 $1/d$ and orientation

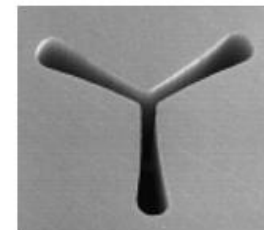
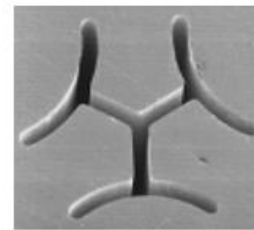
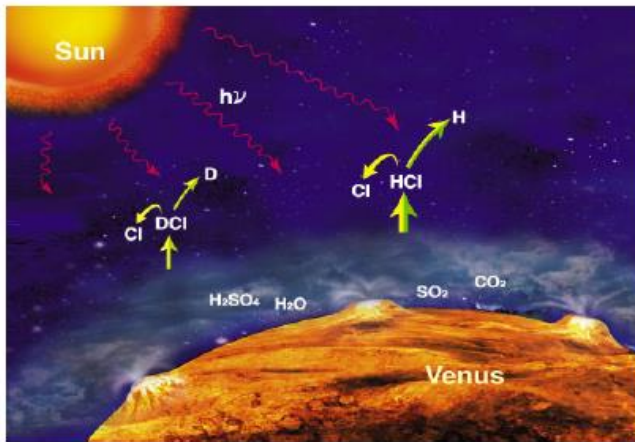
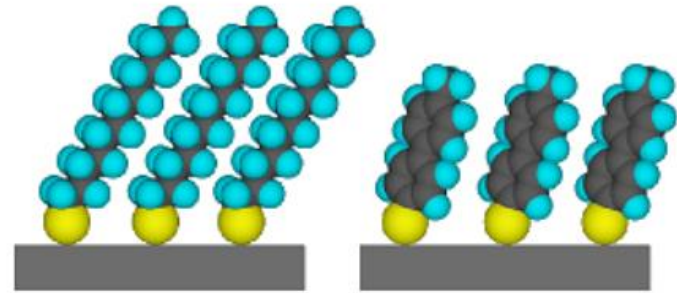
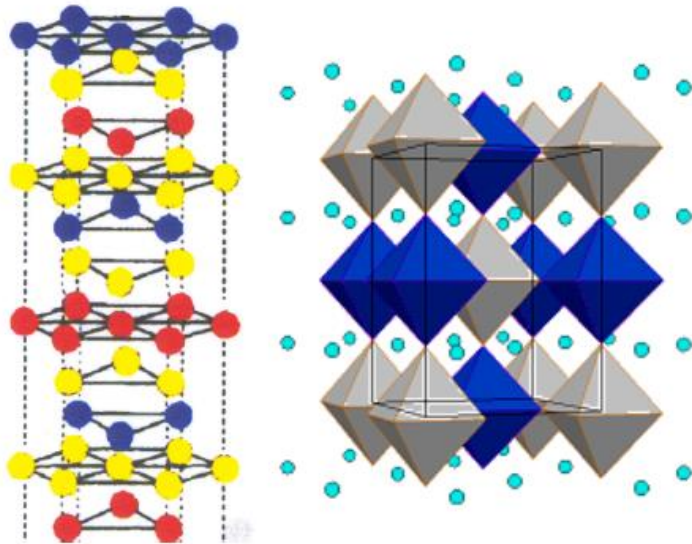


Single Crystal Diffraction - Laue Diffraction

- Method: stationary
- Light source: a polychromatic 'pink' beam (e.g. $\Delta E < 1$ keV @ 10 keV)
- Applications: orient single crystals, determine their crystal quality, dynamical studies of transient crystalline states (time-resolved study)
- Disadvantage: not well-suited for determining the full atomic structure of a crystal



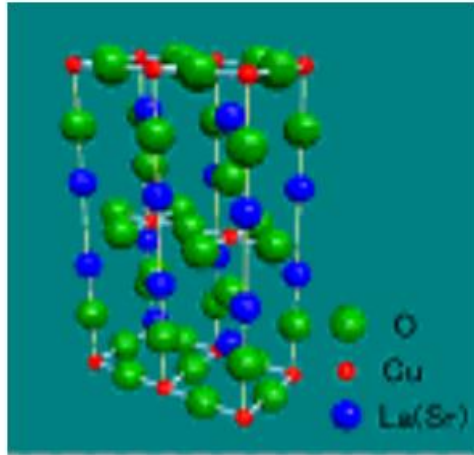




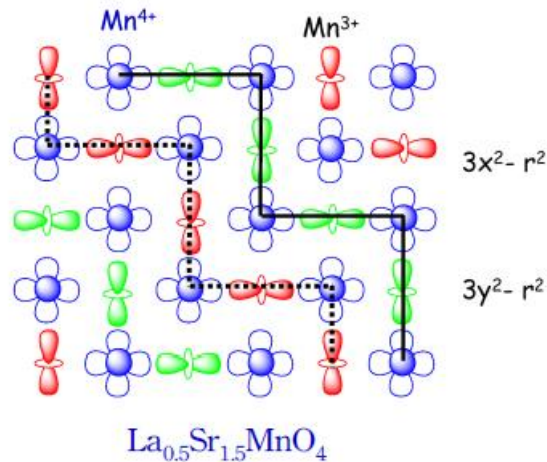
Synchrotron light source is a powerful tool for basic and applied studies in physics, chemistry, materials, biology and medicine, and their many subfields.



Condensed-Matter Physics



Electronic properties of novel materials can be revealed with X-ray scattering.

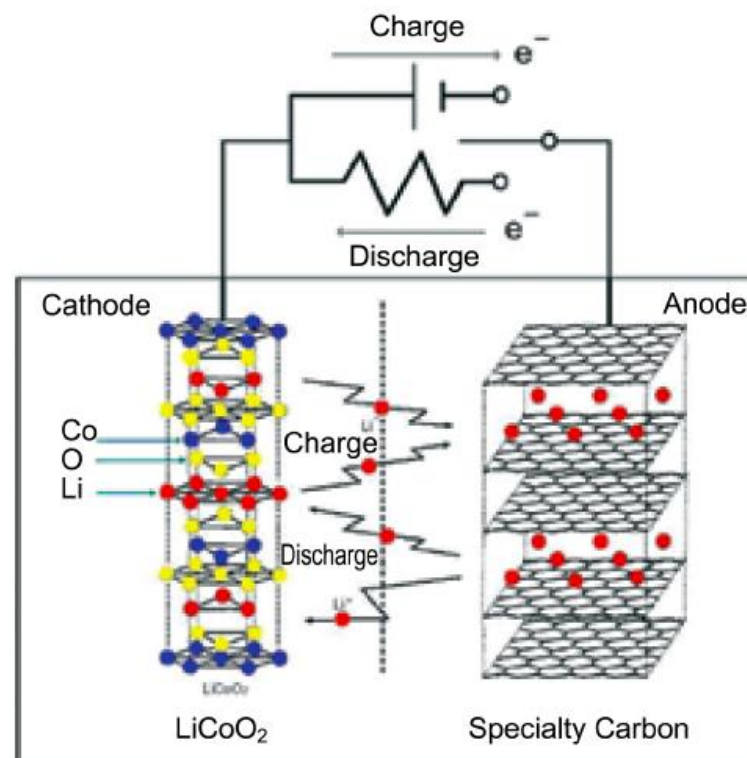
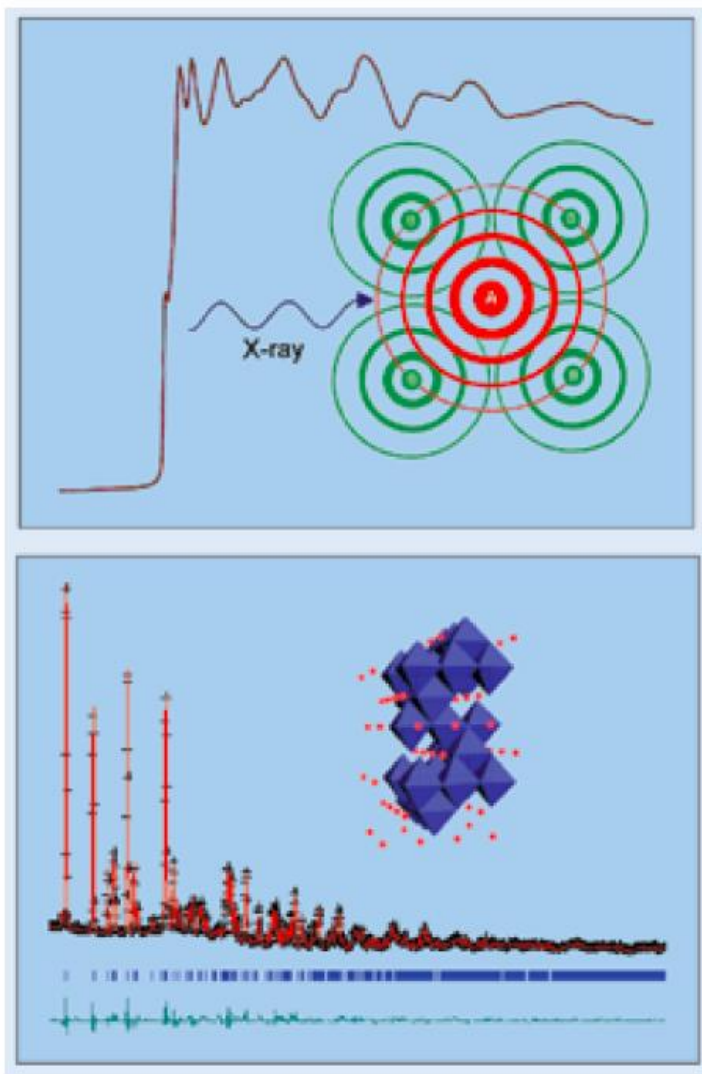


(Source: website of Railway Technical Research Institute, Japan)



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Energy Science



structure $\leftrightarrow$ electrochemical properties of electrode



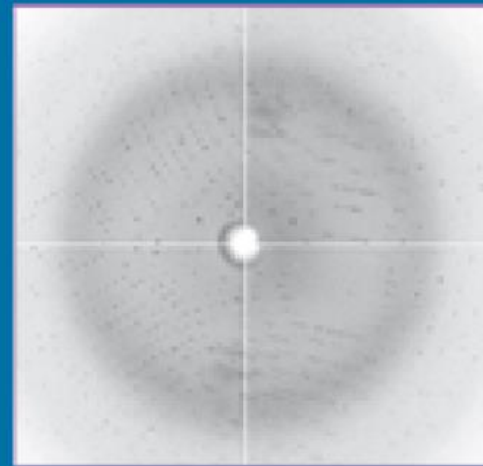
develop novel electrode materials.



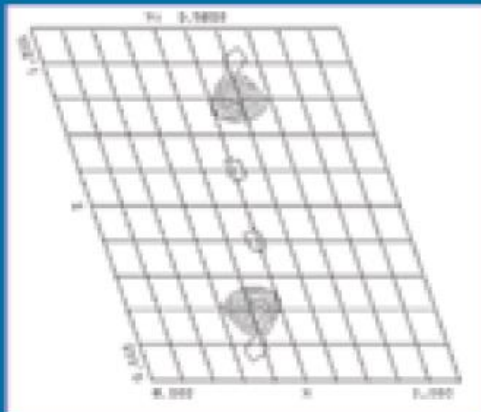
Biological structure: protein crystallography



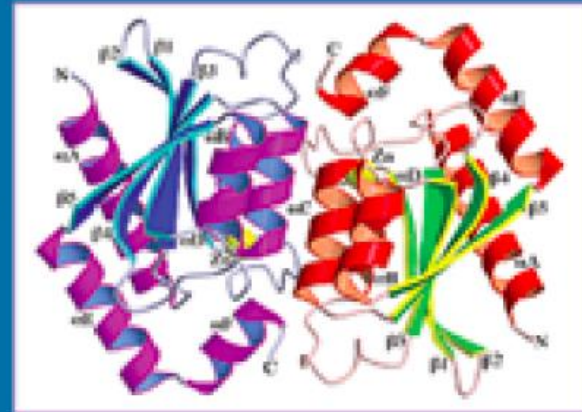
(1) crystallization



(2) data collection

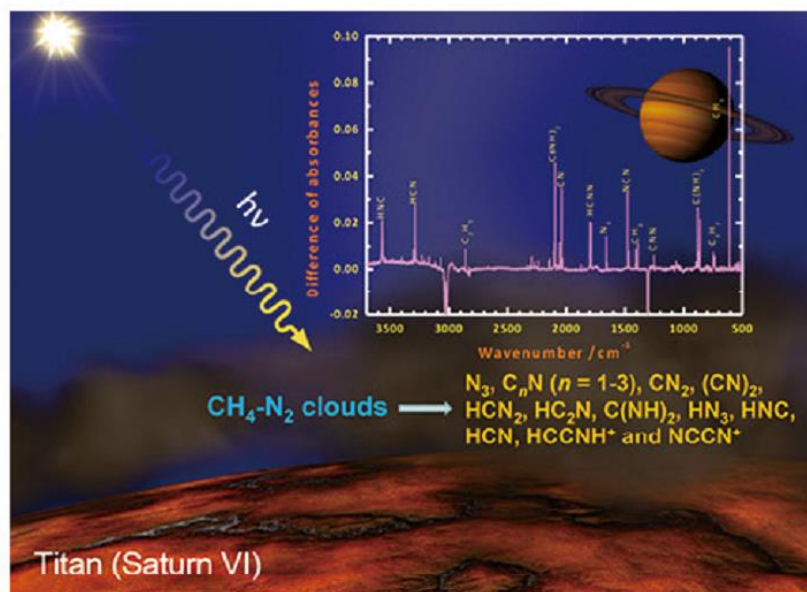
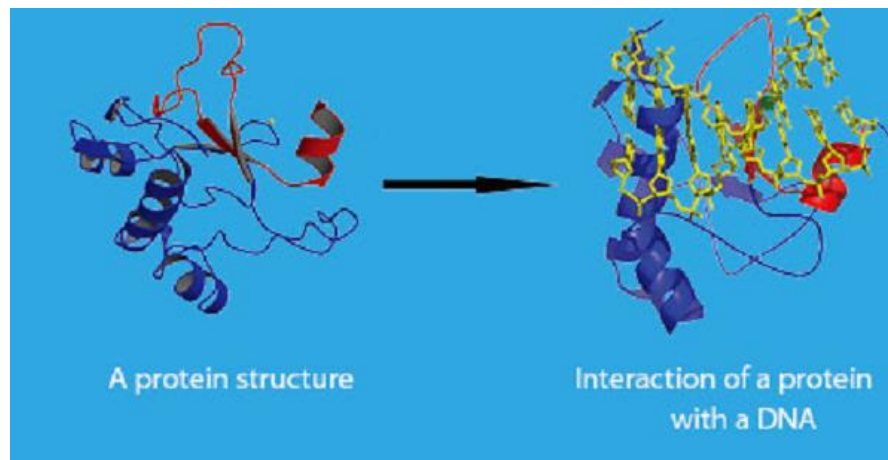


(3) determination of heavy atom position

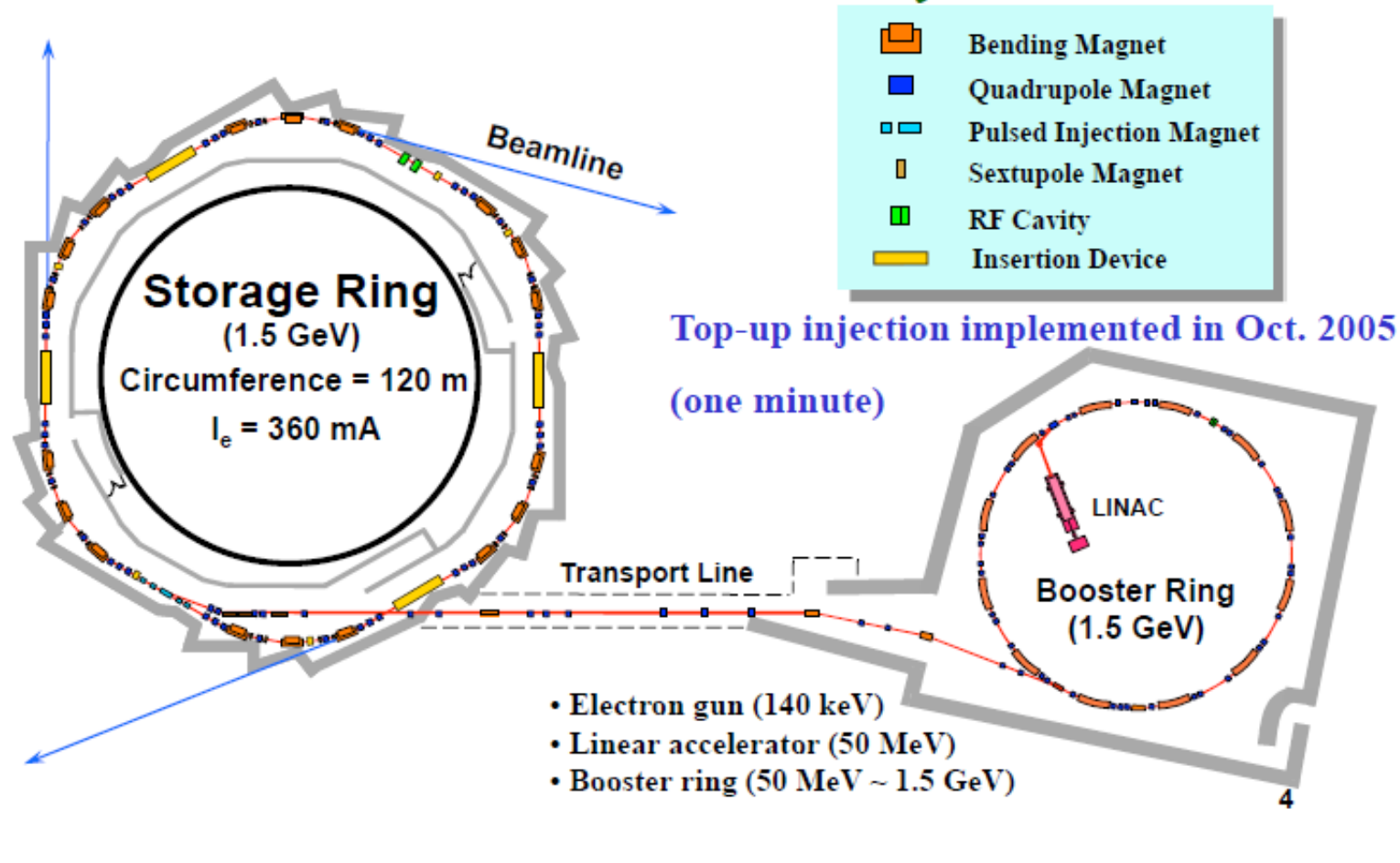


(4) determination of molecular structure





Taiwan Light Source (TLS) Accelerator Facility

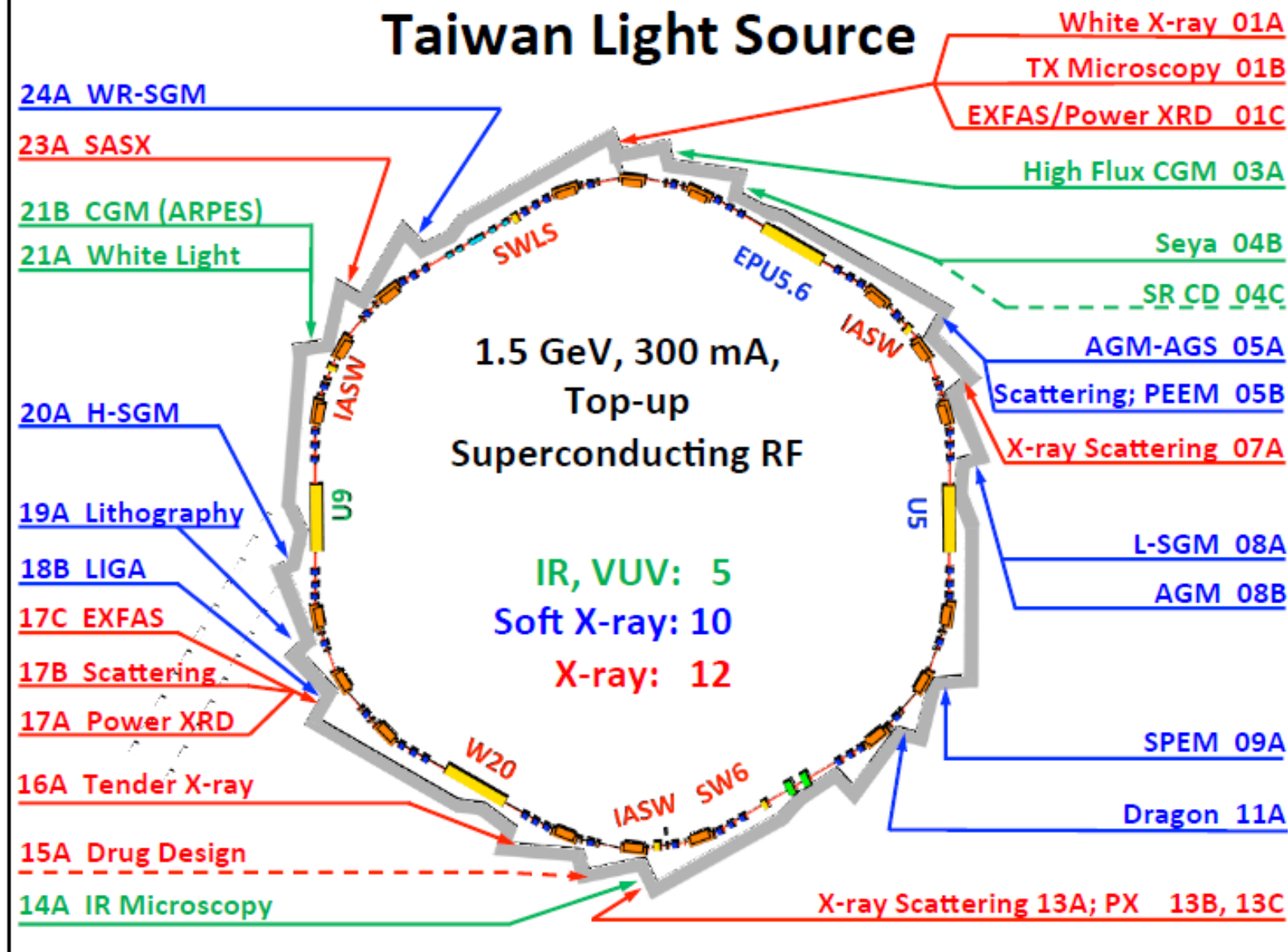


TLS Experimental Hall



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Taiwan Light Source



NSRRC is constructing a low-emittance synchrotron-based light source, Taiwan Photon Source (TPS)



3 GeV
518.4 m
500 mA
1.6 nm-rad

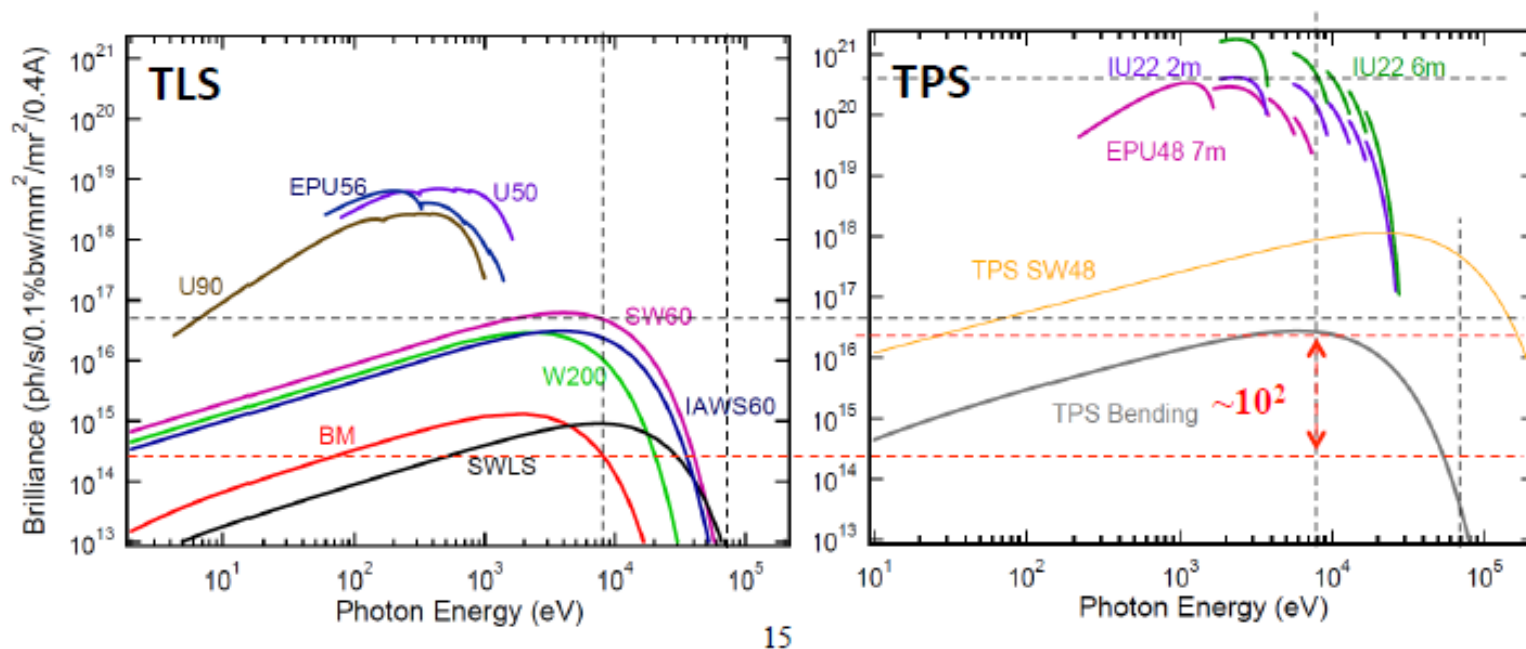


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National Synchrotron Radiation Research Center

Comparison of Brilliance between TLS and TPS

The X-ray spectrum (photon energy 8 keV - 70 keV):
the brightness of bending magnet $>10^2$.

the brightness of IDs: 4~6 orders of mag.



中心現址衛星圖 (太空中心提供)

Groundbreaking
2010-02-07



2010-02-10



2010-05-21



2010-08-04



2011-02-05



2011-09-27



2012-05-14



2013-01-16





Civil Construction of TPS



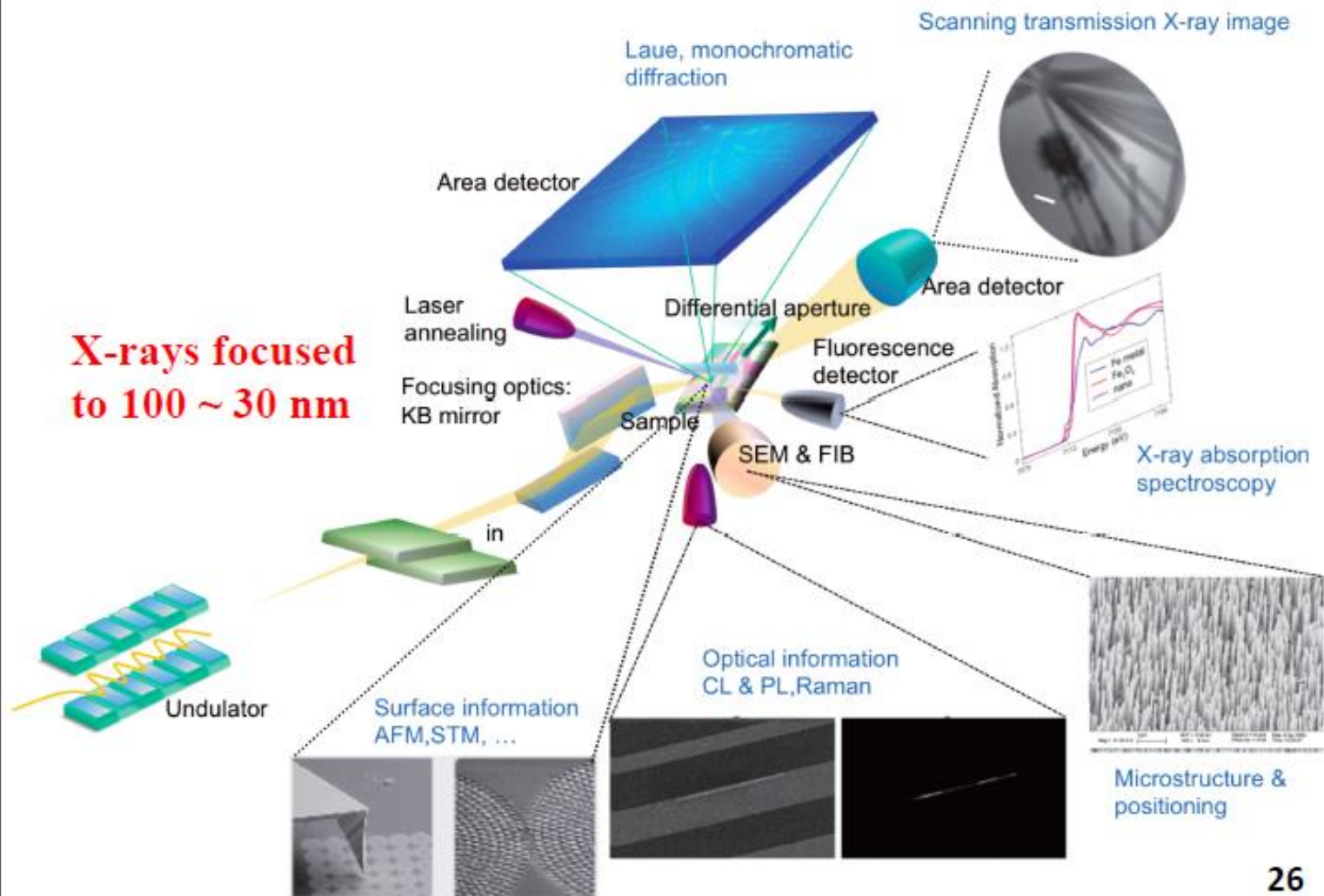
Taiwan Photon Source (TPS)

台灣光子源第一道光芒
2014. 12. 31

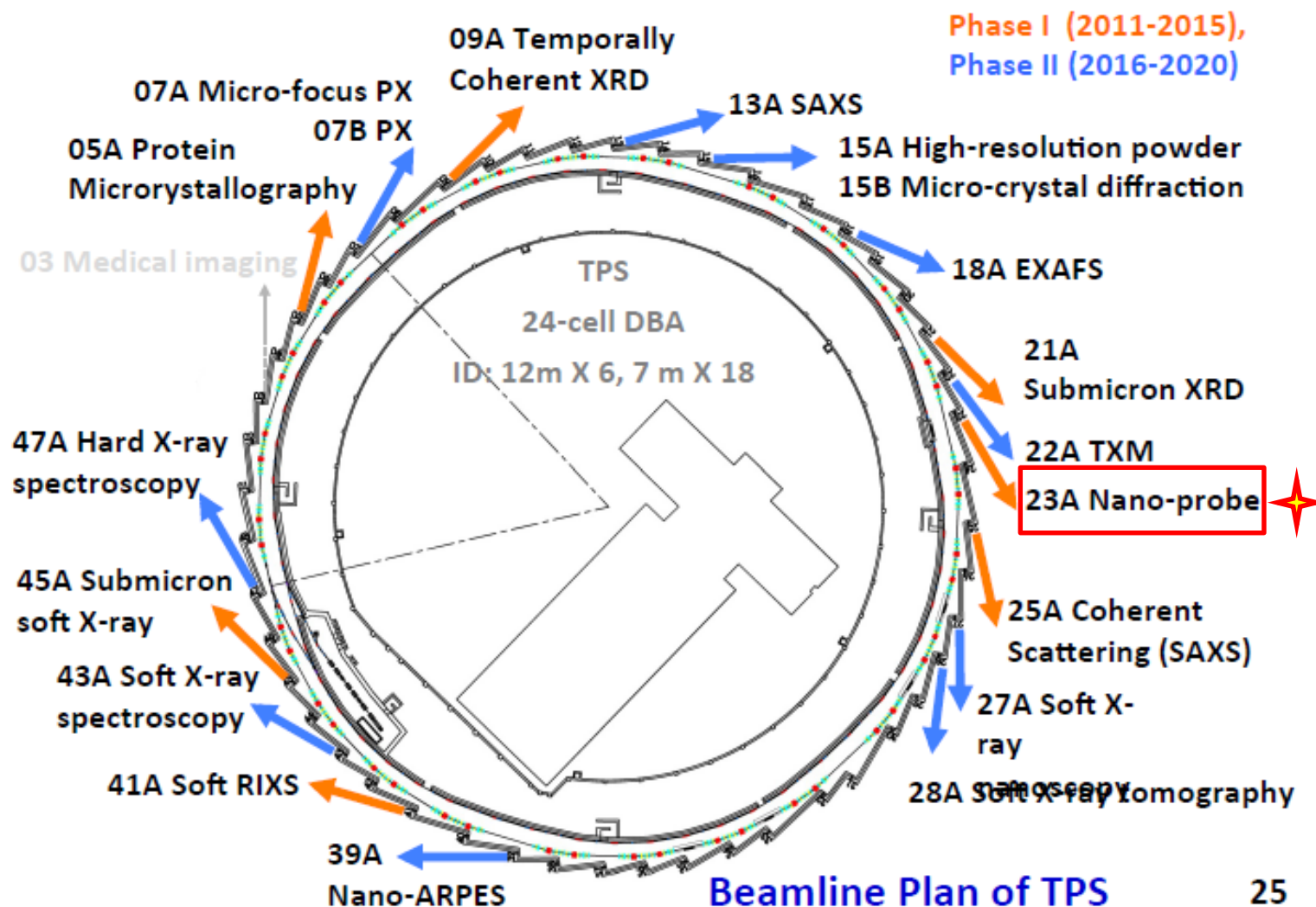


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TPS will brighten the future of scientific discovery.



The user operation of the TPS will begin in 2015.



Outline

- Synchrotron Light Source
- Application of Synchrotron Light
- X-ray nano probe at TPS



- nano-XRF (x-ray fluorescence)
 - Element-specific nanoimaging
- nano-XAFS (x-ray absorption fine structures)
 - Local electronic structure
 - Local chemical environments
 - Element-specific, averaged over nano-size area
- nano-XEOL (x-ray excited optical luminescence)
 - X-ray-to-visible down-conversion efficiency in nano phosphor
- nano-PXM (projection x-ray microscopy)
 - Absorption and phase contrast x-ray images

Beyond sub-ten-nm resolution (coherent)

- nano-CXDI (coherent x-ray diffraction imaging)
- Bragg-ptychography
 - strain dynamics in nano-devices

Other than X-rays

- SEM (SE, EDS, CL with high spatial resolution)
- Fly scanning
- Nanomotors (optional)
- Sample environment -heat, electric, L-He (optional)

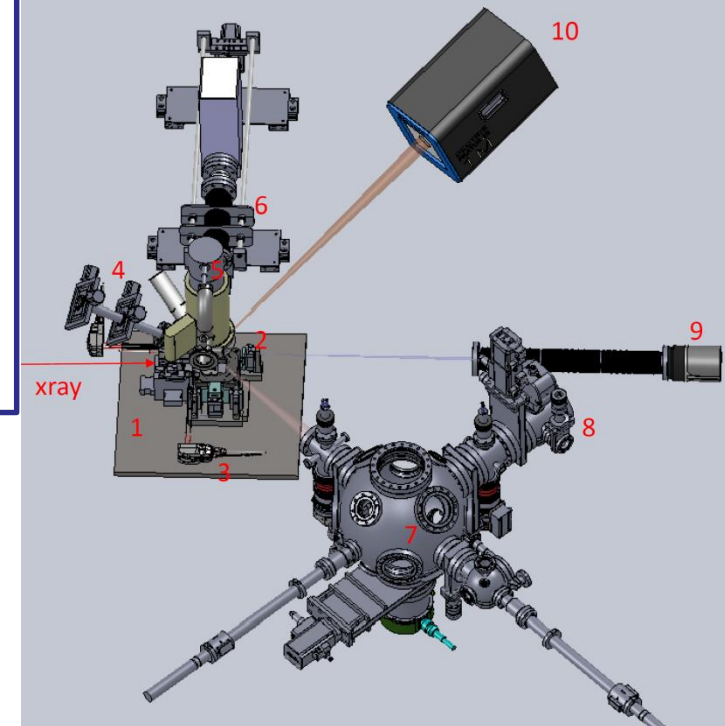
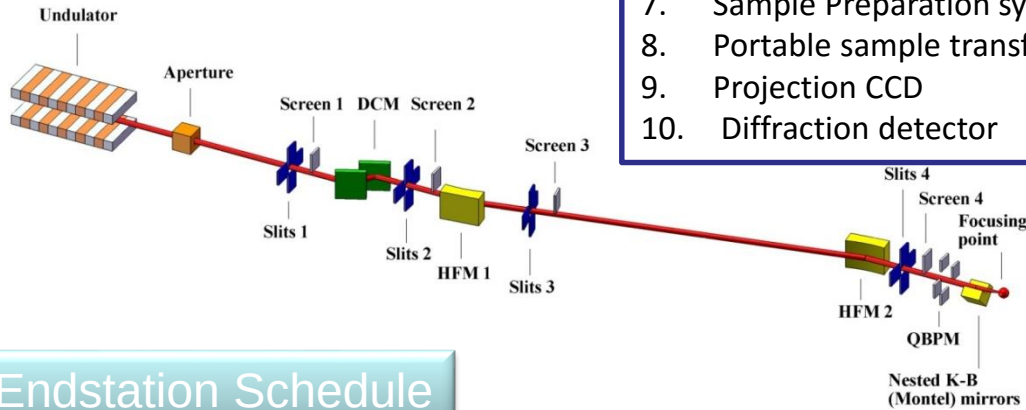
Beamline specification

- Energy range : 4 - 15 keV
- Photon flux :
 $10^{10} \sim 10^{11}$ photons/sec
- Energy resolution :
< 2×10^{-4} with Si(111) crystals
- Beam size :
~ 40 nm at 10 keV (H × V, FWHM)
- High-order harmonic contamination :
 $\leq 1 \times 10^{-4}$
- Energy scanning capabilities.



TPS 23A XNP

1. Montel mirror
2. Sample Stage
3. Laser interferometer
4. XEOL
5. SEM
6. EDS
7. Sample Preparation system
8. Portable sample transfer
9. Projection CCD
10. Diffraction detector



Endstation Schedule

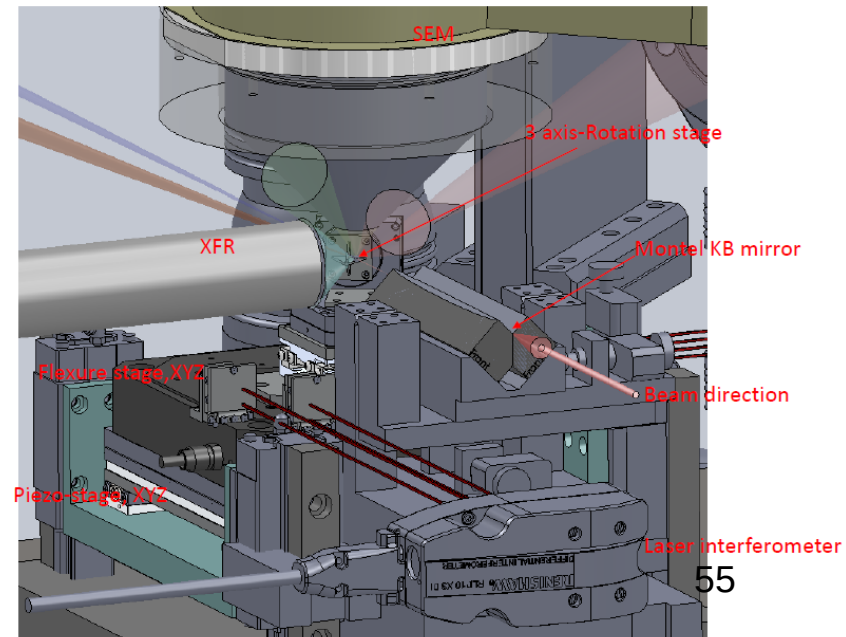
Now

Beamline ready

Commissioning

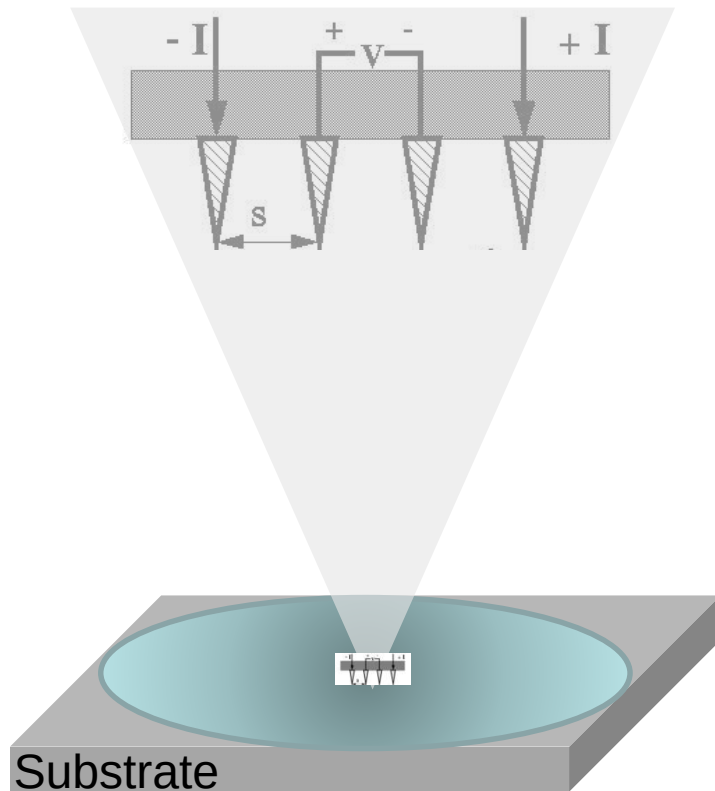
2017

	2014	2015	2016	2017
Electronics & interferometer system development				
Finish test chamber	Main chamber & support design	Main chamber fabrication		
user requirement	Stage design	Procurement of stage		
	Diffraction detector holder design	Procurement of holder		
	KB mirror & holder	Test of Montel KB		
	In-situ system (optional)	Procurement of Pilatus diffraction detector		
		Stage test		
		Optical table, support		
		Air conditions	CCD Detector	
		Software development		





Nanomotor Probe Application

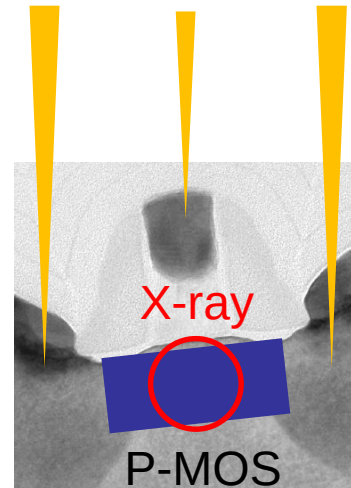


Nanometer can construct
the 4-point probe

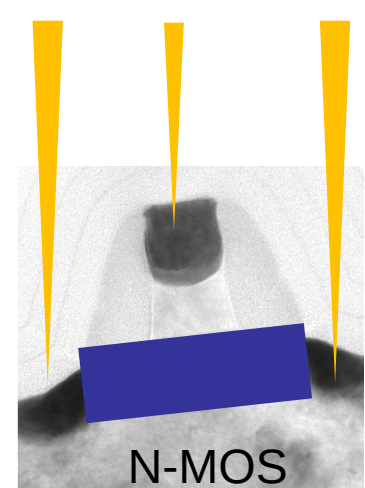


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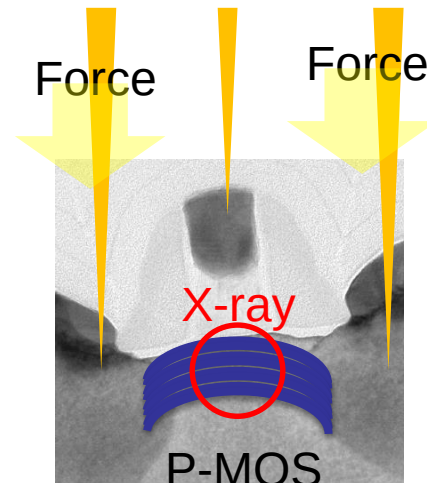
I-V measurement



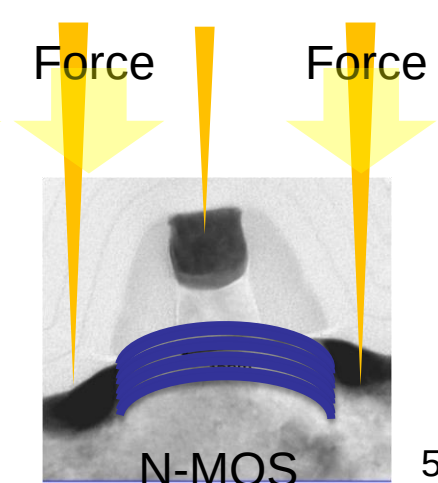
I-V measurement

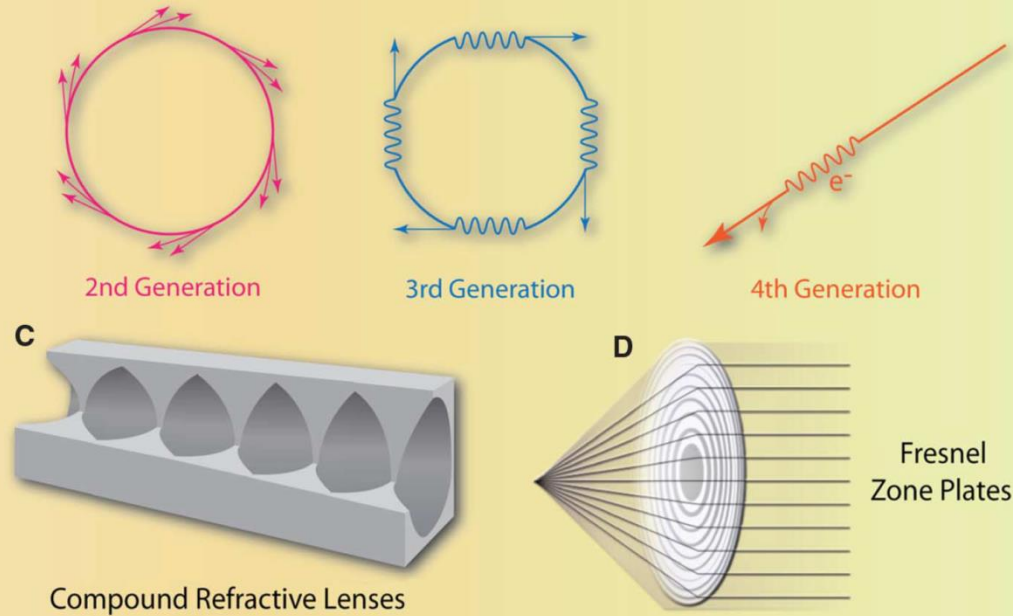
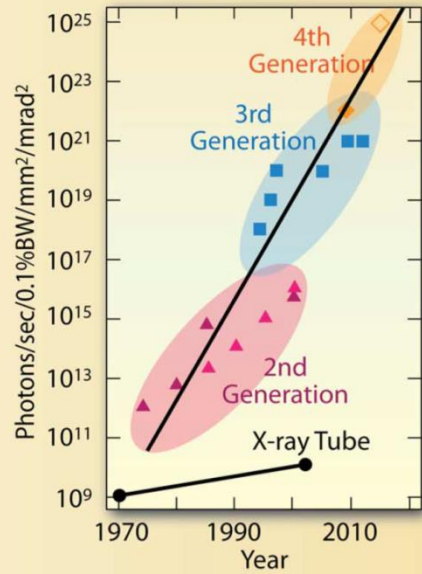
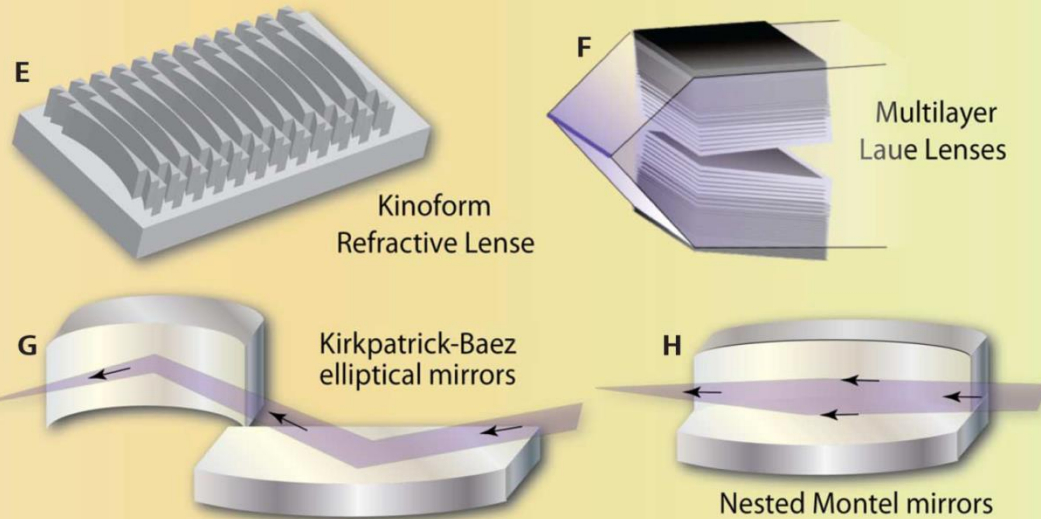
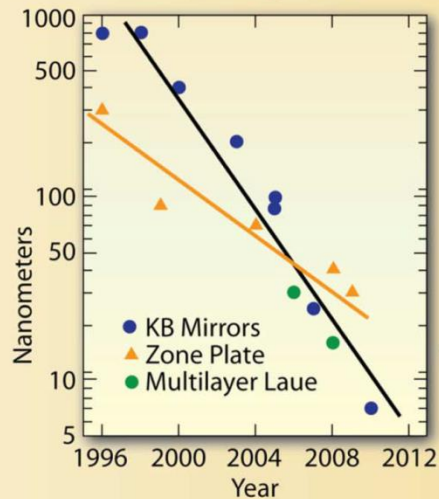


I-V measurement



I-V measurement

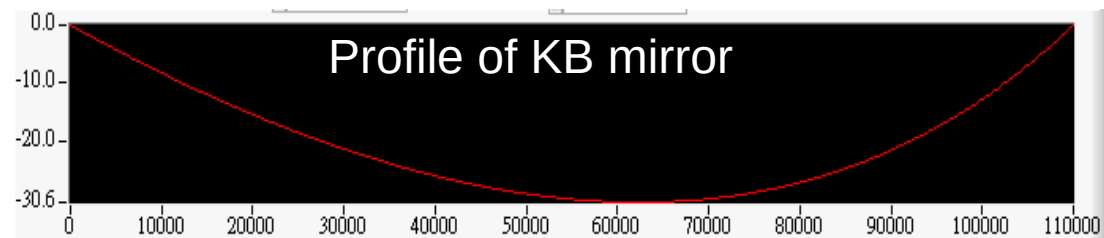
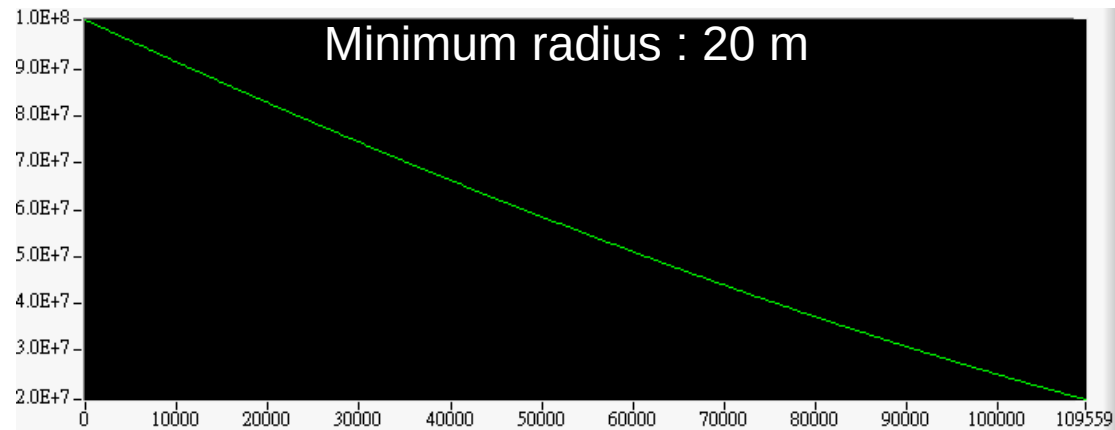
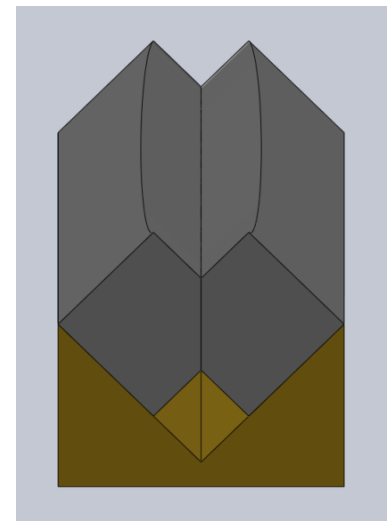
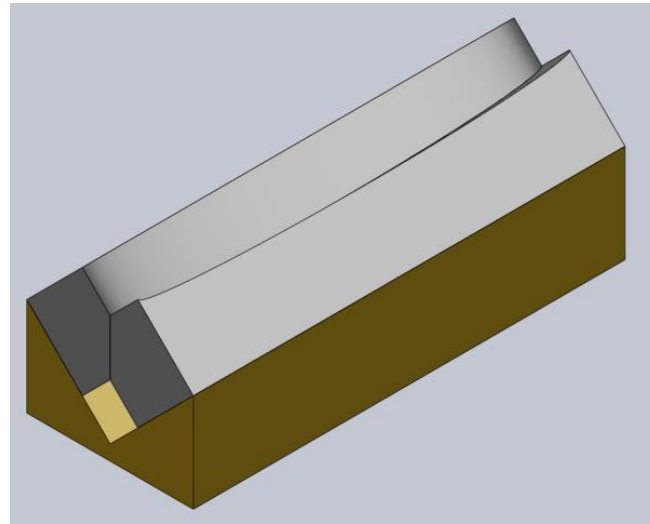


A Time-average 10 keV X-ray Brilliance**B** 10 keV Spot Size

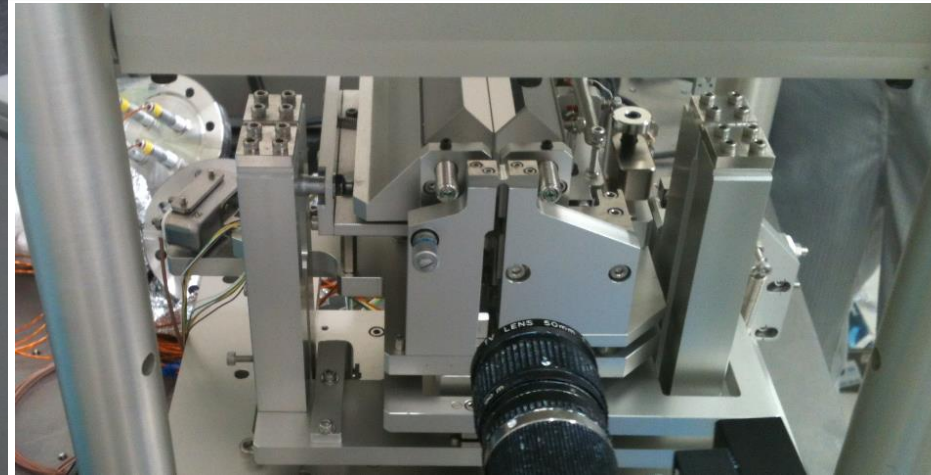
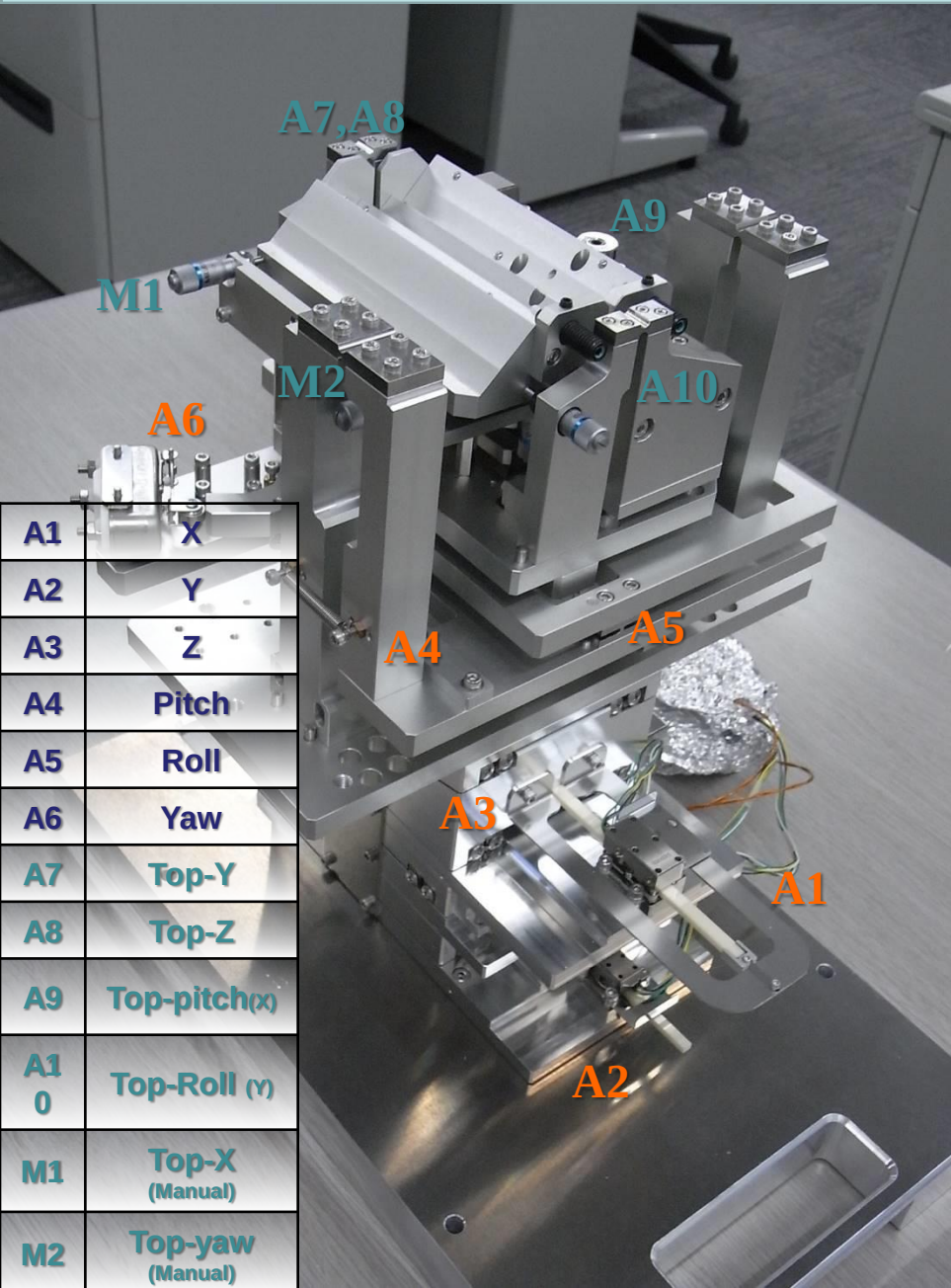
Montel Nested KB Mirror @TPS-23A

- **Montel nested KB mirror @ APS:**
 - Focal spot: 100 nm
 - **Challenges:**
 - Gap between mirrors
 - Slope error
- Overcome by **Elastic Emission Machining (EEM)**
- **Montel nested KB mirror @ TPS:**

Objective distance	69 m
Focus length	11 cm
Mirror length	11 cm
Slope error (RMS)	< 0.05 μ rad
Incident angle	4 mrad
Coating	Rh
Material	silica
Working Distance	5.5 cm



Montel KB Montel Mirror and Holders



Montel Mirror on the holder



Gap imaged by microscope

June 2015, at JTEC

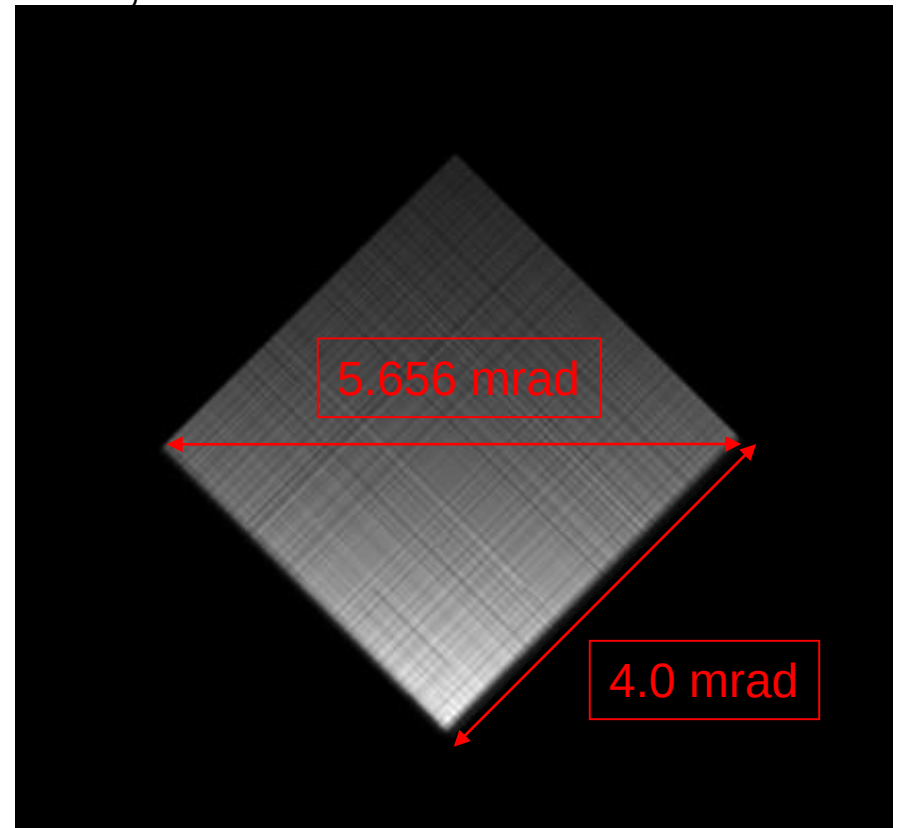
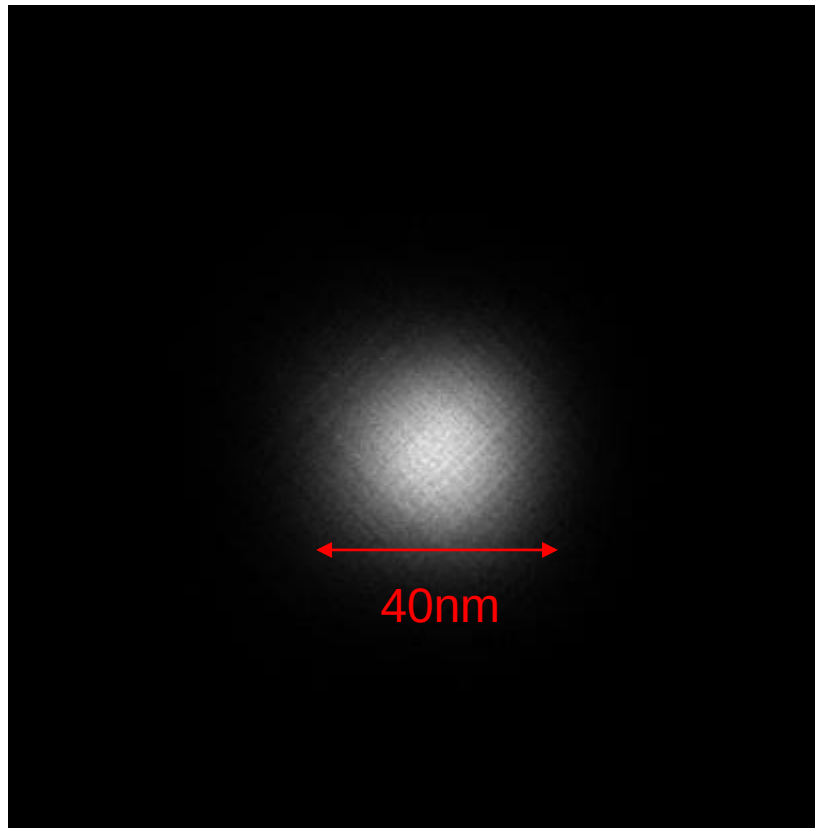
Simulation of Focus Spot

Simulation at 10 keV, average reflection=0.802, by ray tracing

Source size 12.5 μm x 12.5 μm

Source divergence 6 μrad x 6 μrad

FHWM 32nm x 32nm,



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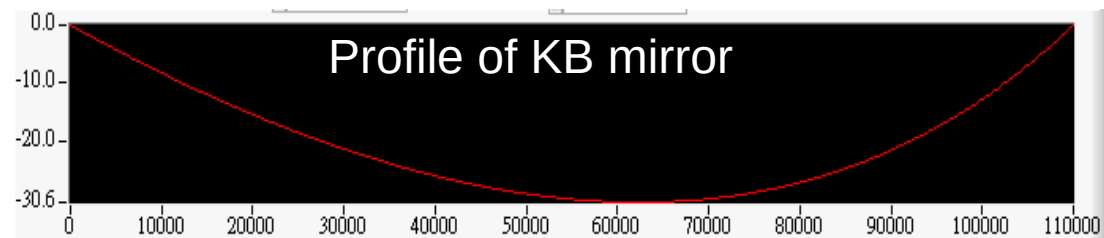
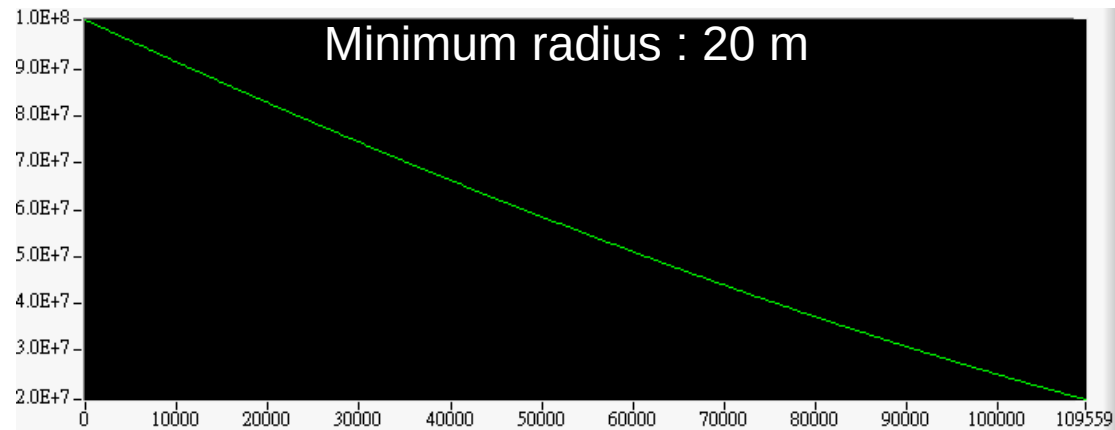
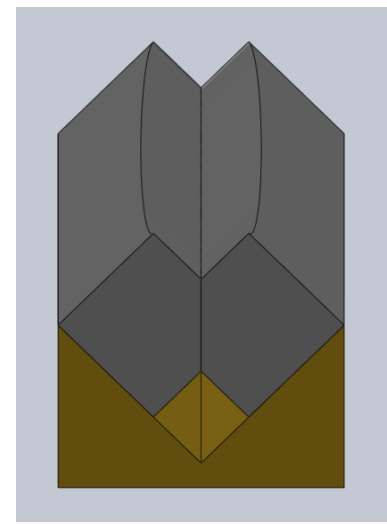
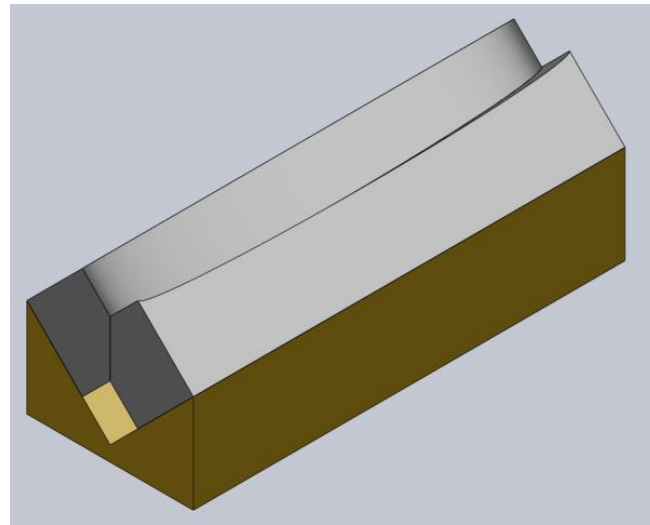
Simulated
Focus spot size

Simulated
Divergence
By Gung-Chian Yin

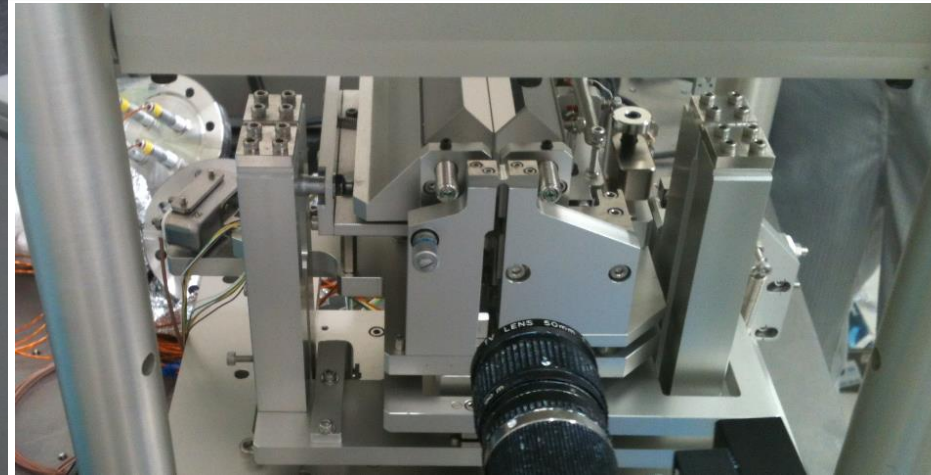
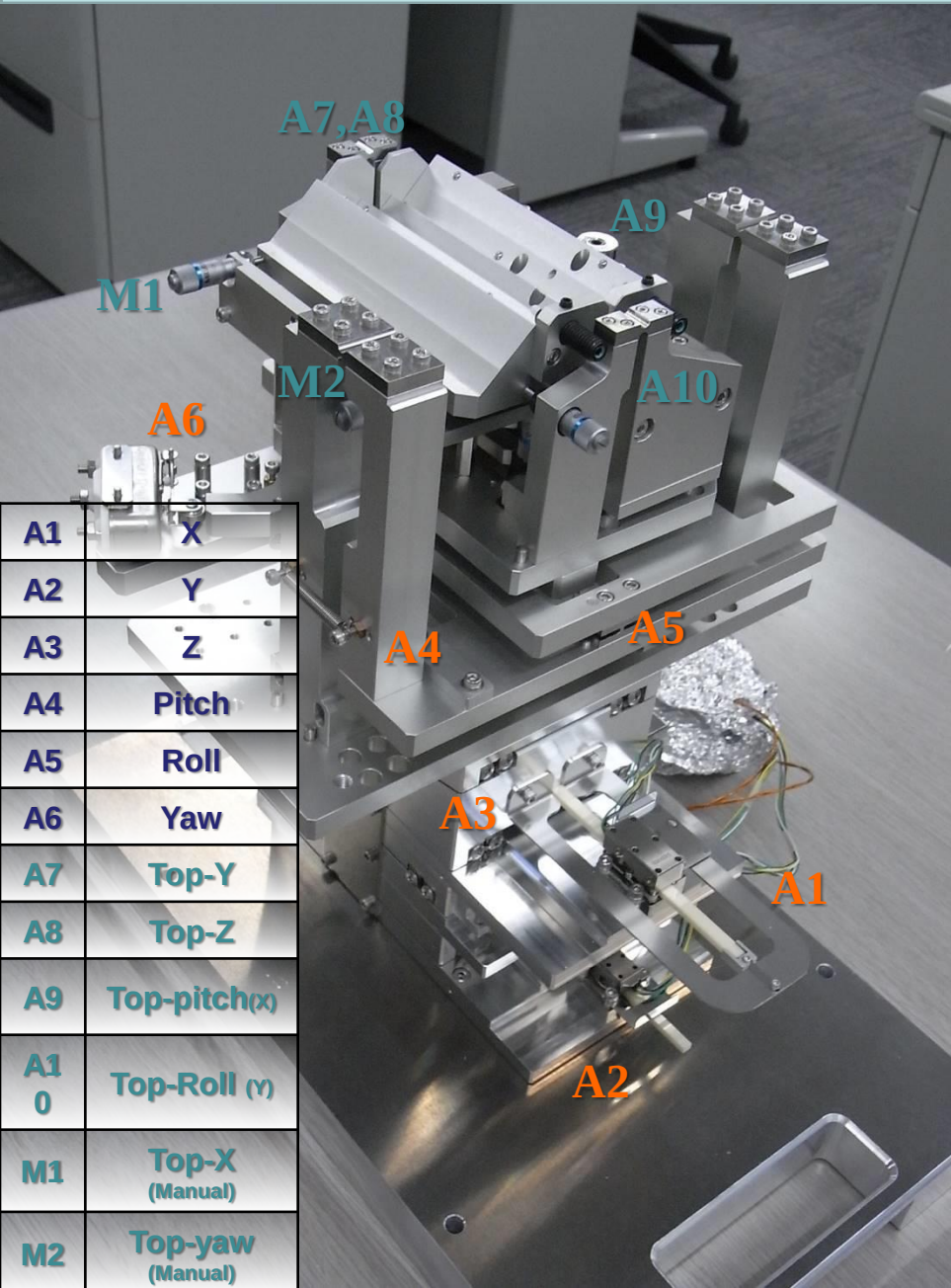
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Montel KB Montel Mirror and Holders

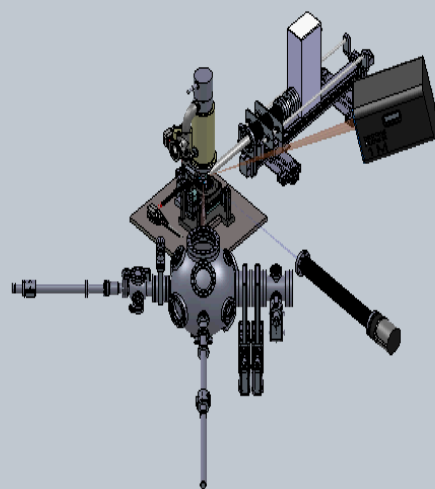


Montel Mirror on the holder



Gap imaged by microscope

June 2015, at JTEC



nano-XRF (x-ray fluorescence)

Element-specific nano-imaging

Doping of ZnO NWs by transition metal Co.

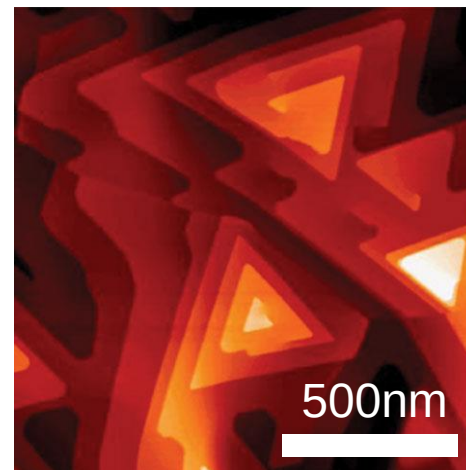
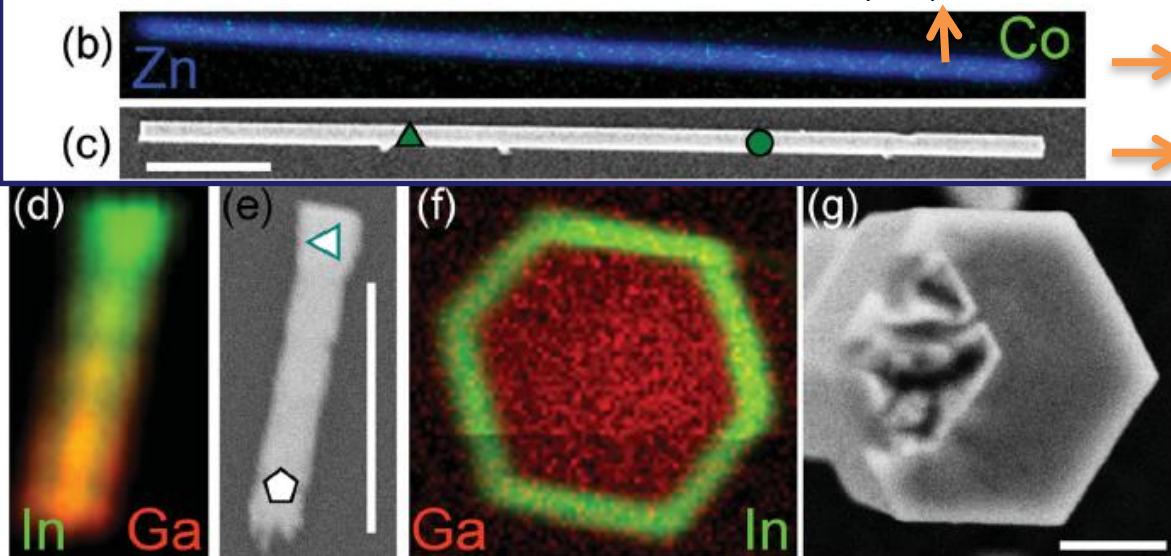
Application : [Spintronic device](#)

Want to know:

- Distribution
- Short structure order
- Elemental composition

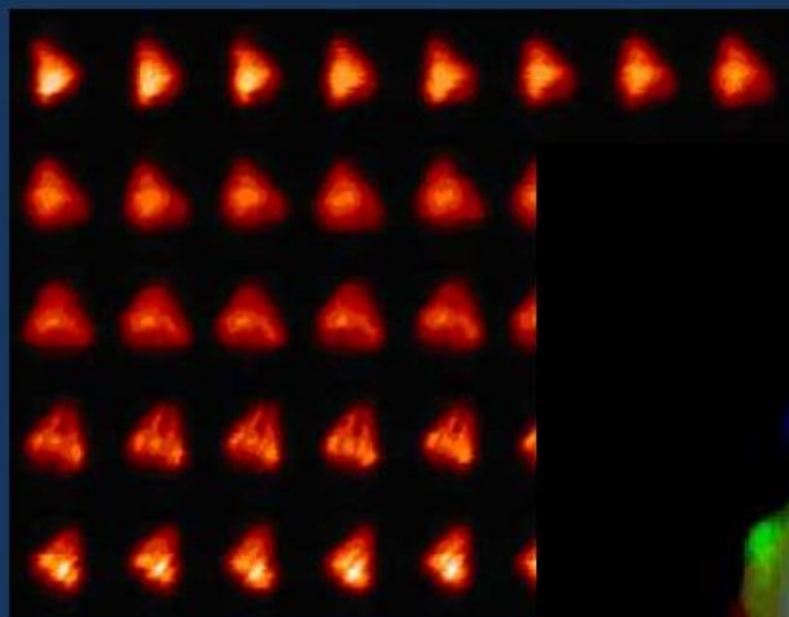
Vapour-liquid-solid process
Nano Lett. 2011, 11, 5322–5326

Doping method:
Ion implantation
and thermal annealing
Elemental map of XRF
SEM

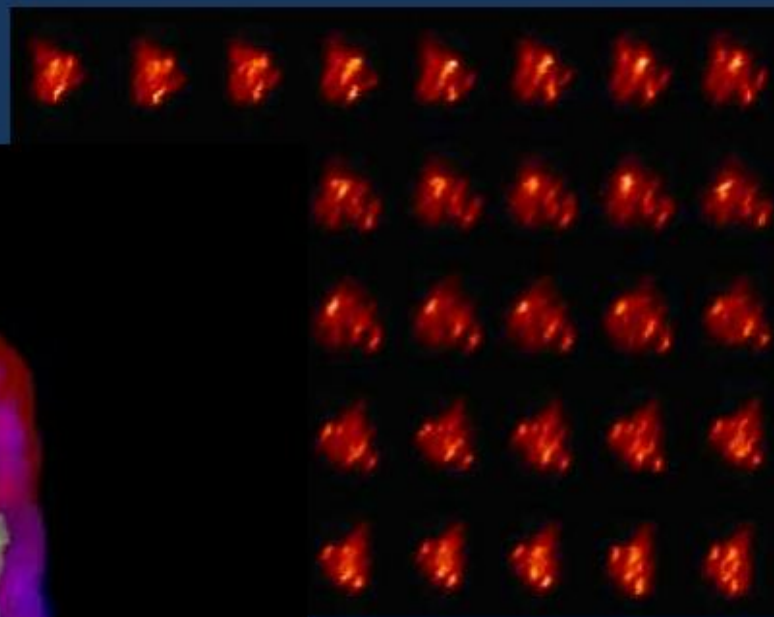


High resolution XRF tomography

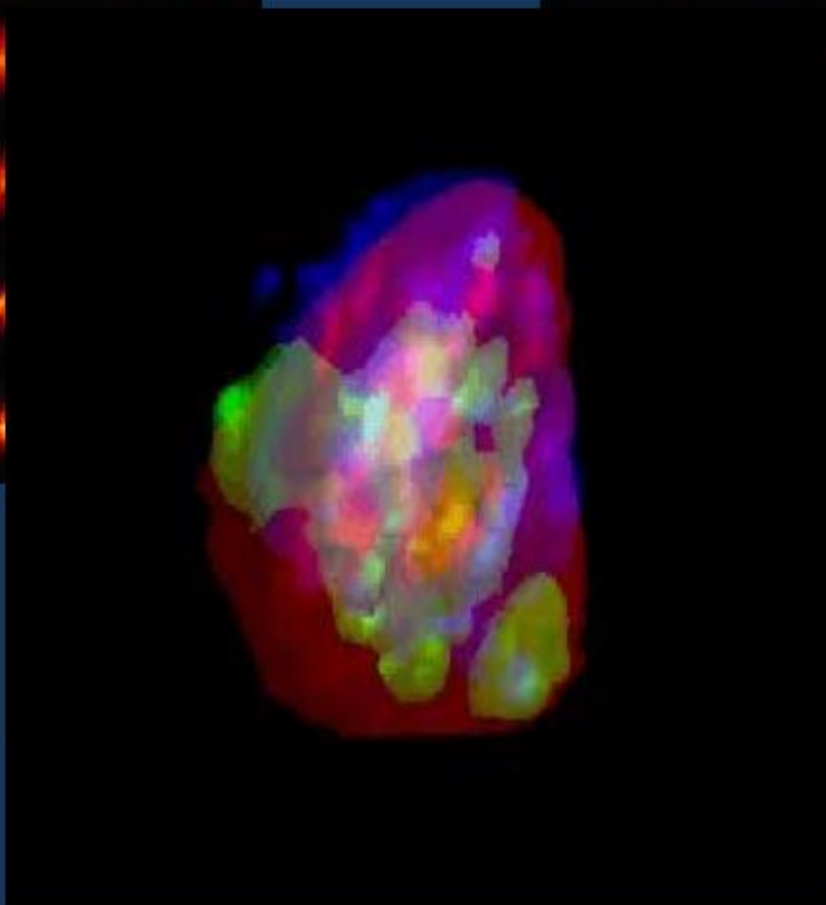
Pixel size: 100 nm, sample rotation 0-180° (4.5° / image)



Fe



Cr

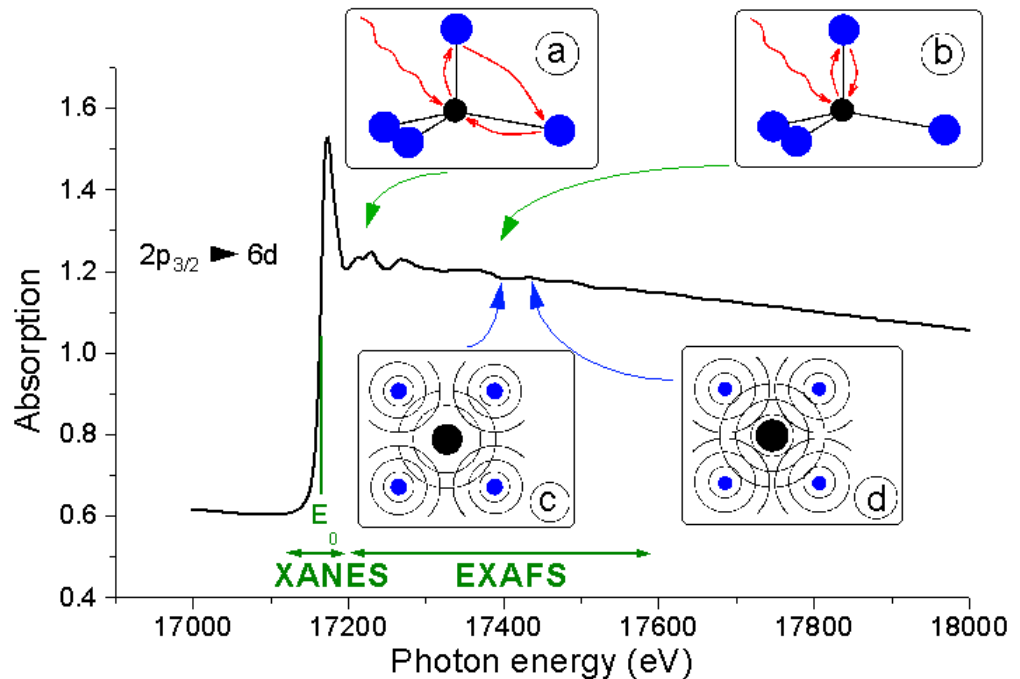
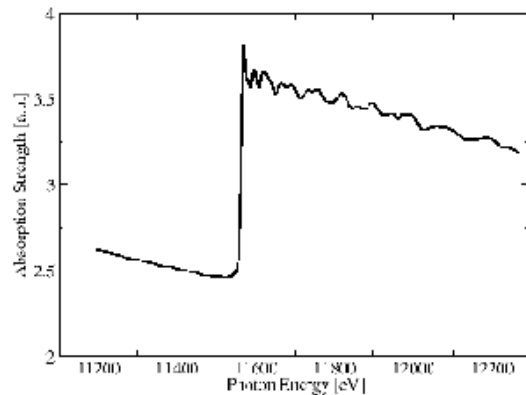
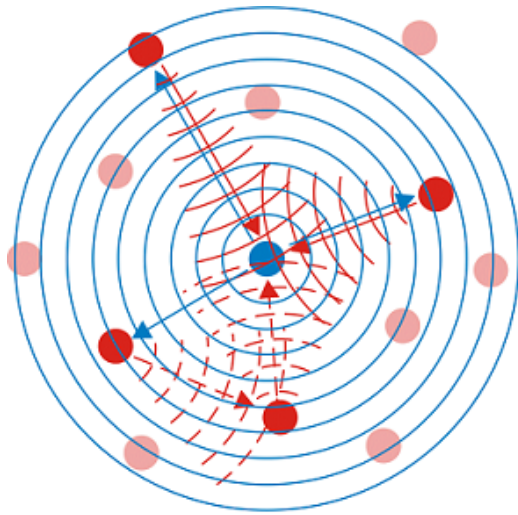


Composite
Fe-Cr-Se

Silversmit *et al.*, *Anal. Chem.* 81 (2009)

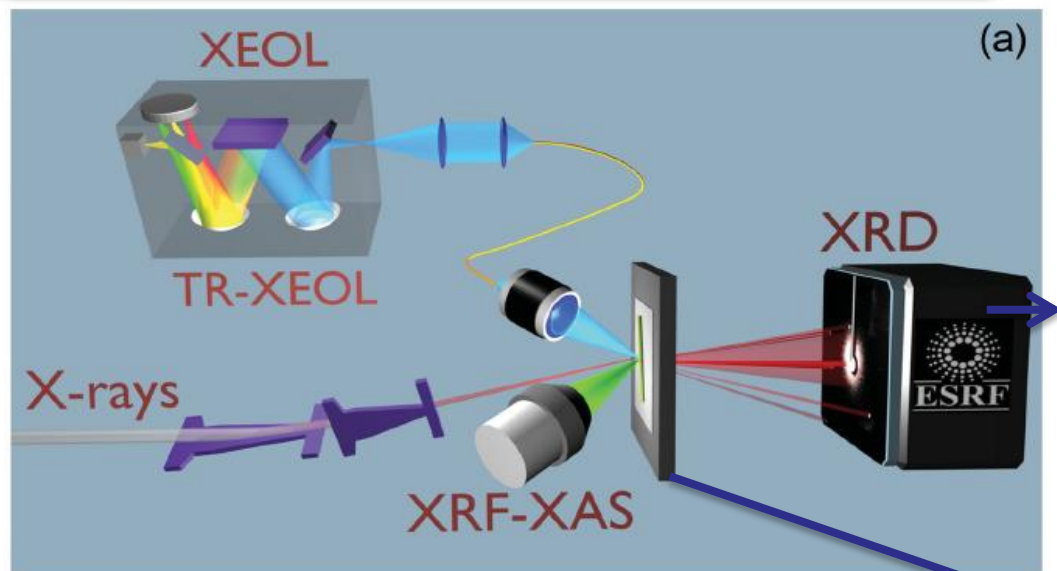
nano-XAFS (x-ray absorption fine structures)

- Local electronic structure
- Local chemical environments
- Element-specific, averaged over nano-area



XEOL

- Multimode optical fiber
- UV-VIS : linear CCD Si detector
- Si avalanche photodiode (id100 from id-Quantique)



ESRF ID16B methods

XRD

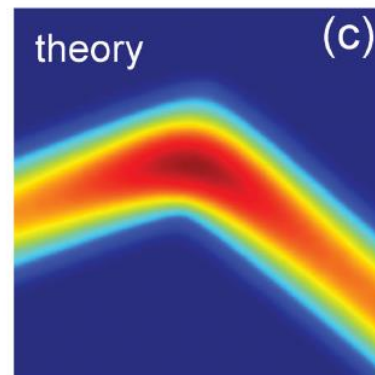
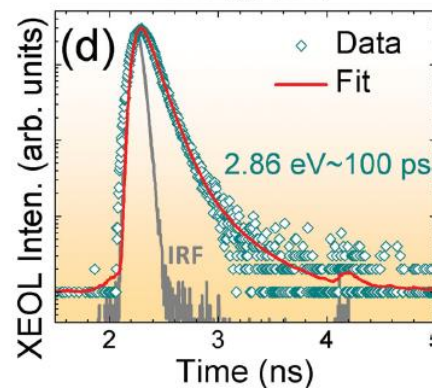
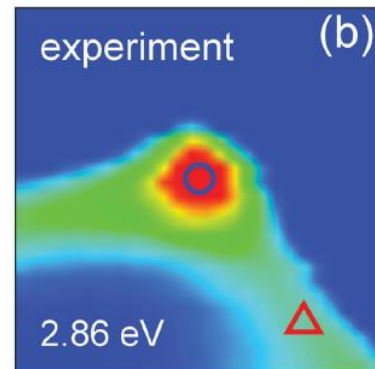
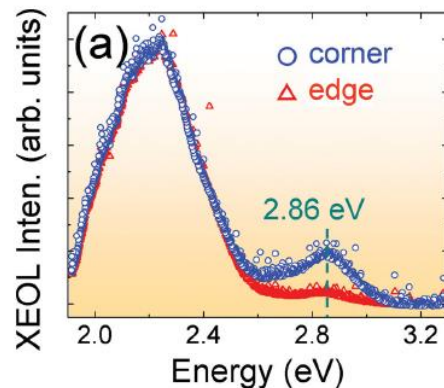
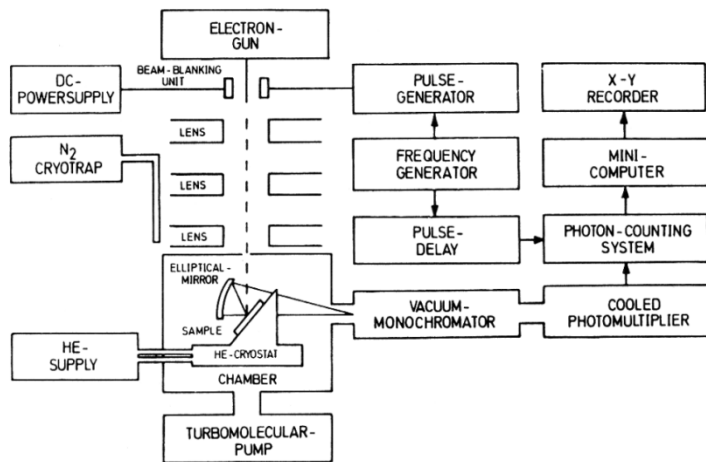
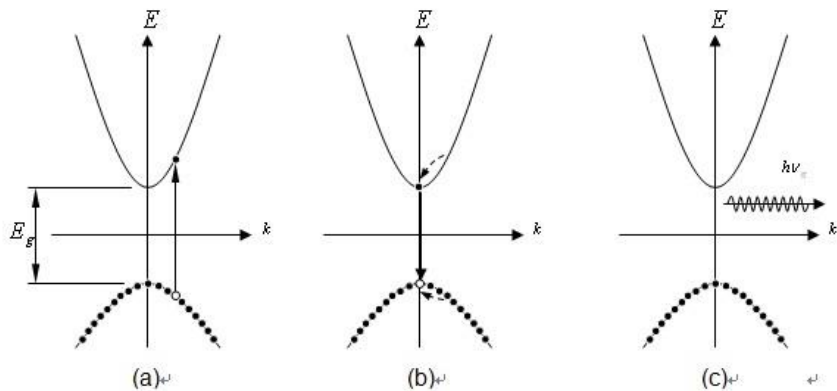
- The XRD signal was measured using a fast readout low noise (FReLoN) CCD detector.
- The CCD images were processed using Fit2D software to generate the standard diffractograms.
- Using the experimental parameters derived from the measurement of an Al₂O₃ reference sample.

XRF

- XRF signal was collected at 15°
- The elemental composition of the NWs was estimated by fitting the XRF spectra using the [PyMca](#) program.
- XANES spectra were recorded in X-ray fluorescence mode with a step size of 1 eV and integration times determined by the counting statistics.
- The data analysis was performed using the IFEFFIT package.

- 200 nm thick SiN membranes.
- Without XRF background signal
- X-ray diffraction can be transmitted

nano-XEOL (x-ray excited optical luminescence) & CL (cathodoluminescence)

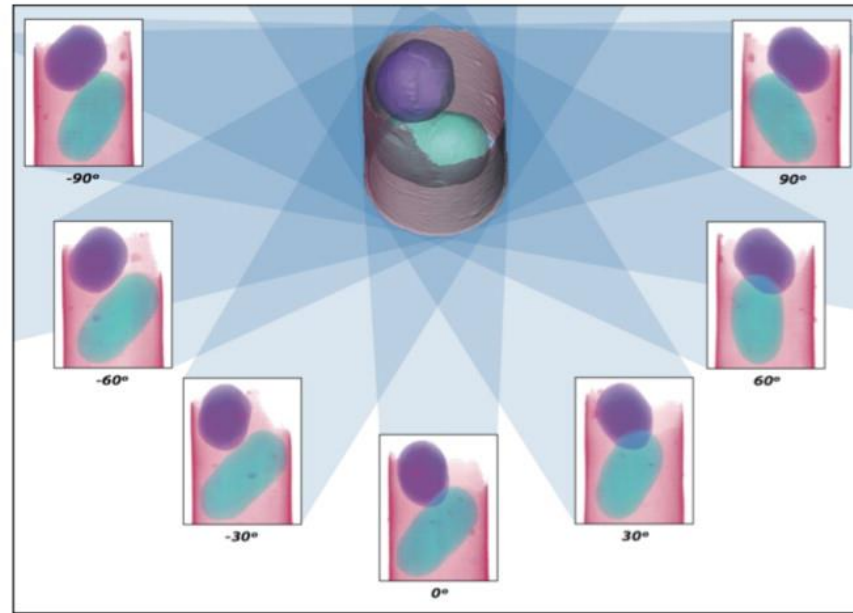
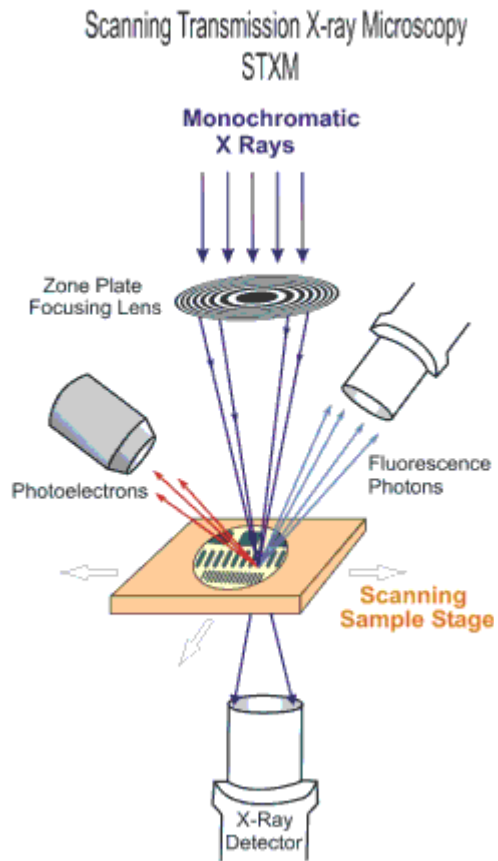


XEOL: 1.nano-area
2.multi-layer, buried layer

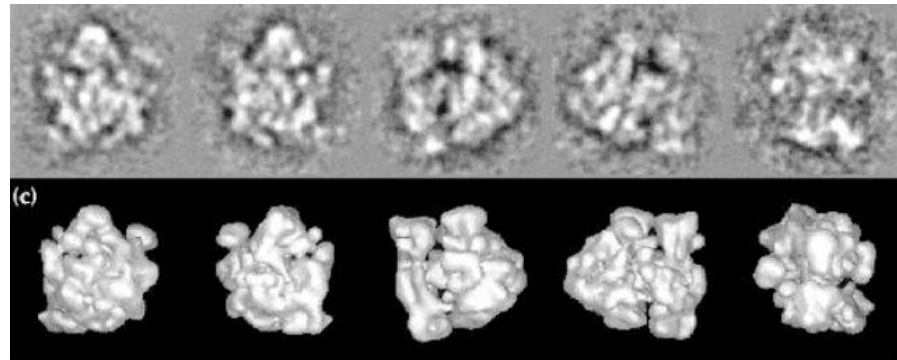
Doping species, Band gap, Defect band,
Charge transport

nano-PXM (projection x-ray microscopy)

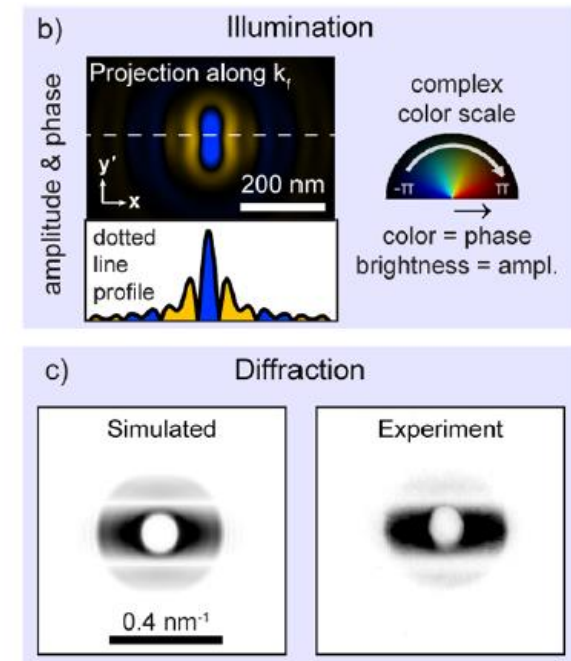
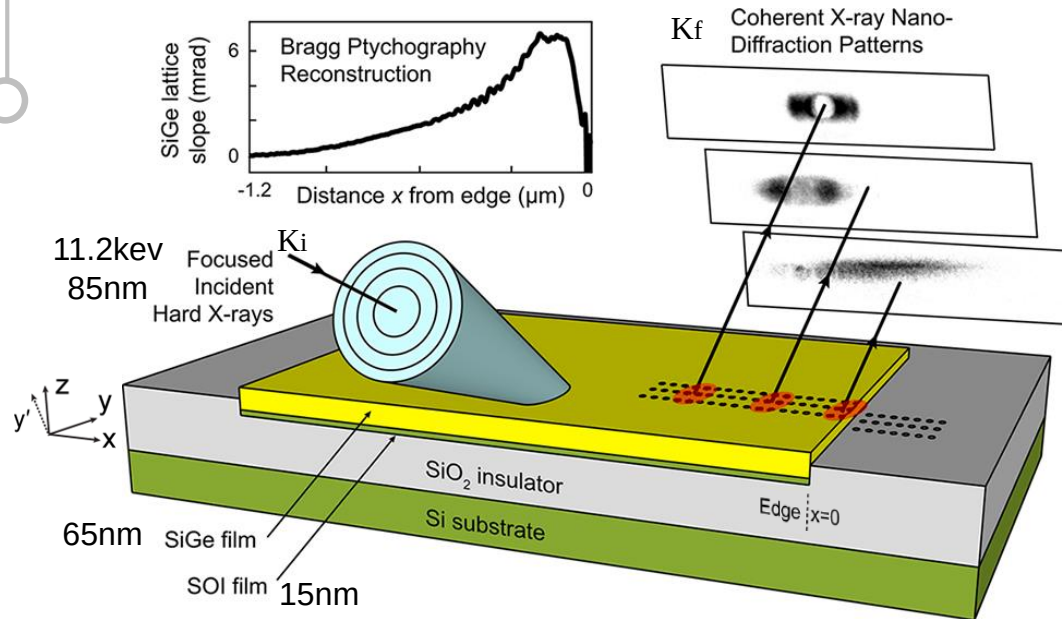
– Absorption and phase contrast x-ray images



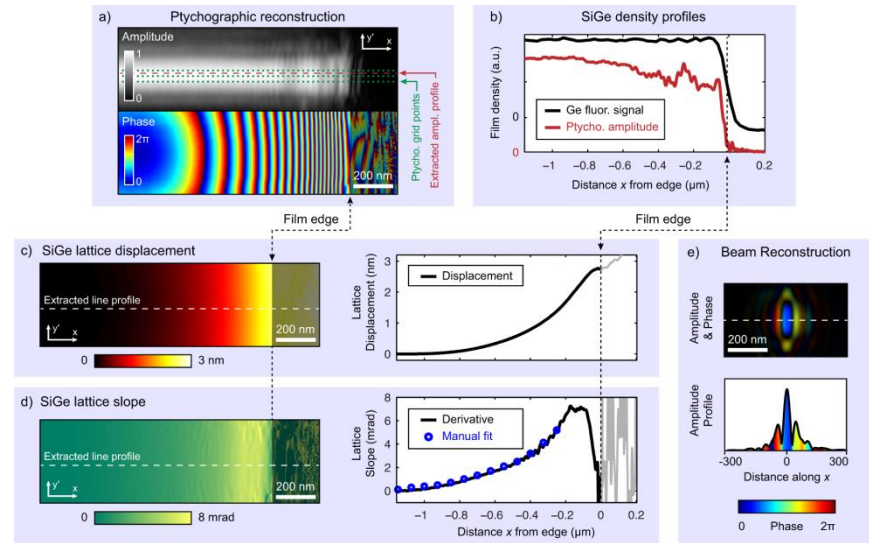
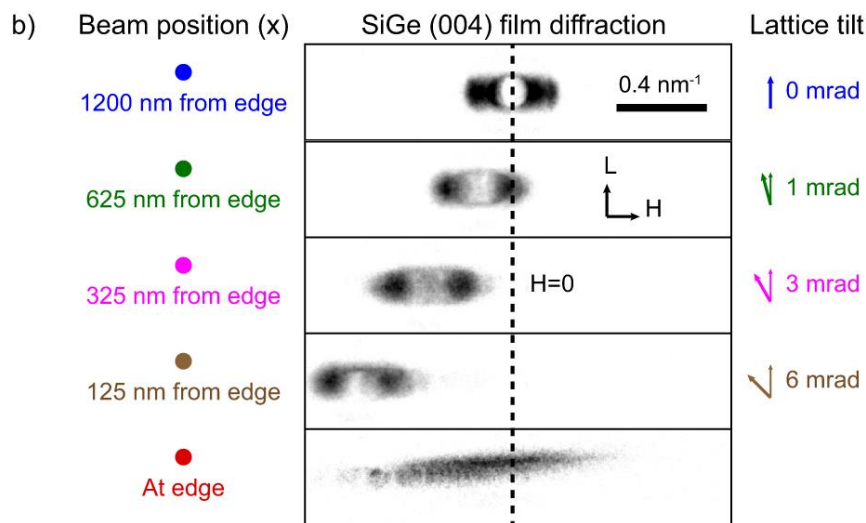
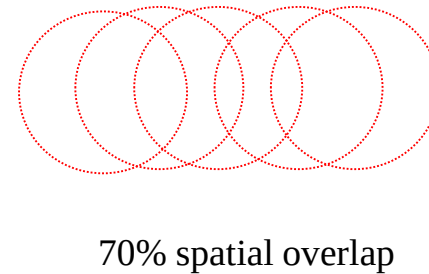
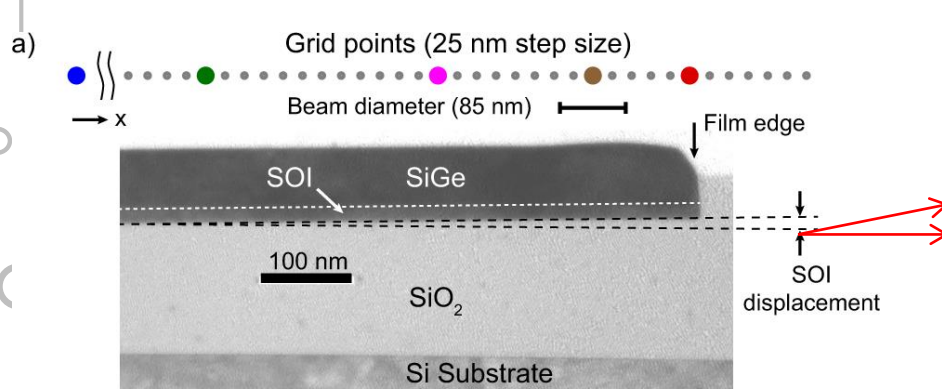
TRENDS in Cell Biology



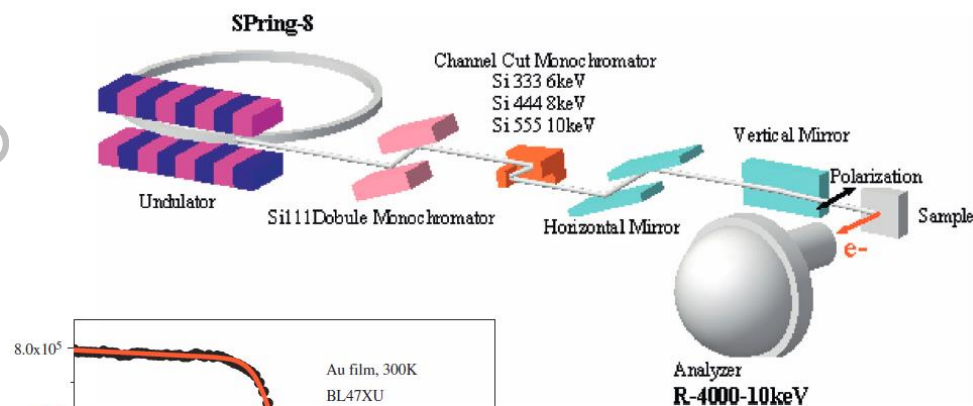
X-ray Bragg projection ptychography from thin film heterostructures



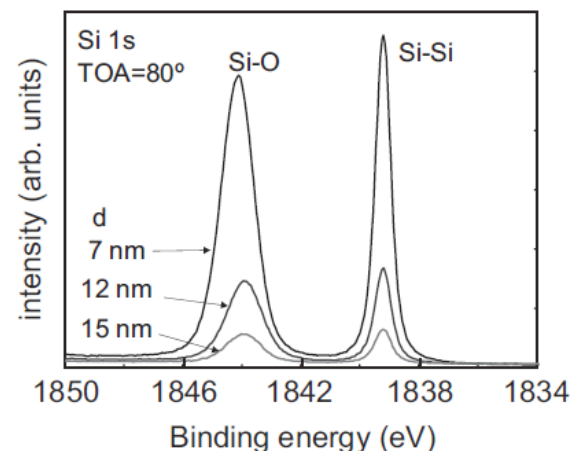
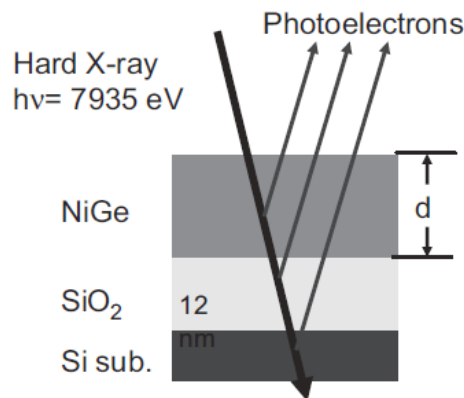
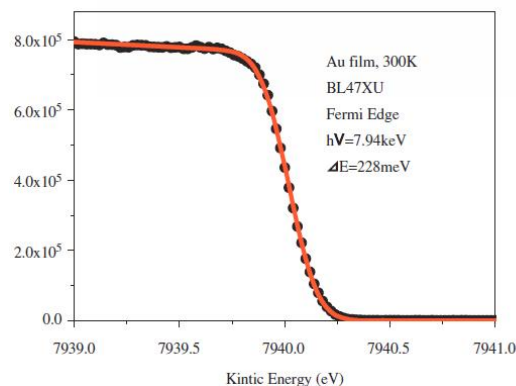
Focused beam Bragg diffraction near the device edge



Upgrade: Hard X-ray photoelectron spectroscopy(HXPS) at XNP



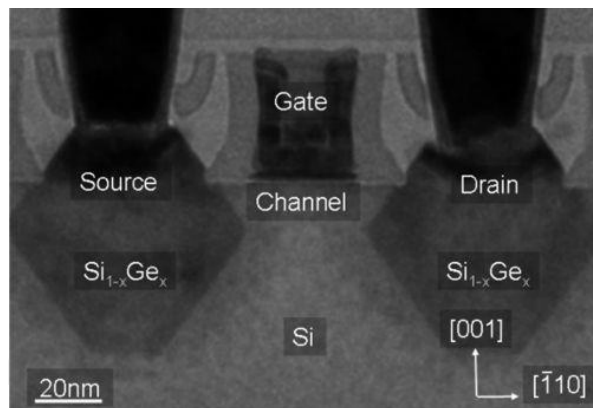
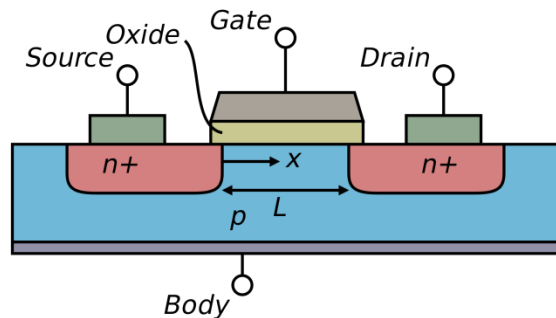
HXPS: Several keV to 15 keV to increase bulk sensitivity for bulk electronic structure and buried interface.



Applications

Solid state physics

- Strongly correlated electron systems
YbAl₃, YbInCu₄, YbCu₂Si₂
La_{1-x}Sr_xMnO₃ (LSMO)
- Spintronics
LaVO₃, LaAlO₃, Fe_{3-x}M_xO₄ (M=Mn, Zn)
- Compound semiconductors
InGaZnO, GaCrN, InN, ZnMgO



M. Chu, et al., Annu. Rev. Mater. Res.
39 (2009) 203-229

High-k gate stacks

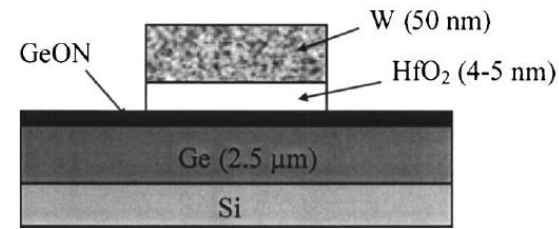
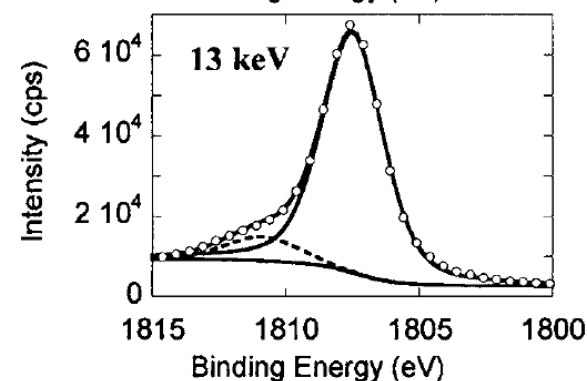
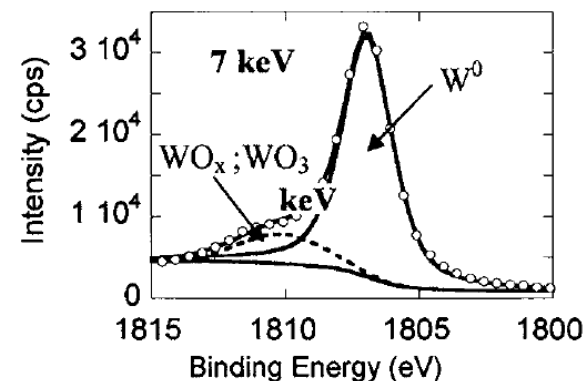


FIG. 1. Diagram of the W/HfO₂/GeON/Ge stack.




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- ☐ (NSRRC用戶函) 請於2/6 (五) 前建議2015年用戶年會研討會議題及邀請講員 (2015-01-06)
- ☐ 2015-2期NSRRC光束線使用申請至2015年1月31日 (六) 24時截止, 請如期繳交。(2014-12-12)
- ☐ NSRRC公告 --- 明日10/16(四)本中心餐廳開賣囉! (2014-10-15)
- ☐ 2015年第一期 NSRRC 中子實驗計畫(包含SIKA), 申請至2015年1月5日 24:00截止。(2014-12-08)
- ☐ To Users of SPring-8: Change in locations of check-in procedures and safety training sessions (2014-08-18)
- ☐ Announcement of Soft X-ray Chemistry Beamline, BL05B1, at NSRRC (2014-04-24)

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每間單人住宿價為NT\$700/天, 雙人住宿價為NT\$1,000/天;四人房價為NT\$1,500/天。

房型	實景	間數	房間坪數	收費	備註
二張單人床		30	6	1,000元/晚	單人住宿一律 NT \$700 元
四張單人床		1	12	1,500元/晚	
交誼廳		4	10		一至四樓
餐廳		2	7		三至四樓



SR International Course



AOFSRR Activities



國家同步輻射研究中心
National Synchrotron Radiation Research Center

AOFSRR Cheiron School 2015

ver. 2015/07/15

Time	Sep.10 Thu.	Time	Sep.11 Fri.	Time	Sep.12 Sat.	Time	Sep.13 Sun.	Time	Sep.14 Mon.	Time	Sep.15 Tue.	Time	Sep.16 Wed.	Time	Sep.17 Thu.	Time	Sep.18 Fri.	Time	Sep.19 Sat.
			9:00 9:20 Opening Remarks																Guest House Check-out
			9:20 10:00 Lec. 1 Overview of SR and AOFSRR R. Garrett (ANSTO)										9:20 1F Lobby, Main Bldg.						9:00 10:20 Lec. 21 Atomic and Molecular Physics at SACLA K. Ueda (Tohoku Univ.)
			10:00 10:20 Coffee Break										9:30 10:50 Meet the Experts Part 2						10:20 Break
			10:20 11:40 Lec. 2 Ring Accelerator Physics H. Tanaka (RIKEN)										11:00 12:20 Lec. 14 XAFS P. Fons (AIST)						10:30 11:00 Lec. 22 Future of SR T. Ishikawa (RIKEN)
			11:40 12:30 Lunch										12:20 13:20 Lunch						11:00 11:30 Closing Remarks
			12:30 13:50 Lec. 3 Light Source (1) T. Tanaka (RIKEN)										13:20 14:40 Lec. 15 Inelastic Scattering M. Dean (BNL) / Lec. 16 Infrared F. Borondics (Soleil)						11:30 12:20 Lunch
			13:50 14:40 Safety Education										14:40 15:00 Coffee Break						12:30 Bus leaves for KIX
			14:40 15:50 Participants' Self-Introduction										15:00 15:20 Move to SACLA						
			15:50 16:00 Move to Central Bldg.										15:20 15:40 School Photo						
			16:00 18:00 Site tour SPRING-8										15:40 17:00 Lec. 13 XFEL K. Tono (JASRI) and T. Inagaki (RIKEN)						
			18:00 18:00 Move to Houkou-kan										16:40 18:00 Lec. 19 Protein Crystallography J. M. Guss (Univ. Sydney) / Lec. 20 Soft X-ray Absorption Spectroscopy P. Krüger (Chiba Univ.)						
			18:00 19:30 Dinner										17:30 18:30 Dinner						
			19:30 20:30 Welcome at Guesthouse										18:00 19:30 Dinner						
													19:30 20:30 SPECTRA Workshop						

☆ Parallel Lectures

SPRING-8 Cafeteria Breakfast: 8:00-9:30
Opening Hour: 11:30-14:00
Dinner: 17:30-19:30



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Enjoy the Cheiron School!



Thanks to many people for slides
Particularly Edgar Weckert, DESY

2015 Cheiron School



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Thanks for your attentions